

Fundamentals of Electronic Circuits and Systems II

# CMOS Digital Logic Circuits

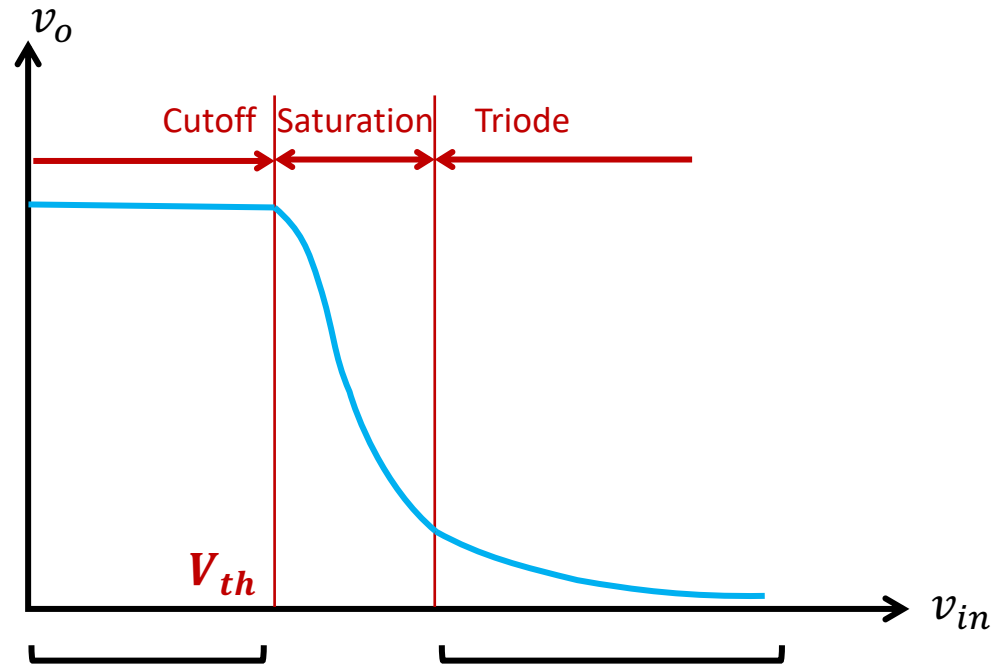
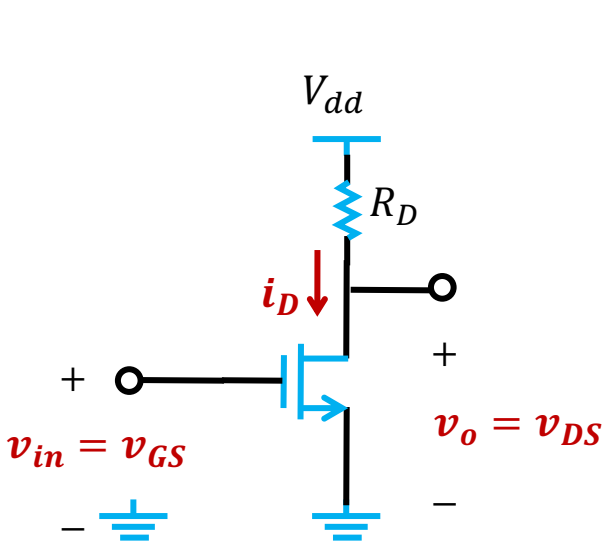
Milin Zhang

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# Outline

- CMOS Inverters
- Logic-Gate Circuits
- Digital Switches
- Memory Circuits

# Recall: NMOS Transfer Characteristic



$$v_{in} < V_{th}$$

$$i_D = 0$$

$$v_o = V_{dd} - i_D R_D = V_{dd}$$

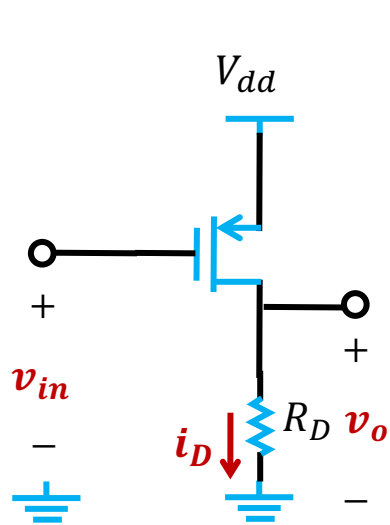
$$v_{in} > V_{th}$$

$$v_{GS} - v_{DS} > V_{th}$$

$$i_D = k_n \left[ (v_{GS} - V_{th})v_{DS} - \frac{1}{2}v_{DS}^2 \right]$$

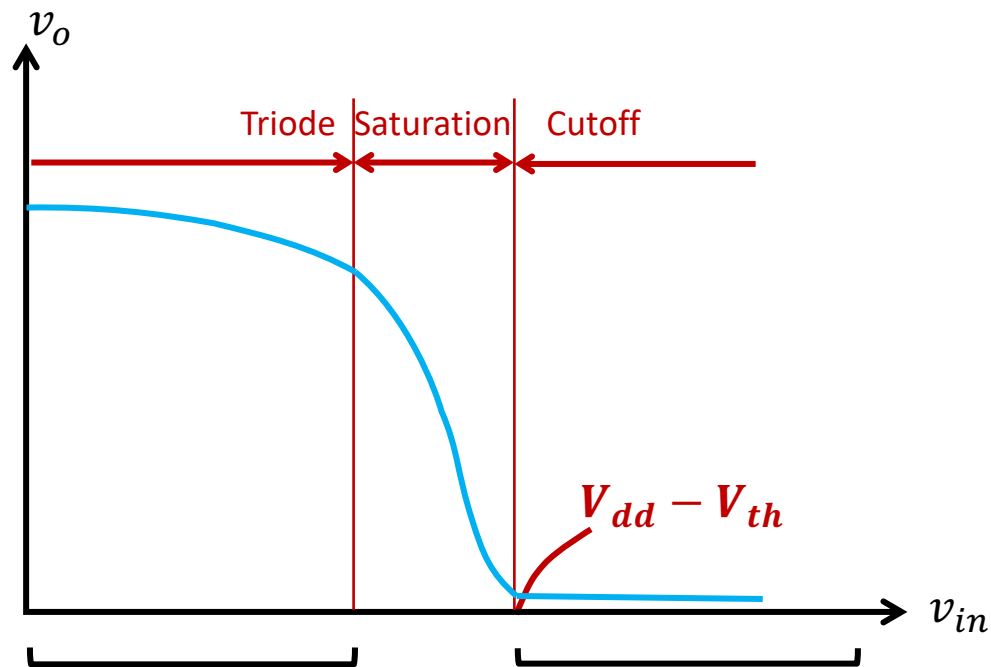
$$v_o = V_{dd} - i_D R_D$$

# How about a PMOS circuit?



$$v_{in} = V_{dd} + v_{GS}$$

$$v_o = V_{dd} + v_{DS}$$



$$v_{in} < V_{dd} - V_{th}$$

$$v_{DS} - v_{GS} > V_{th}$$

$$i_D = k_n \left[ (v_{SG} - V_{th})v_{SD} - \frac{1}{2}v_{SD}^2 \right]$$

$$v_{in} > V_{dd} - V_{th}$$

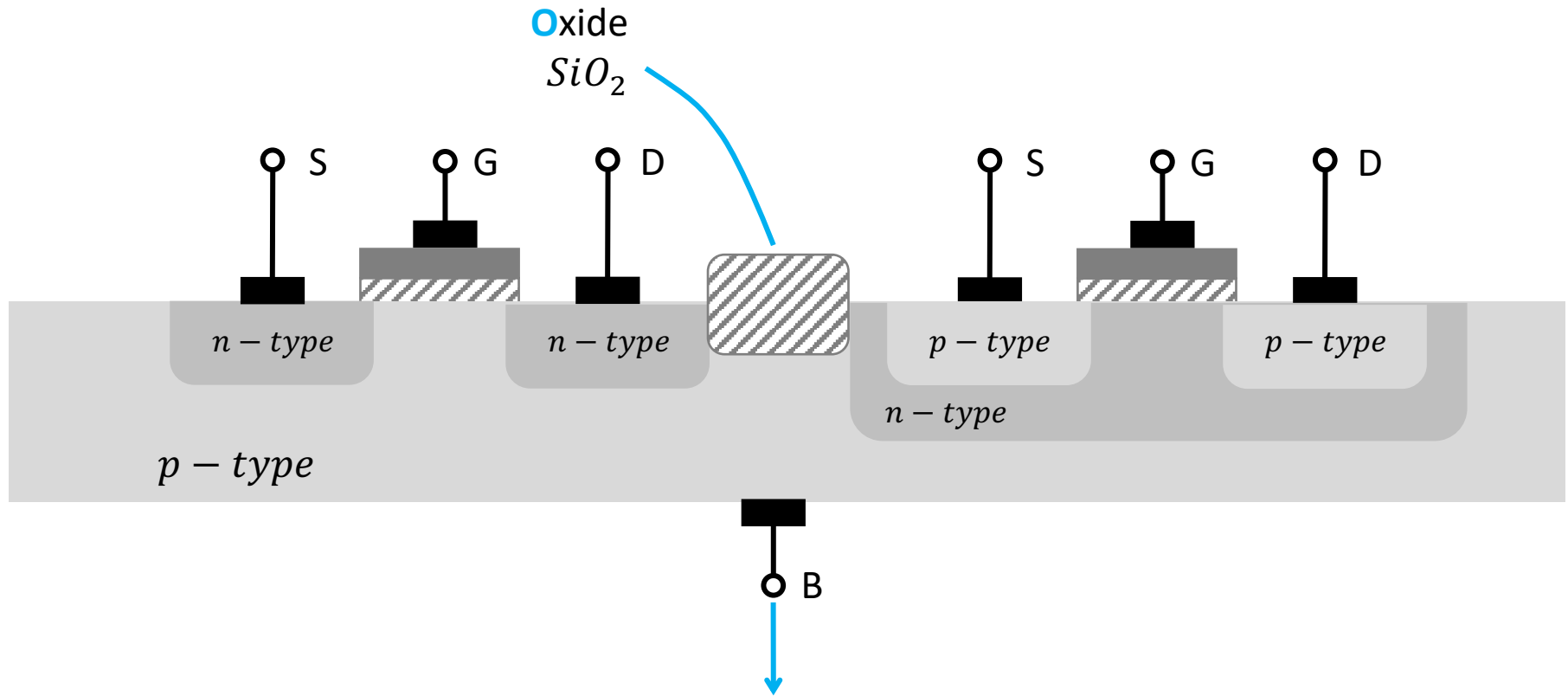
$$i_D = 0$$

$$v_o = i_D R_D = 0$$

$$v_{SD} = V_{dd} - v_o = V_{dd}$$

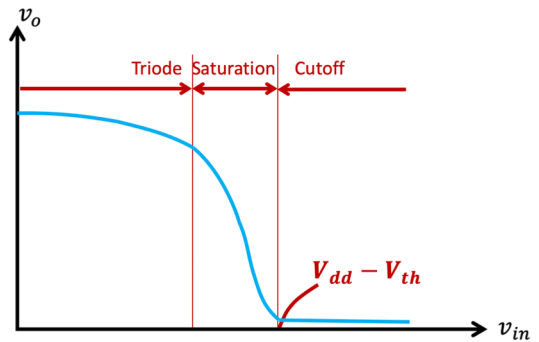
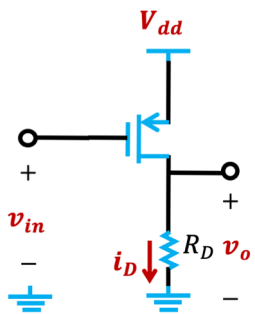
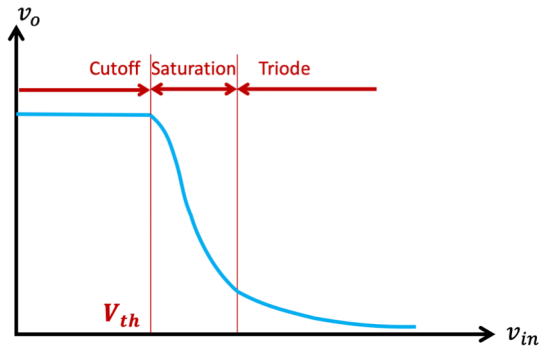
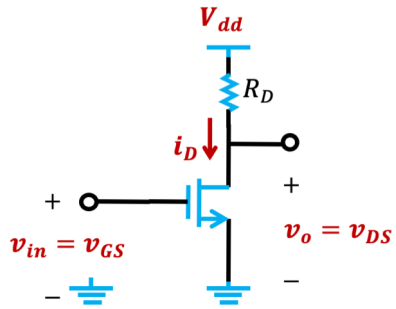


# Recall: Complementary MOS (CMOS)

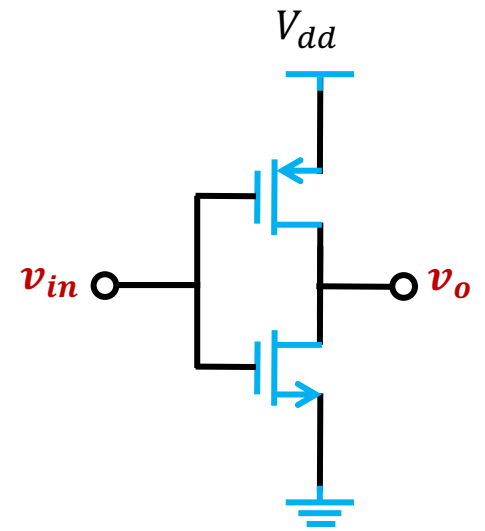


Connected to the most negative power supply to avoid body-effect

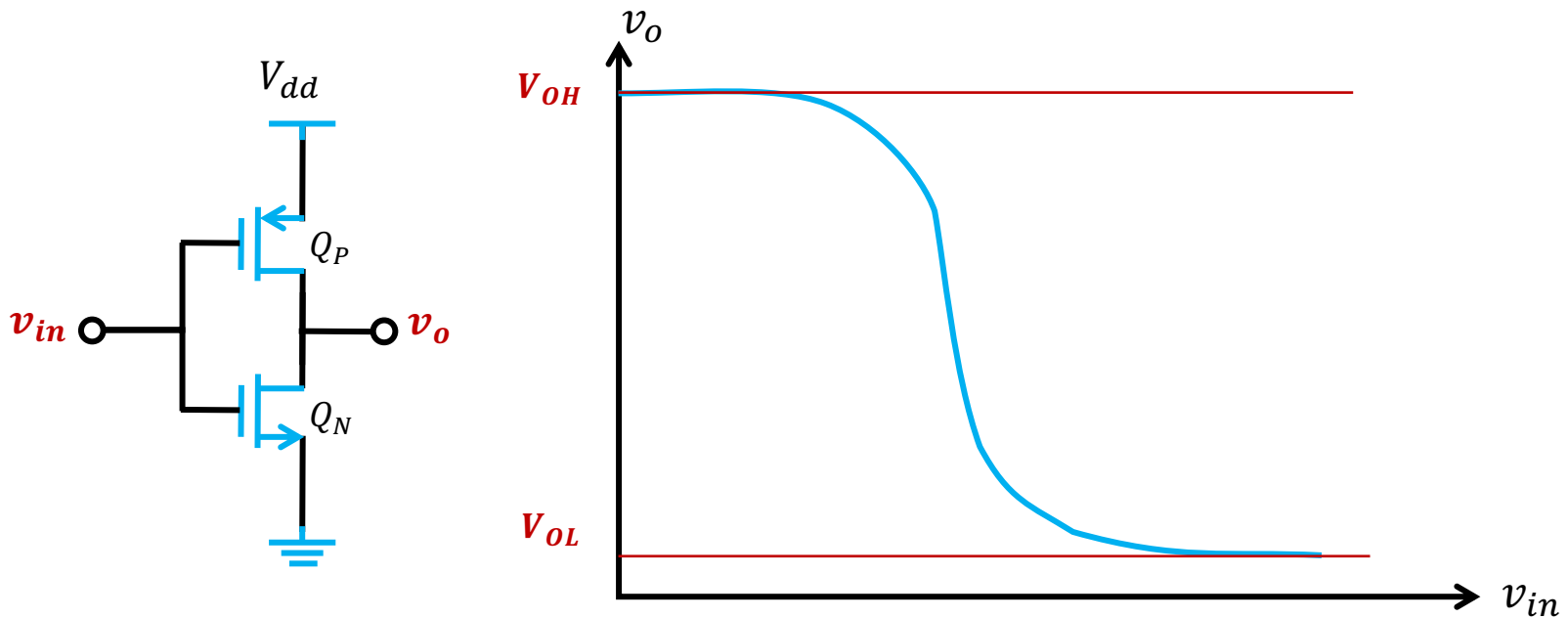
# CMOS Inverter



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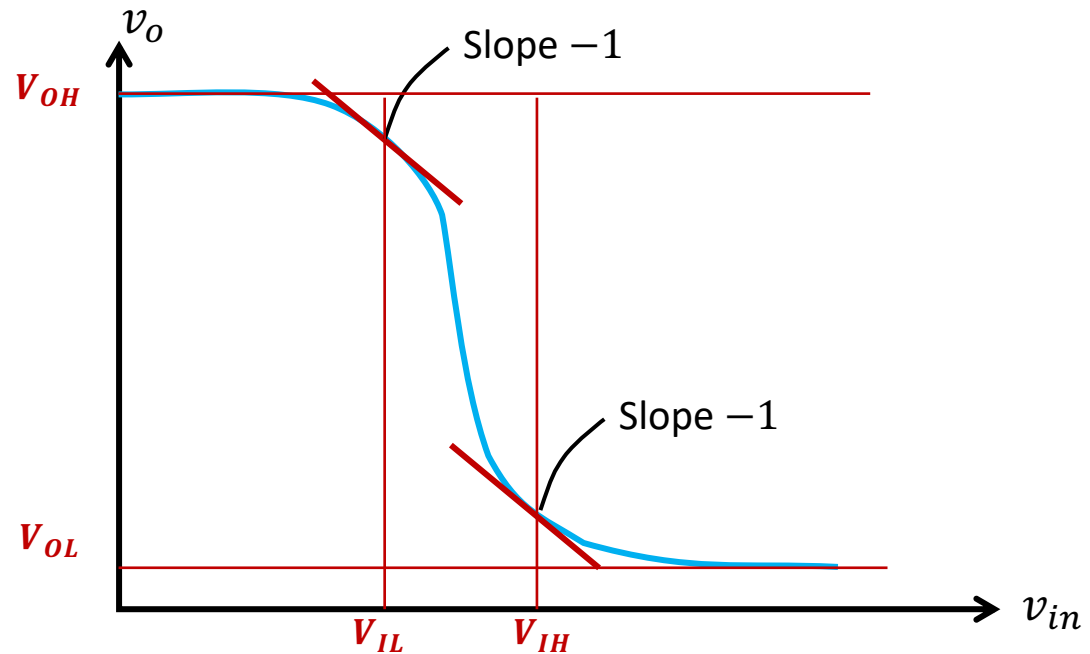
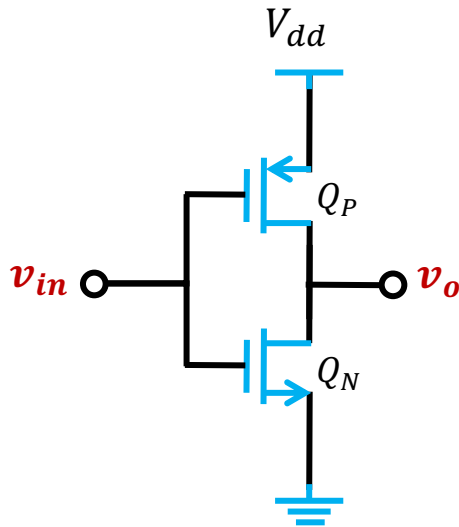


# Voltage Transfer Characteristic (VTC)



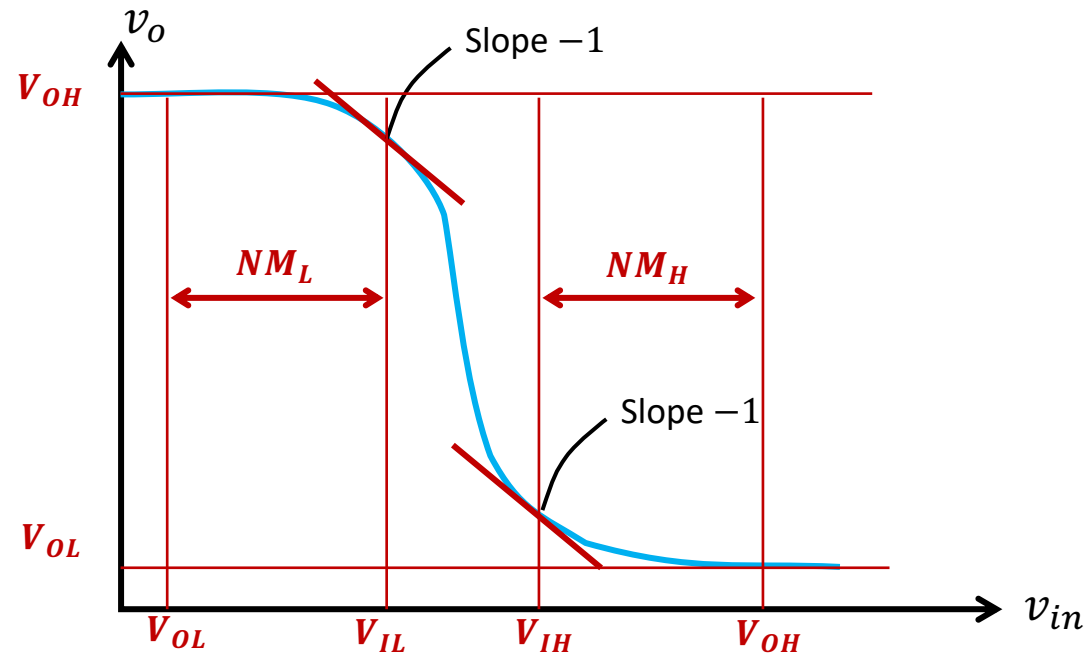
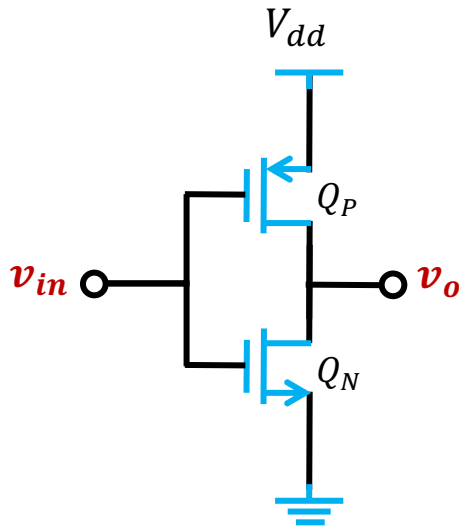
- Define OUTPUT HIGH LEVEL  $V_{OH}$   Logic-1 output
- Define OUTPUT LOW LEVEL  $V_{OL}$   Logic-0 output

# Voltage Transfer Characteristic (VTC)



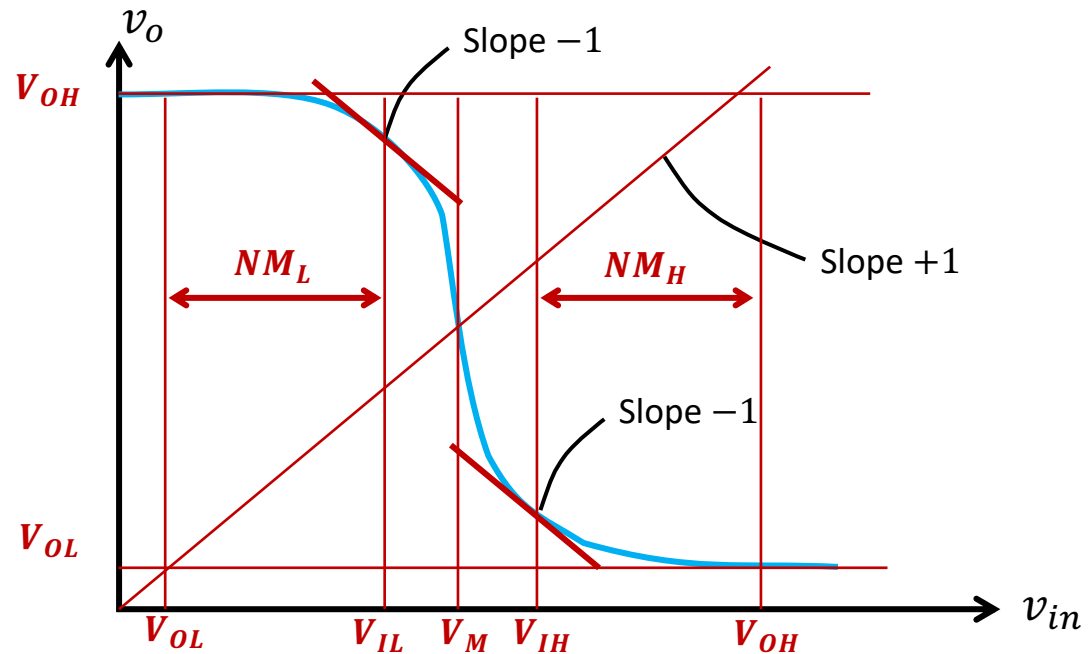
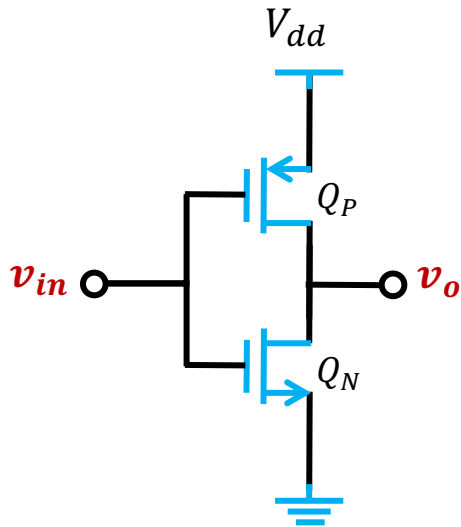
- Define INPUT HIGH LEVEL  $V_{IH}$  ➡ Minimum input to be presented as logic 1
- Define INPUT LOW LEVEL  $V_{IL}$  ➡ Maximum input to be presented as logic 0

# Voltage Transfer Characteristic (VTC)



- Define NOISE MARGIN FOR LOW INPUT  $NM_L = V_{IL} - V_{OL}$
- Define NOISE MARGIN FOR HIGH INPUT  $NM_H = V_{OH} - V_{IH}$

# Voltage Transfer Characteristic (VTC)

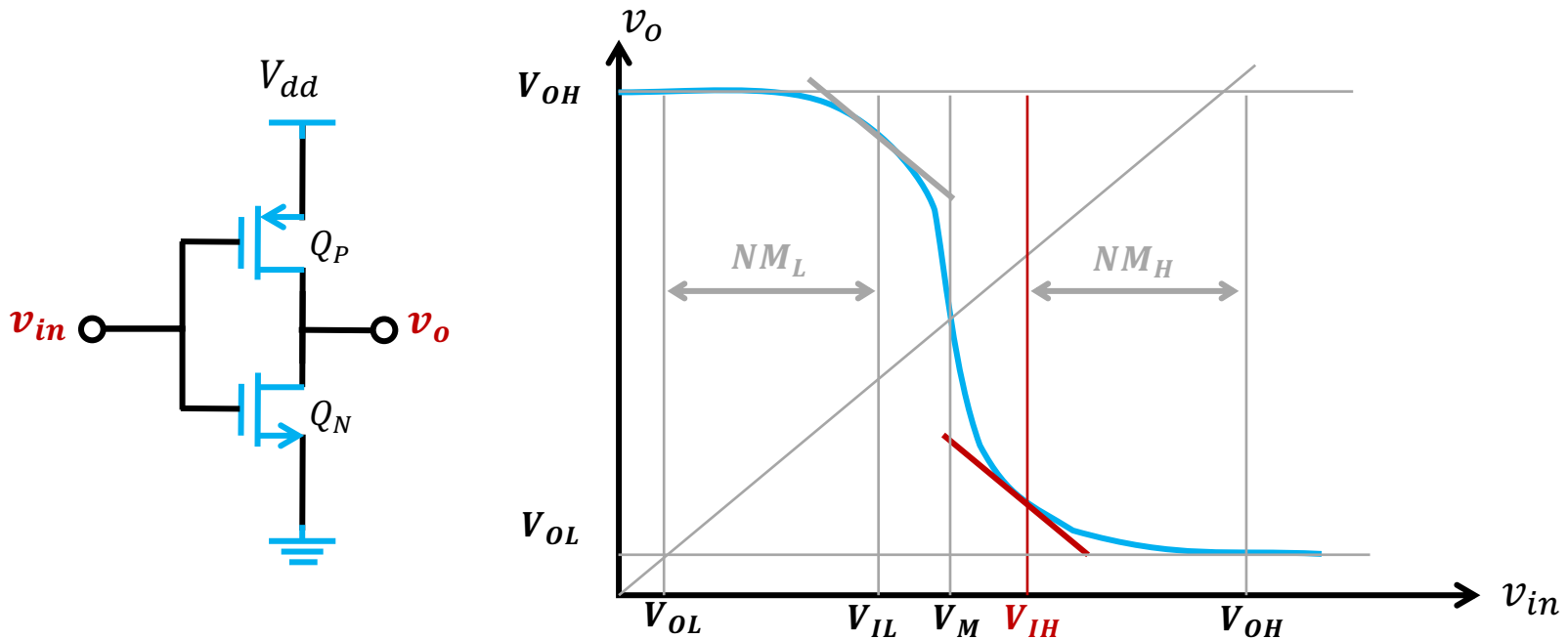


- Define midpoint of the VTC

$$V_M \xrightarrow{\text{ideally}} \frac{V_{dd}}{2}$$



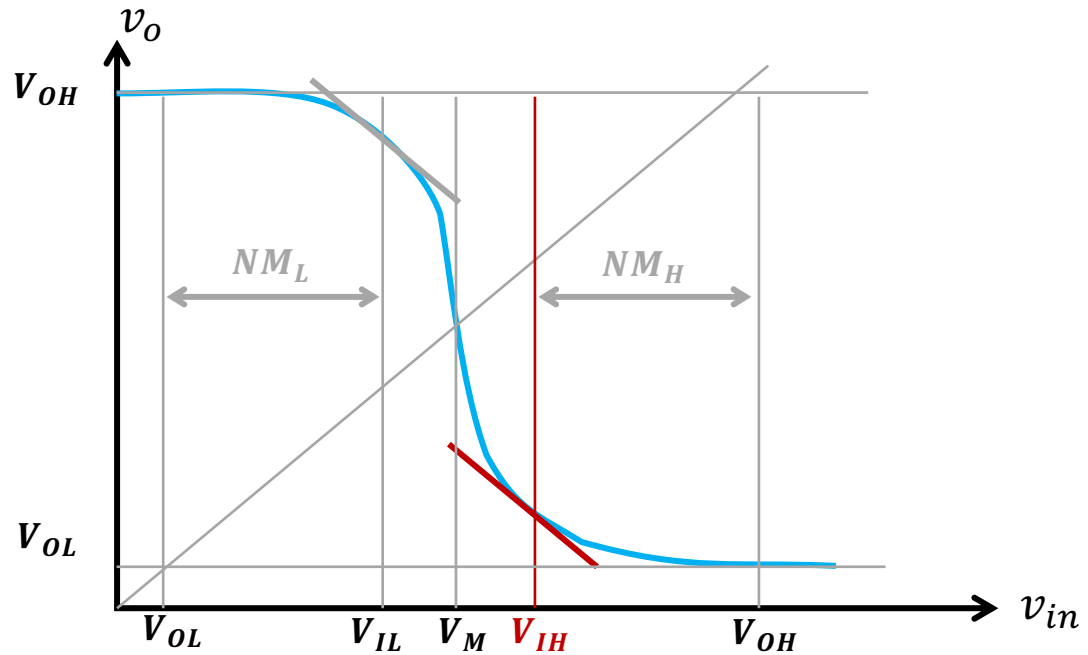
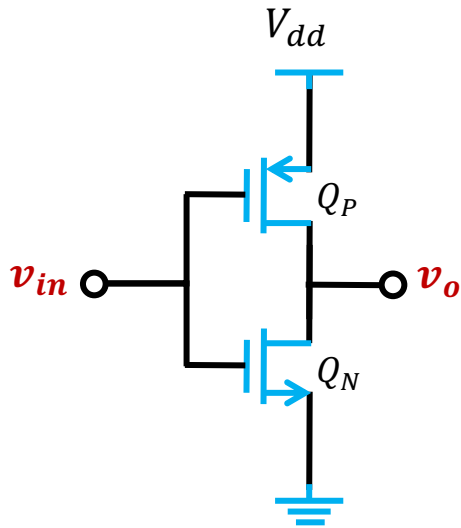
# Voltage Transfer Characteristic (VTC)



- @  $v_{in} = V_{IH}$ 

|   |  |   |                                   |
|---|--|---|-----------------------------------|
| { | $v_{SG,P} \geq V_{th}$<br>$v_{DG,P} \leq V_{th}$ | ➤ | $Q_P$ biased in Saturation region |
| { | $v_{GS} \geq V_{th}$<br>$v_{GD} \geq V_{th}$     | ➤ | $Q_N$ biased in Triode region     |

# Voltage Transfer Characteristic (VTC)



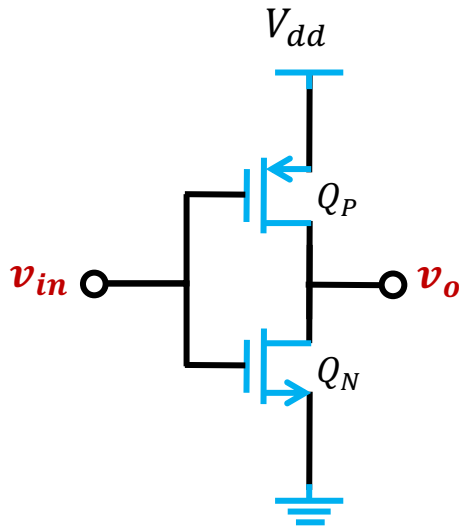
▪ @  $v_{in} = V_{IH}$

$Q_P \in$  Saturation region

$Q_N \in$  Triode region

$$\begin{cases} i_{Dp} = i_{Dn} \\ i_{Dn} = (\mu_n C_{ox}) \left(\frac{W}{L}\right)_n \left[ (v_{GS,N} - V_{th}) v_{DS,N} - \frac{1}{2} v_{DS,N}^2 \right] \\ i_{Dp} = \frac{1}{2} (\mu_p C_{ox}) \left(\frac{W}{L}\right)_p (|v_{GS,G}| - V_{th})^2 \end{cases}$$

# Voltage Transfer Characteristic (VTC)



$$\begin{cases} i_{Dp} = i_{Dn} \\ i_{Dn} = (\mu_n C_{ox}) \left(\frac{W}{L}\right)_n \left[ (v_{GS,N} - V_{th}) v_{DS,N} - \frac{1}{2} v_{DS,N}^2 \right] \\ i_{Dp} = \frac{1}{2} (\mu_p C_{ox}) \left(\frac{W}{L}\right)_p (|v_{GS,G}| - V_{th})^2 \end{cases}$$

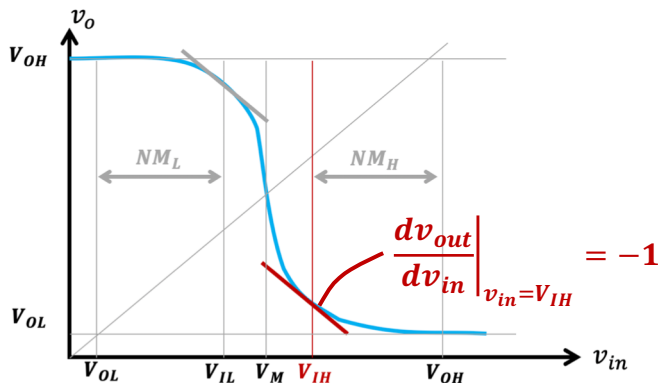
Assume  $(\mu_n C_{ox}) \left(\frac{W}{L}\right)_n = (\mu_p C_{ox}) \left(\frac{W}{L}\right)_p$

$$(v_{in} - V_{th}) v_{out} - \frac{1}{2} v_{out}^2 = \frac{1}{2} (V_{dd} - v_{in} - V_{th})^2$$

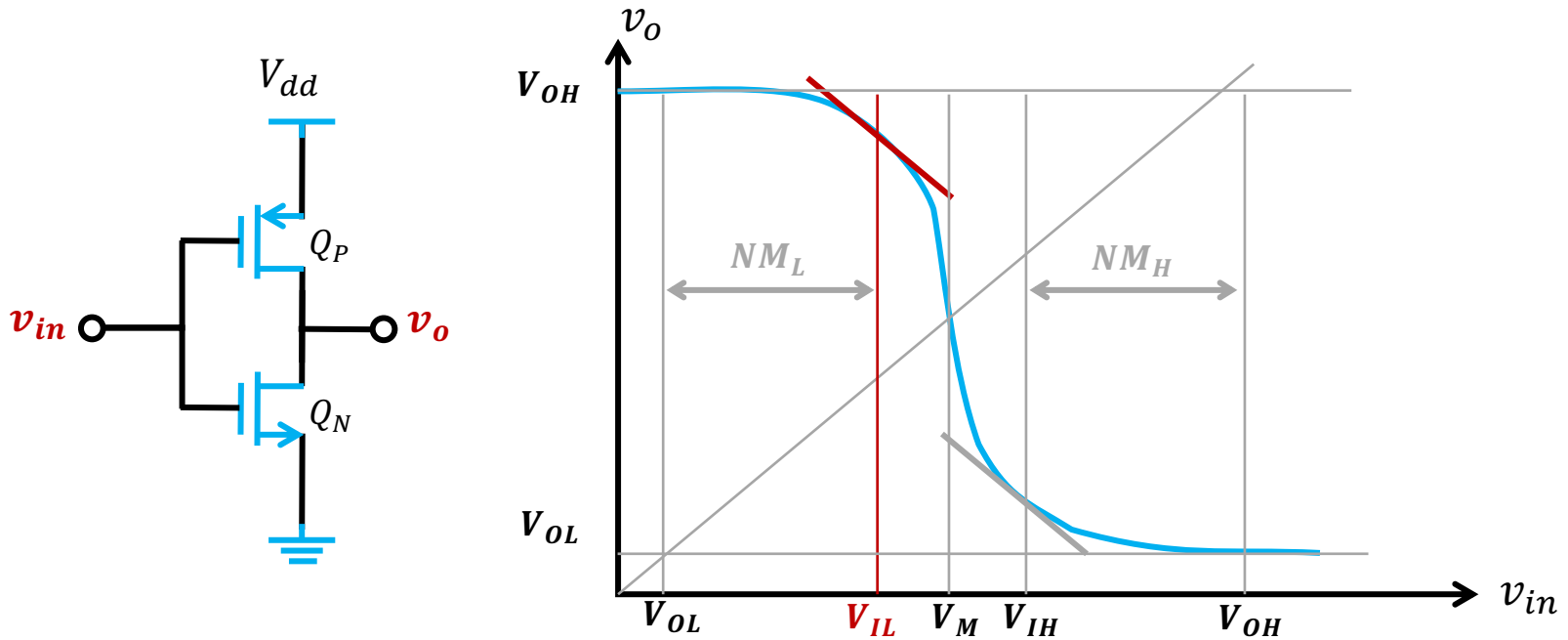
$$(v_{in} - V_{th}) \frac{dv_{out}}{dv_{in}} + v_{out} - v_{out} \frac{dv_{out}}{dv_{in}} = -(V_{dd} - v_{in} - V_{th})$$

$$v_{out} = -\frac{V_{dd}}{2} + v_{in}$$

$$V_{IH} = \frac{5V_{dd} - 2V_{th}}{8}$$



# Voltage Transfer Characteristic (VTC)



- @  $v_{in} = V_{IL}$

$$\begin{cases} v_{SG,P} \geq V_{th} \\ v_{DG,P} \geq V_{th} \end{cases}$$



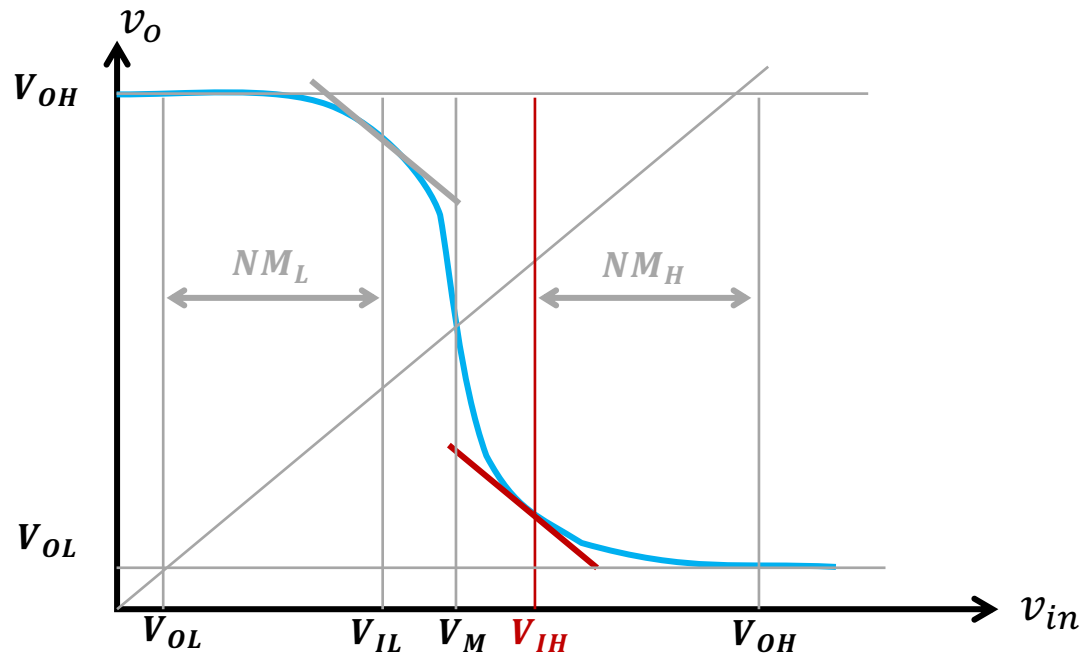
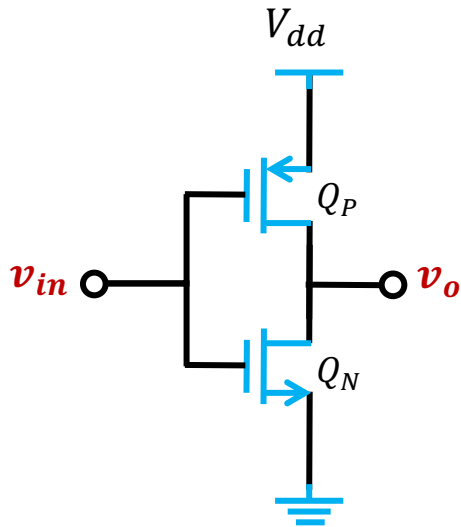
$Q_P$  biased in  
Triode region

$$\begin{cases} v_{GS} \geq V_{th} \\ v_{GD} \leq V_{th} \end{cases}$$



$Q_N$  biased in  
Saturation region

# Voltage Transfer Characteristic (VTC)



▪ @  $v_{in} = V_{IL}$

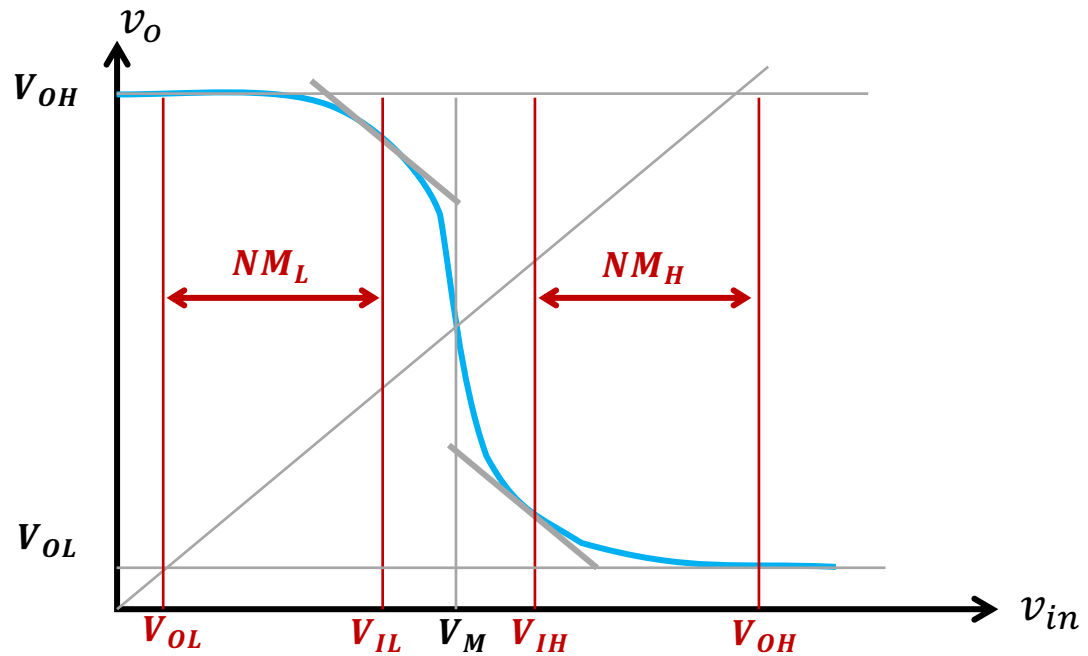
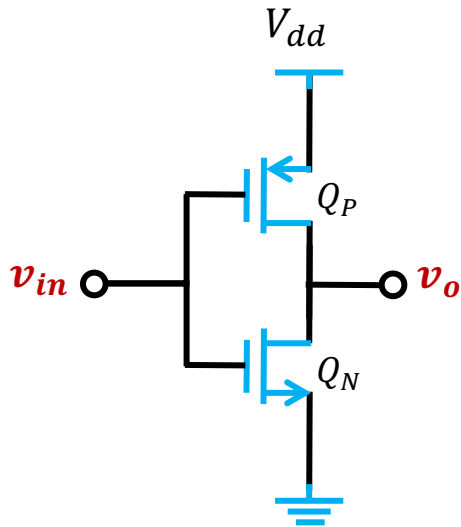
$Q_P \in$  Triode region

$Q_N \in$  Saturation region

▪ Similarly as @  $v_{in} = V_{IH}$

$$V_{IL} = \frac{3V_{dd} + 2V_{th}}{8}$$

# Voltage Transfer Characteristic (VTC)



$$\begin{cases} V_{IH} = \frac{5V_{dd} - 2V_{th}}{8} \\ V_{IL} = \frac{3V_{dd} + 2V_{th}}{8} \end{cases}$$

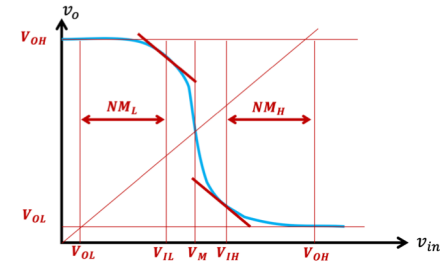
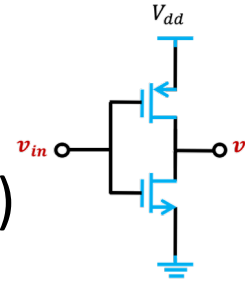
$$NM_L = V_{IL} - \frac{V_{OL}}{0} = \frac{3V_{dd} + 2V_{th}}{8}$$

$$NM_H = \frac{V_{OH}}{V_{dd}} - V_{IH} = \frac{3V_{dd} + 2V_{th}}{8}$$

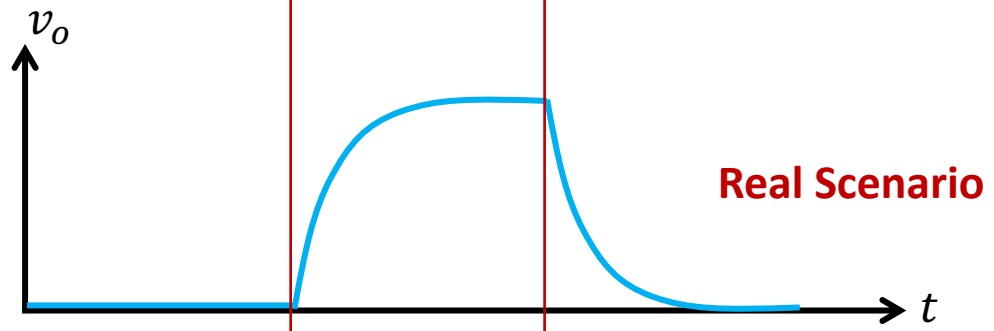
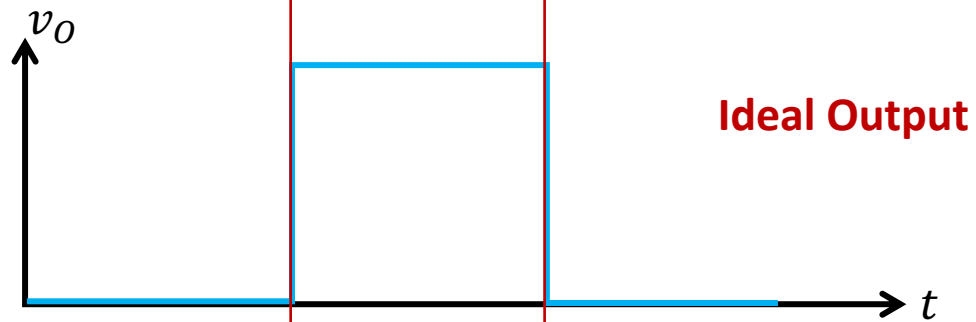
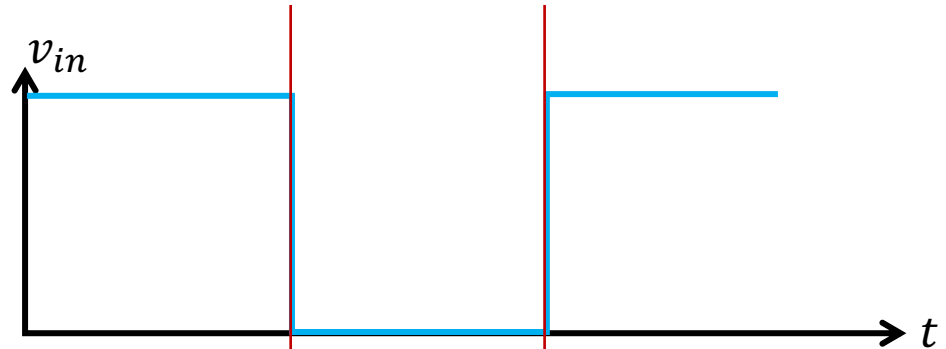
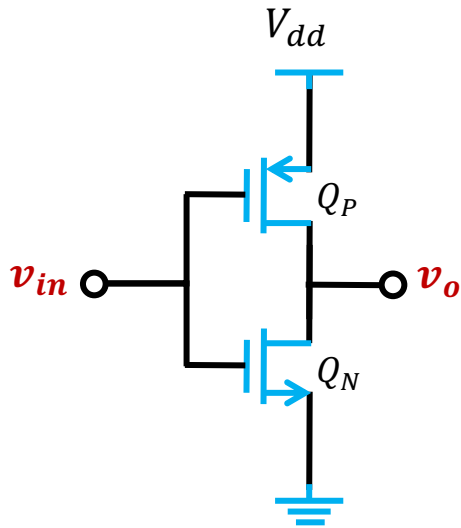


# Outline

- CMOS Inverters
  - Voltage Transfer Characteristic (VTC)
  - Noise margin
  - **Propagation delay**

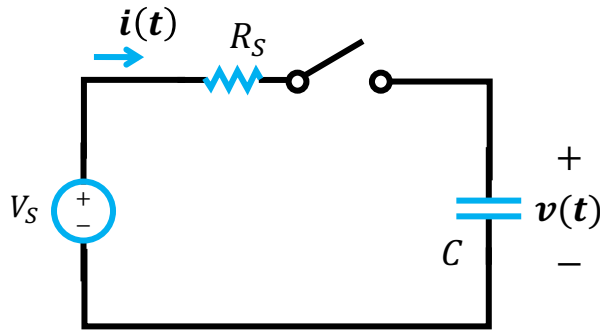


# Propagation delay



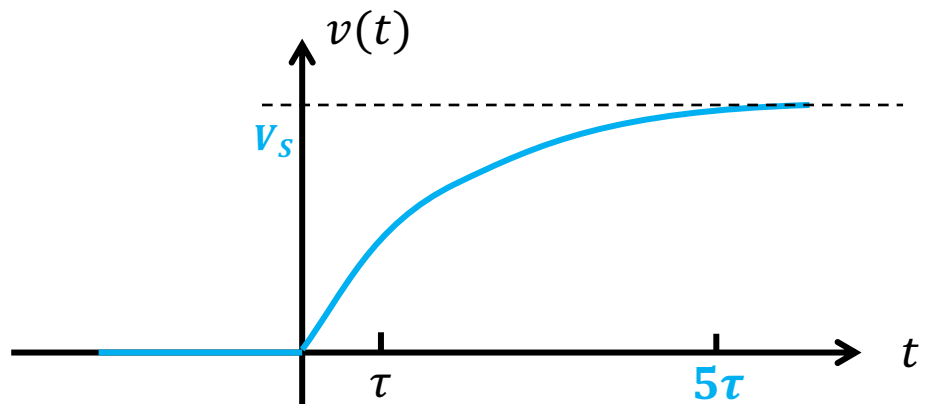
# Recall: charging of a capacitor

**QUESTION:** Assume there is no charge on the capacitor  $C$  before the switch is turned on. Find the response after the switch is turned on.

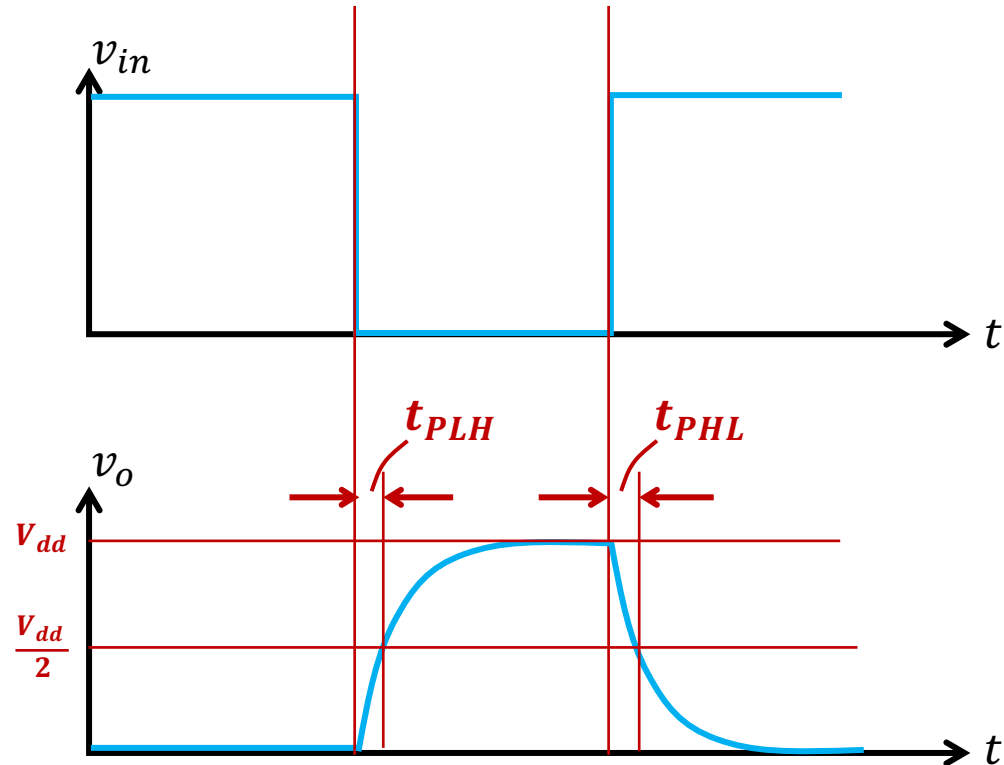
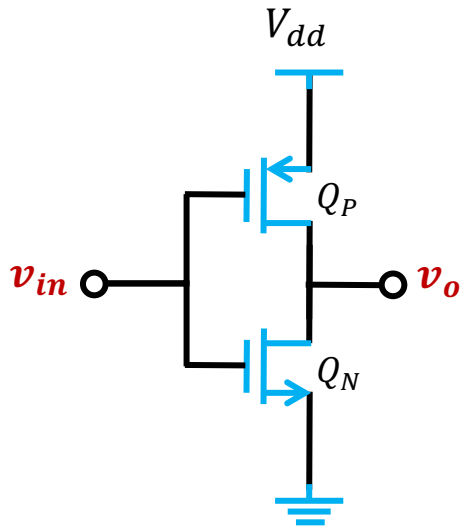


$$\frac{d}{dt}v(t) + \frac{1}{RC}v(t) = \frac{1}{RC}V_S$$

Solution:  $v(t) = V_S - V_S e^{-\frac{1}{RC}t}$

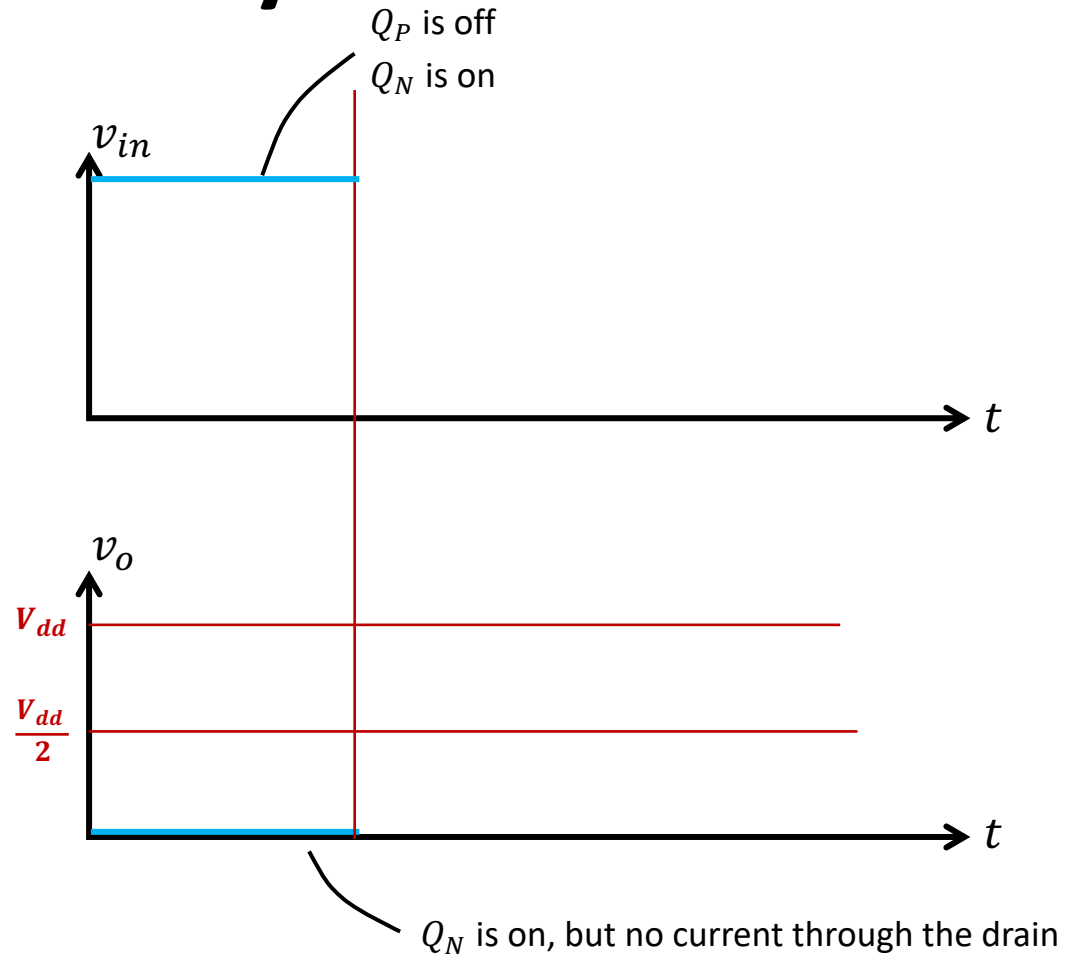
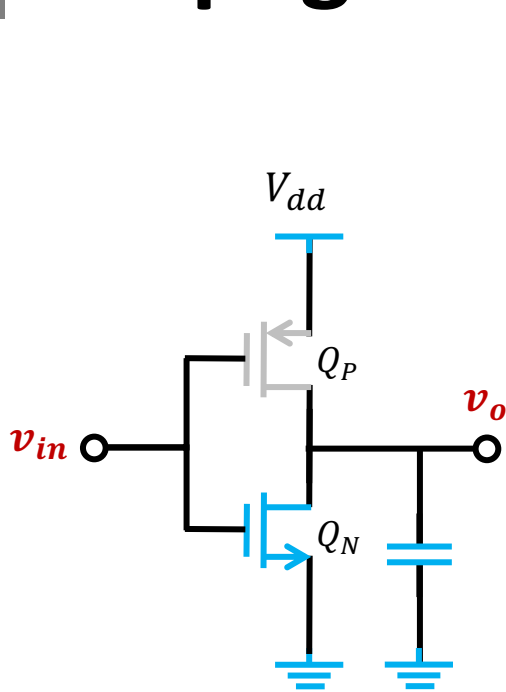


# Propagation delay

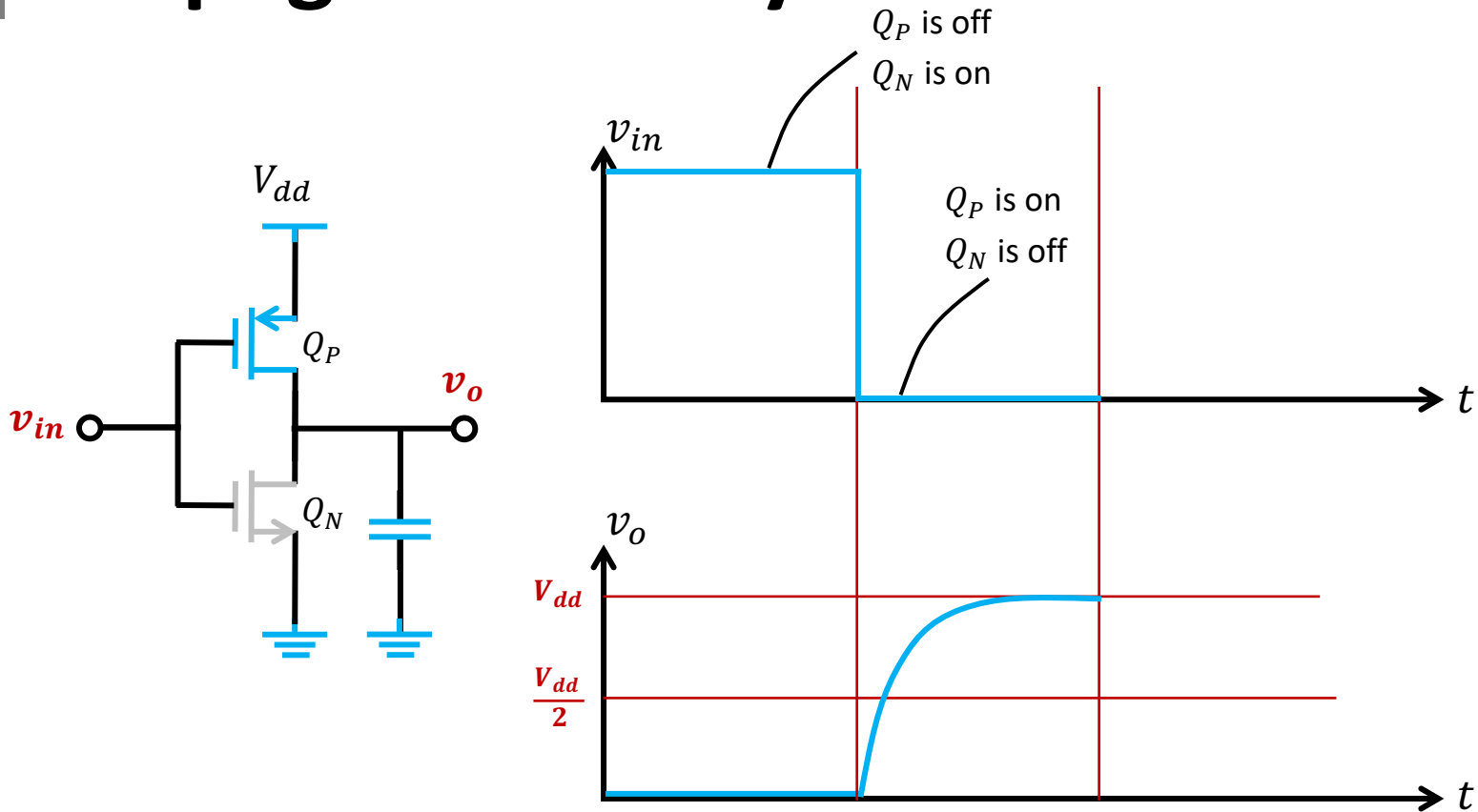


- Propagation delay for the output from LOW to HIGH  $t_{PLH}$
- Propagation delay for the output from HIGH to LOW  $t_{PHL}$

# Propagation delay

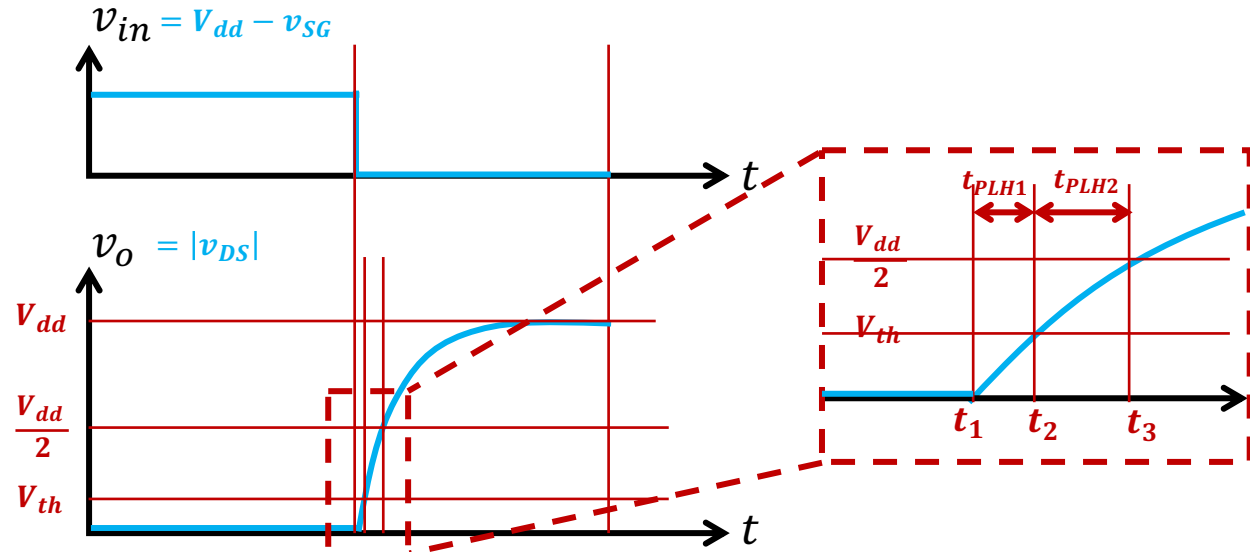
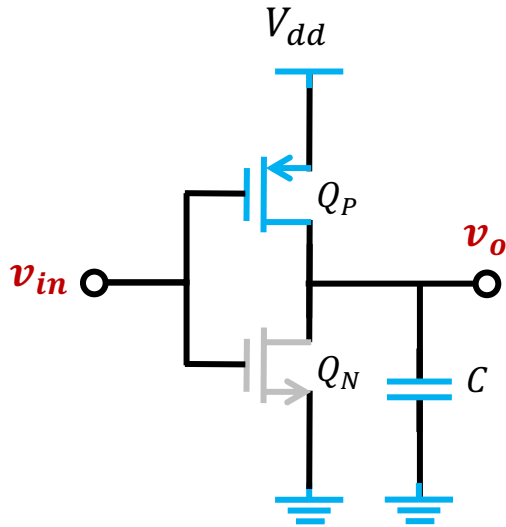


# Propagation delay





# Propagation delay



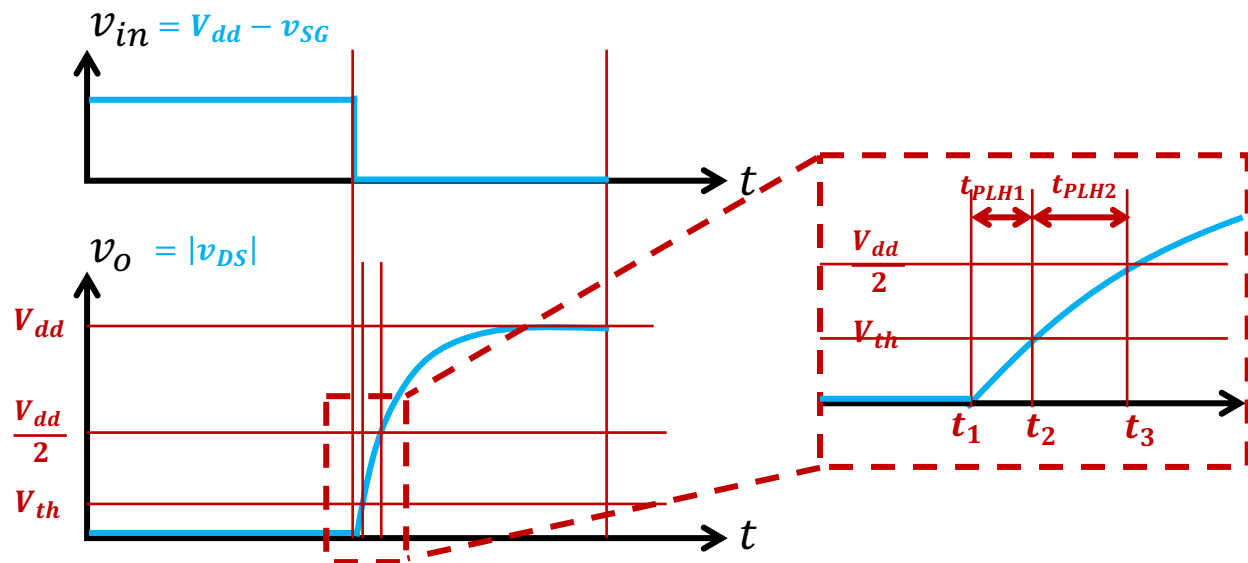
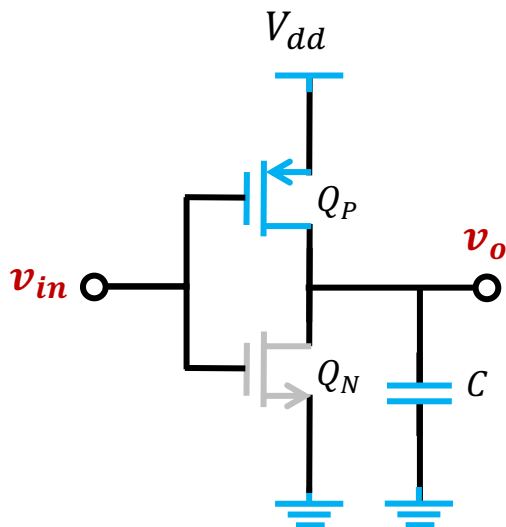
- While  $t \in [t_1^+, t_2]$

$$\begin{cases} v_{SG} = V_{dd} \geq V_{th} \\ v_{DG} = v_o \leq V_{th} \end{cases}$$



$Q_P$  biased in  
Saturation region

# Propagation delay



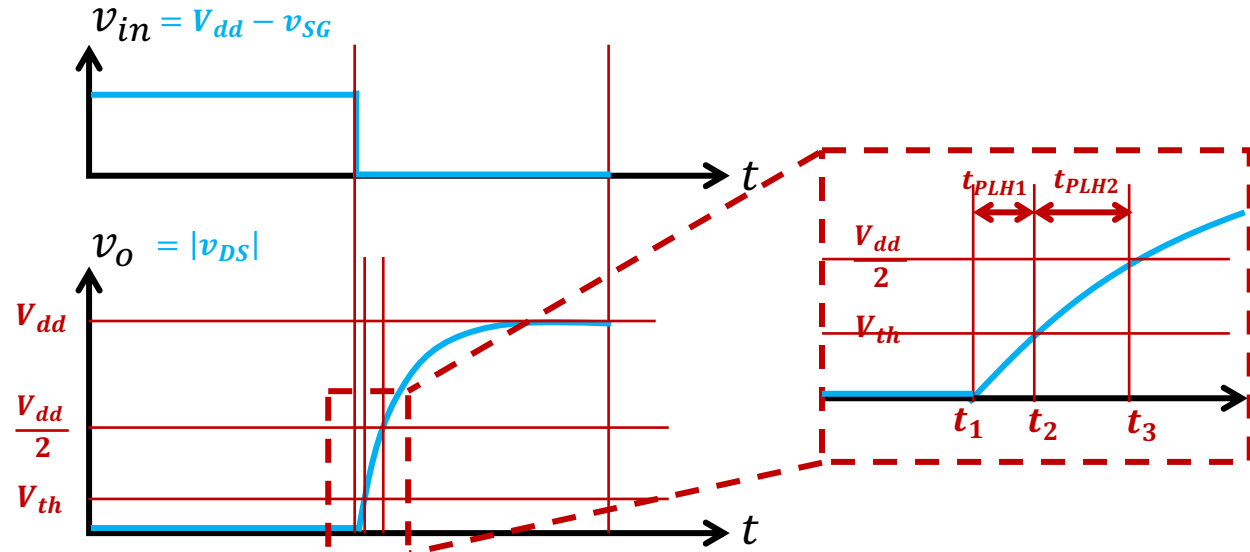
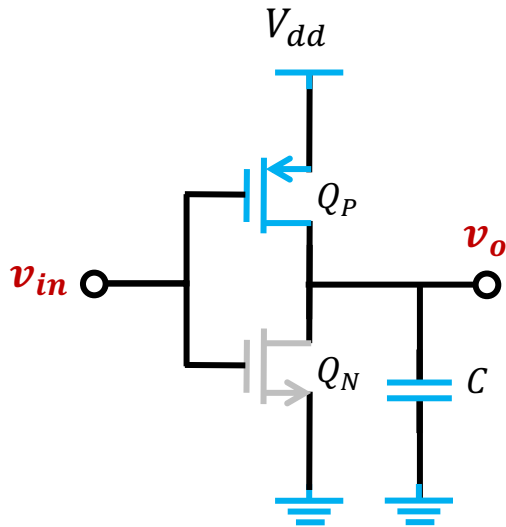
- While  $t \in [t_1^+, t_2]$

$Q_P \in$  Saturation region

- The drain current  $i_{D1} = \frac{1}{2} k_p (|v_{GS}| - V_{th})^2$

- The delay  $t_{PLH1} = t_2 - t_1 = C \frac{\Delta v_{out}}{i_D} = C \frac{V_{th}}{i_{D1}} = 2C \frac{V_{th}}{k_p (V_{dd} - V_{th})^2}$

# Propagation delay



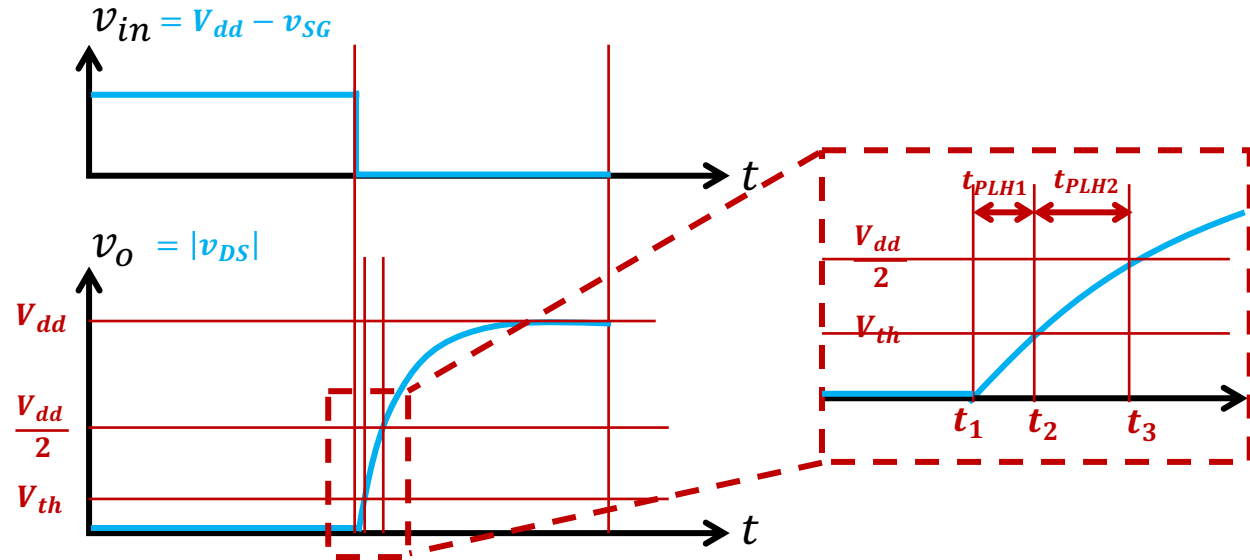
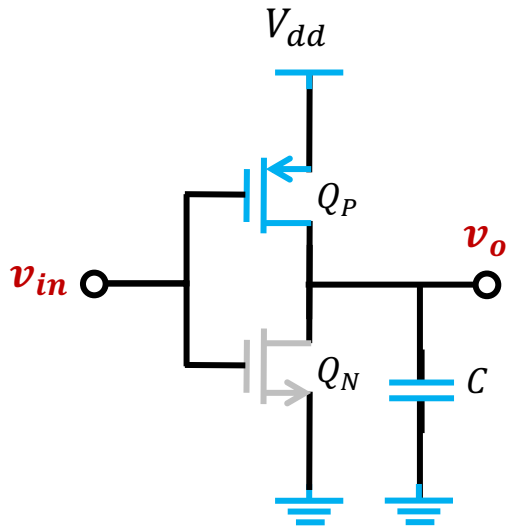
- While  $t \in [t_2^+, t_3]$

$$\begin{cases} v_{SG} = V_{dd} \geq V_{th} \\ v_{DG} = v_o > V_{th} \end{cases}$$



$Q_P$  biased in triode region

# Propagation delay



- While  $t \in [t_2^+, t_3]$

$Q_P \in$  Triode region

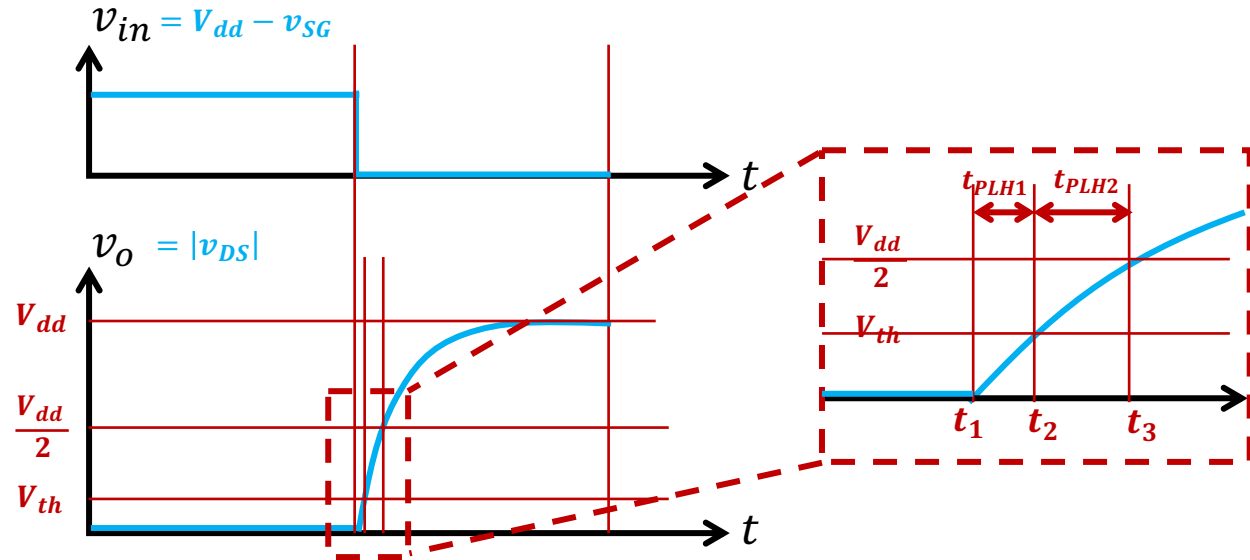
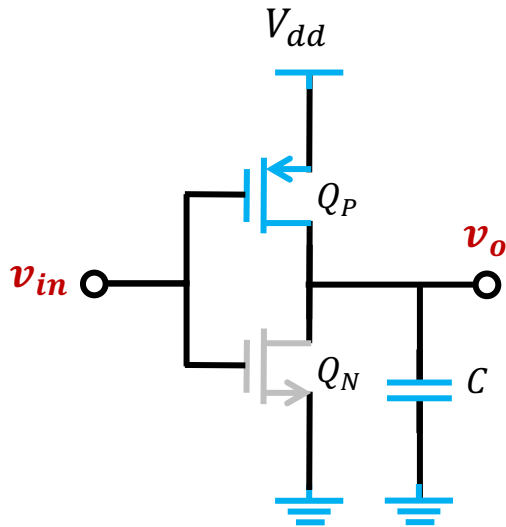
- The drain current

$$i_{D2} = k_p \left[ (|v_{GS}| - V_{th}) |v_{DS}| - \frac{1}{2} v_{DS}^2 \right]$$

- The delay

$$t_{PLH1} = \int_{t_2}^{t_3} C \frac{dv_o}{di_{D2}} = \frac{C}{k_p} \int_{V_{th}}^{\frac{V_{dd}}{2}} \frac{1}{(V_{dd} - V_{th})(V_{dd} - v_o) - \frac{1}{2}(V_{dd} - v_o)^2} dv_o$$

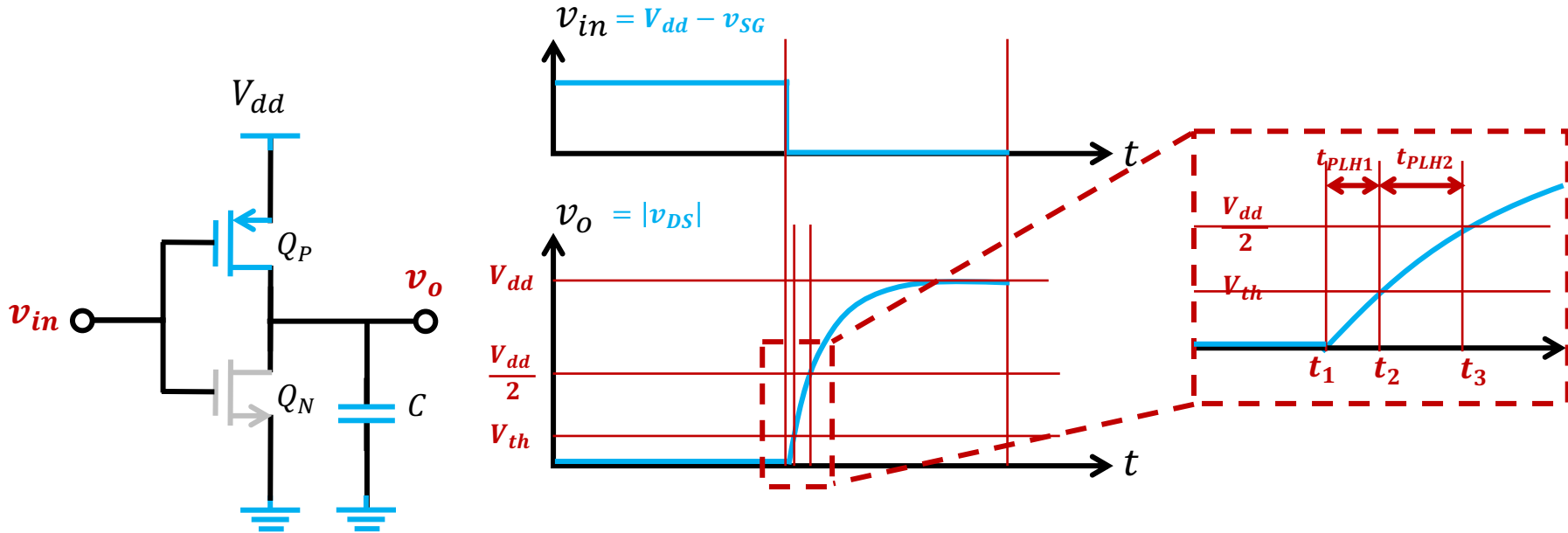
# Propagation delay



- The delay

$$\begin{aligned}
 t_{PLH1} &= \frac{C}{k_p} \int_{V_{th}}^{\frac{V_{dd}}{2}} \frac{1}{(V_{dd} - V_{th})(V_{dd} - v_o) - \frac{1}{2}(V_{dd} - v_o)^2} dv_o \\
 &= \frac{C}{k_p(V_{dd} - V_{th})} \ln \left( \frac{2(V_{dd} - V_{th}) - (V_{dd} - v_o)}{V_{dd} - v_o} \right) \Bigg|_{V_{th}}^{\frac{V_{dd}}{2}} \\
 &= \frac{C}{k_p(V_{dd} - V_{th})} \ln \left( \frac{3V_{dd} - 4V_{th}}{V_{dd}} \right)
 \end{aligned}$$

# Propagation delay



- The total delay  $t_{PLH} = t_{PLH1} + t_{PLH2}$

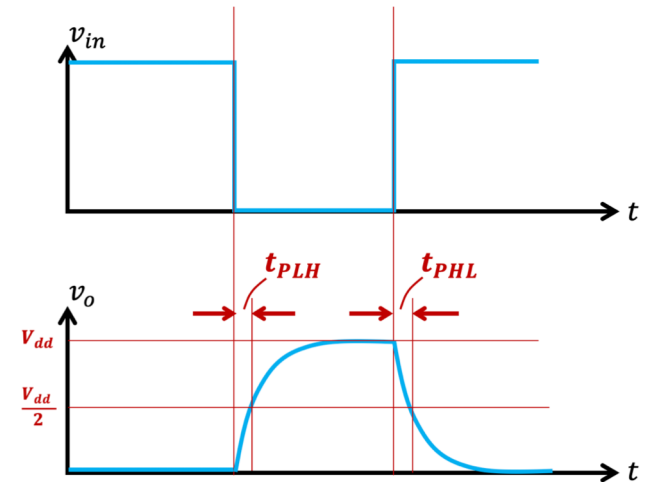
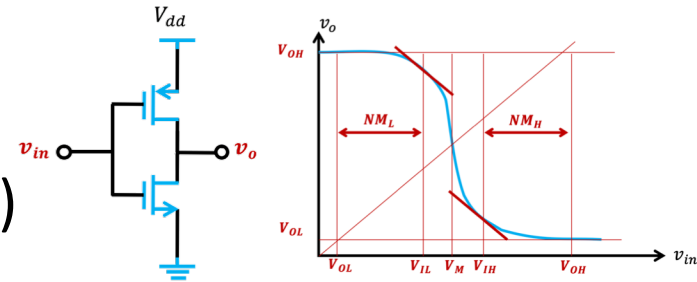
$$= 2C \frac{V_{th}}{k_p (V_{dd} - V_{th})^2} + \frac{C}{k_p (V_{dd} - V_{th})} \ln \left( \frac{3V_{dd} - 4V_{th}}{V_{dd}} \right)$$

- Typically  $V_{th} = 0.2V_{dd}$   $\Rightarrow t_{PLH} \approx \frac{1.6C}{k_p V_{dd}}$

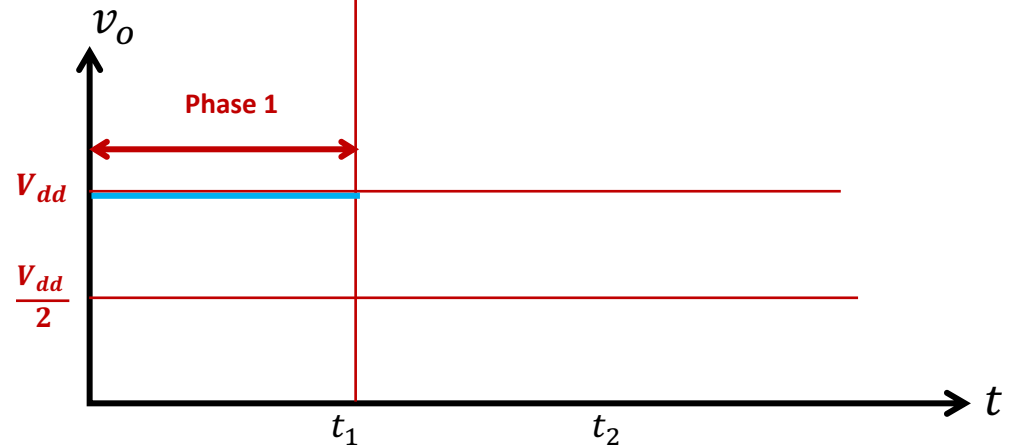
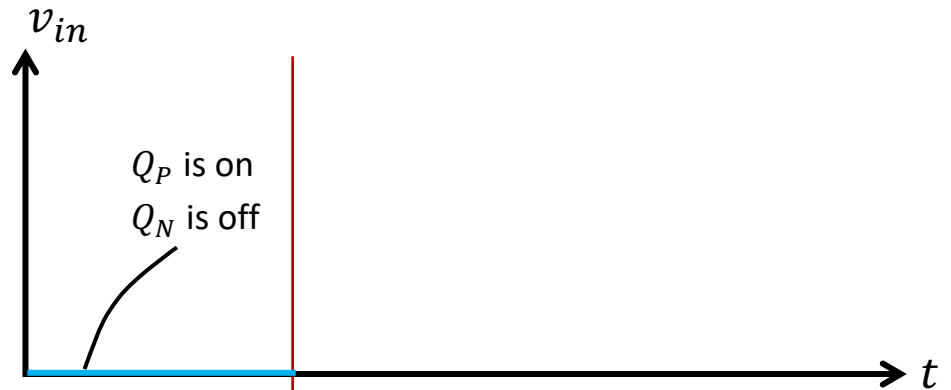
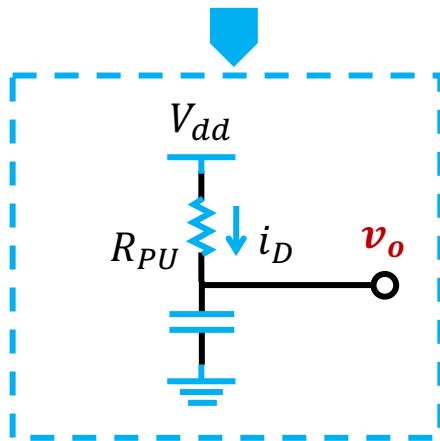
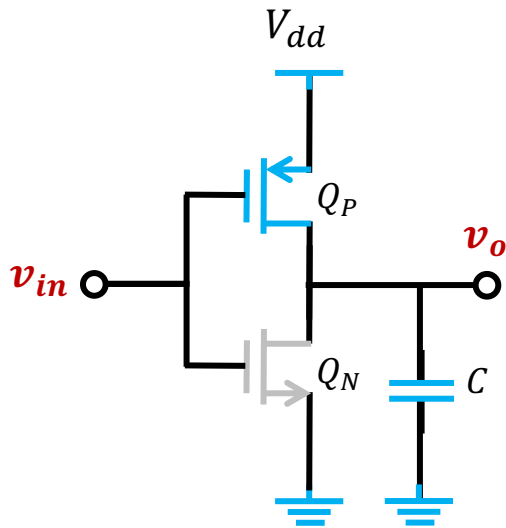


# Outline

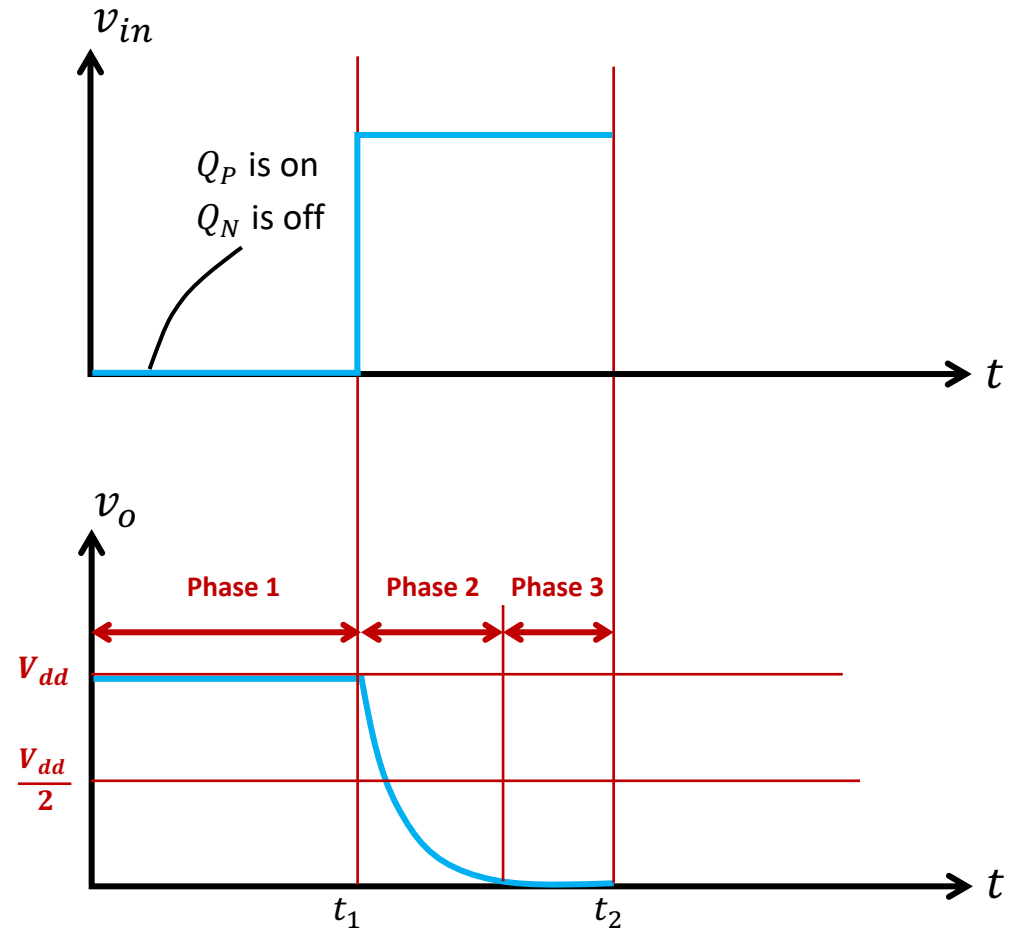
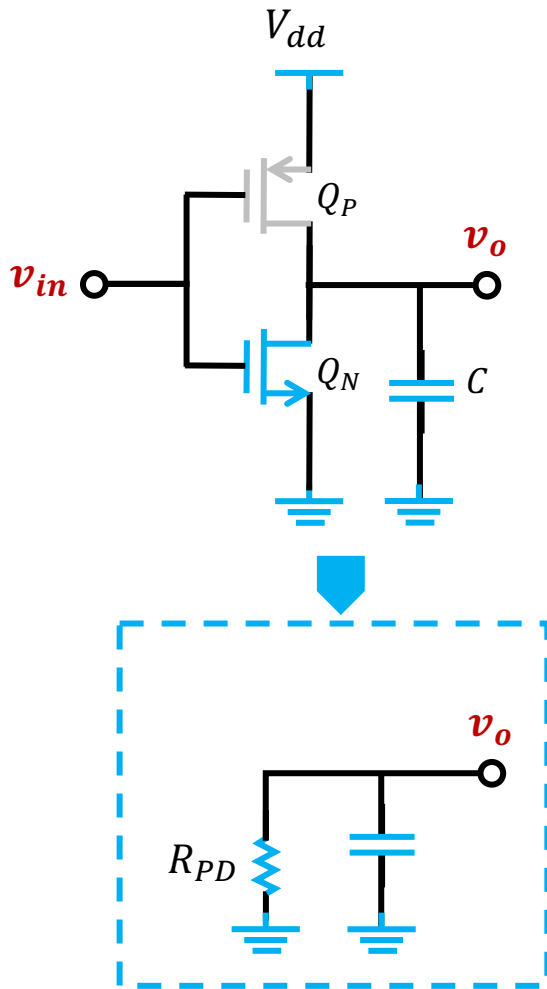
- CMOS Inverters
  - Voltage Transfer Characteristic (VTC)
  - Noise margin
  - Propagation delay
  - **Power consumption**



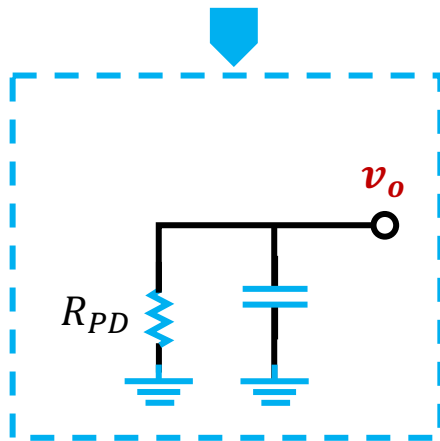
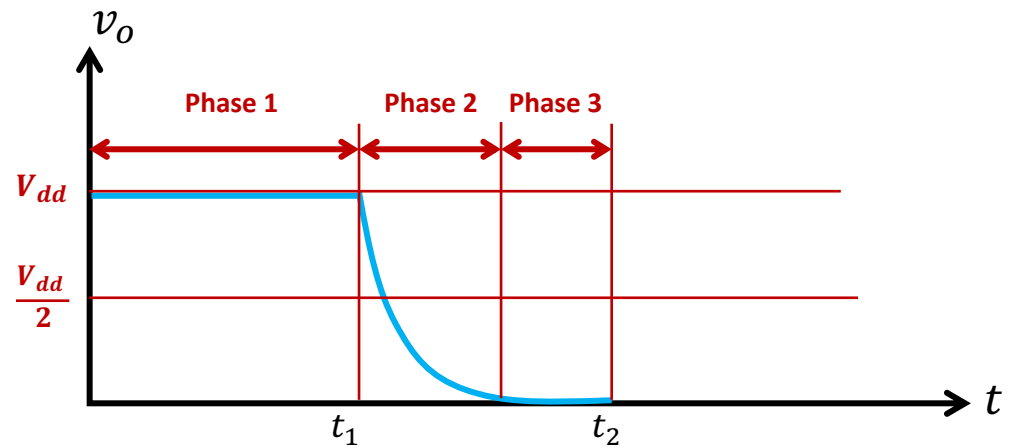
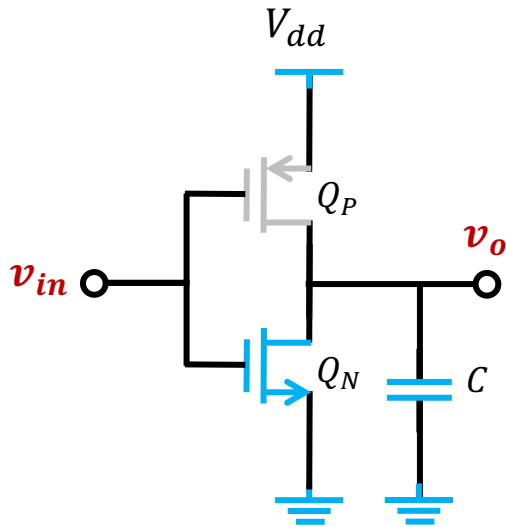
# Power Consumption



# Power Consumption



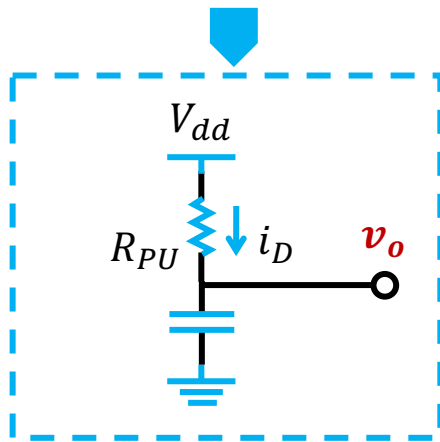
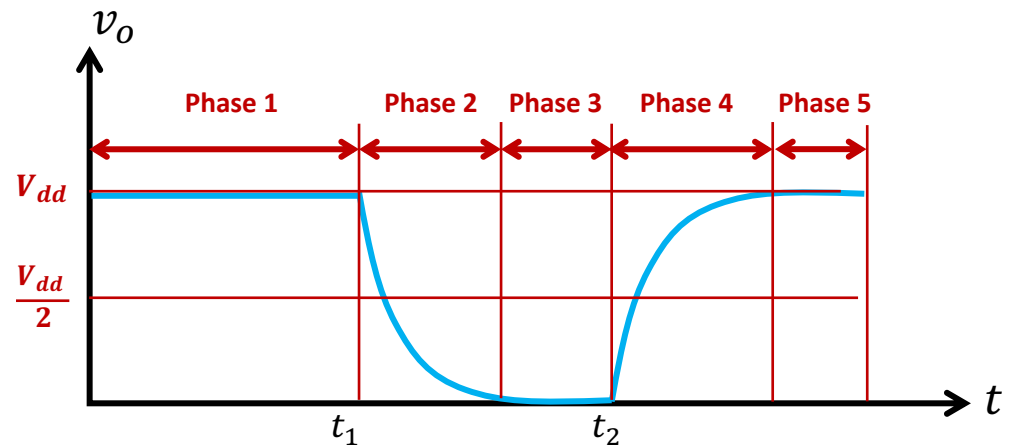
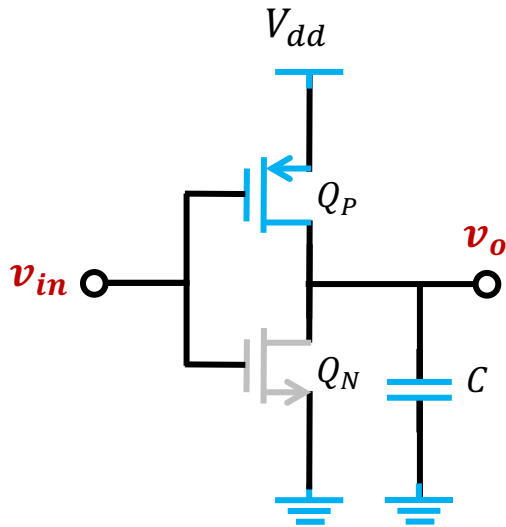
# Power Consumption



- @ Phase 1, energy stored in  $C$  is  $E_{stored} = \frac{1}{2} CV_{dd}^2$
- @ Phase 3, NO energy left
- Thus, energy dissipated in  $R_{PD}$  @Phase 2 is

$$E_{dissipated} = \frac{1}{2} CV_{dd}^2$$

# Power Consumption

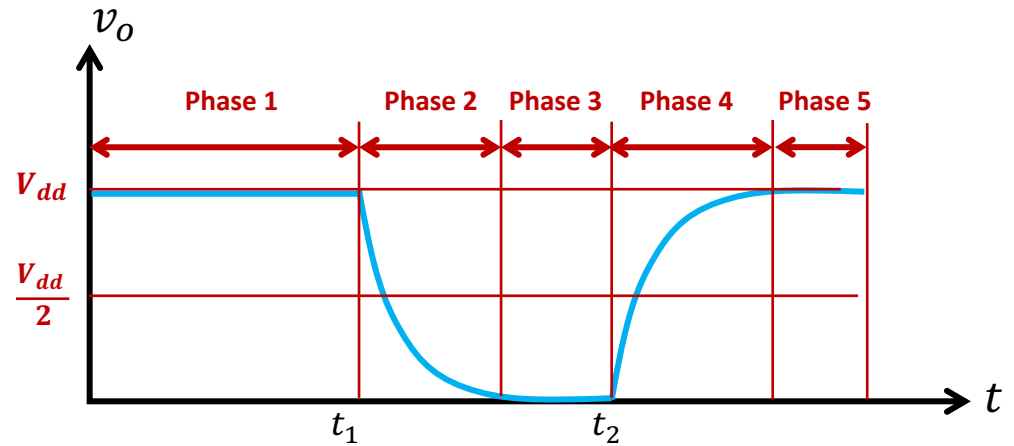
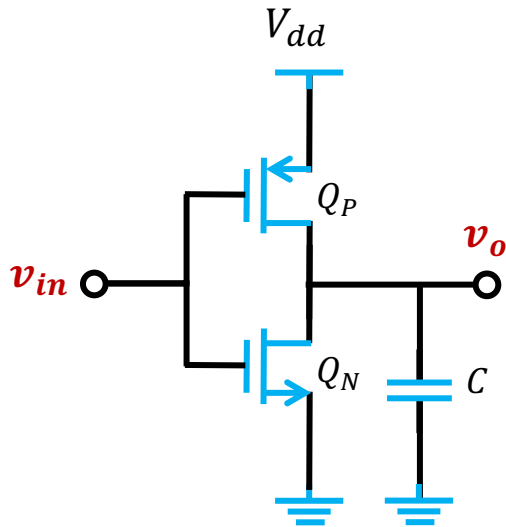


- @ Phase 4, energy provided by the power

$$E_{V_{dd}} = \int V_{dd} i_D dt = V_{dd} \int i_D dt = V_{dd} Q = CV_{dd}^2$$

- @ Phase 5, energy stored in  $C$  is  $E_{stored} = \frac{1}{2} CV_{dd}^2$
- Energy dissipated in  $R_{PU}$  is  $E_{dissipated} = \frac{1}{2} CV_{dd}^2$

# Power Consumption



- Total dissipated energy per cycle

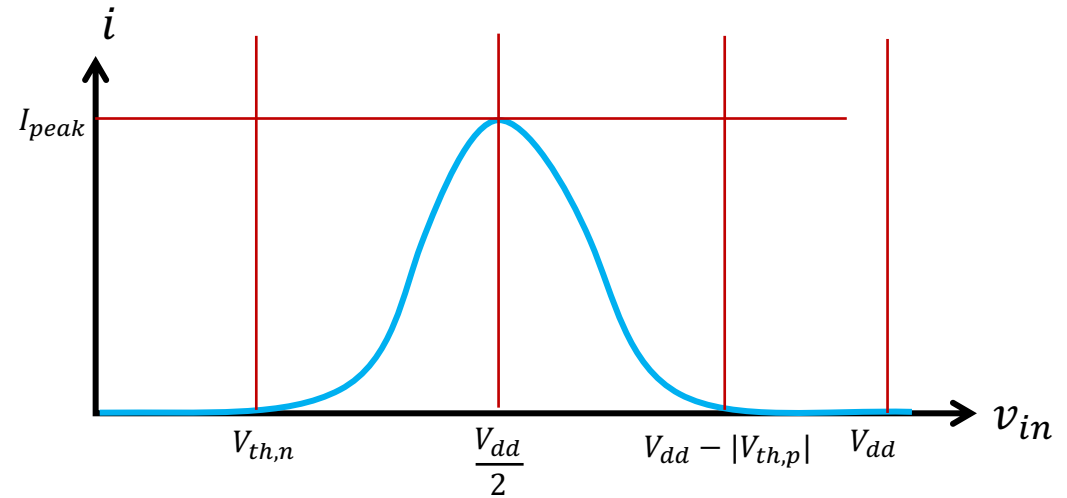
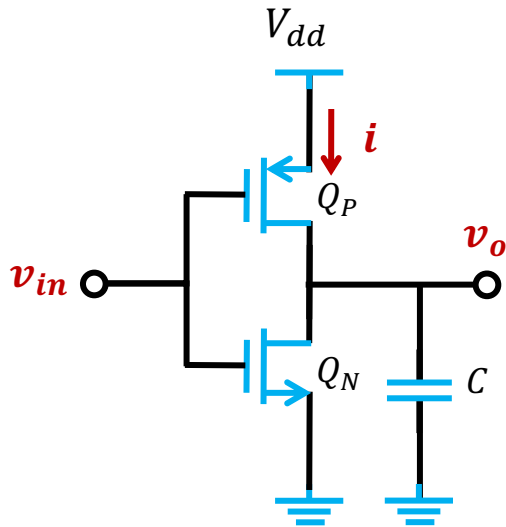
$$E_{dissipated} = CV_{dd}^2$$

- The dynamic power dissipation

$$P_{dyn} = fCV_{dd}^2$$

↓  
inverter switch frequency

# Power Consumption

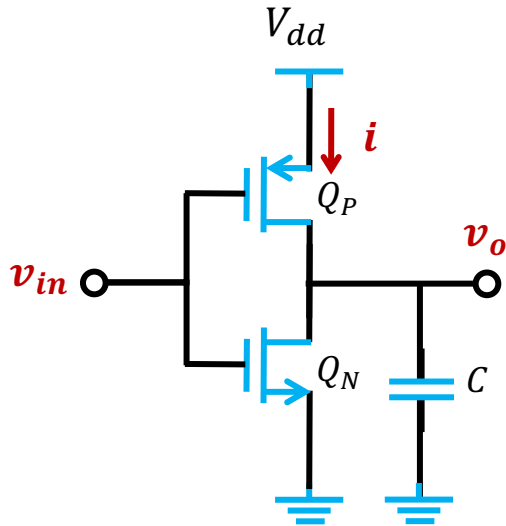


- @  $v_{in} = \frac{V_{dd}}{2}$  ➡ Saturation region

$$I_{peak} = \frac{1}{2} (\mu_n C_{ox}) \left(\frac{W}{L}\right)_n \left(\frac{V_{dd}}{2} - V_{th,n}\right)^2$$

Another source of dynamic power

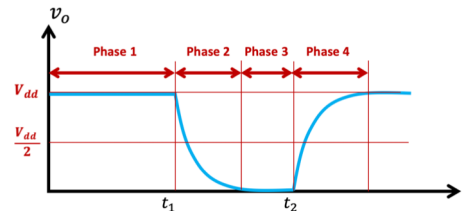
# Summary: Power Consumption



## ■ STATIC POWER

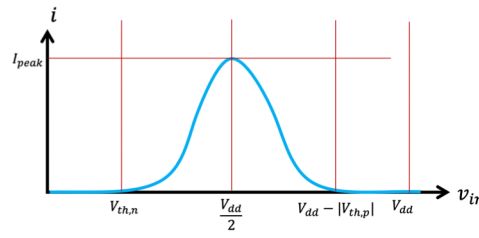
Negligible low ▶ Key advantage of CMOS circuits

## ■ DYNAMIC POWER



Source 1 – gate switching

$$P_{dyn} = fCV_{dd}^2$$



Source 2 – current through both transistors

$$I_{peak} = \frac{1}{2}k_n \left( \frac{V_{dd}}{2} - V_{th,n} \right)^2$$

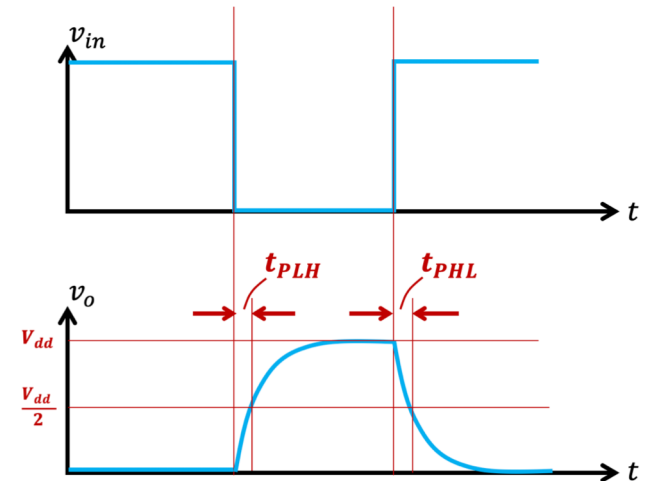
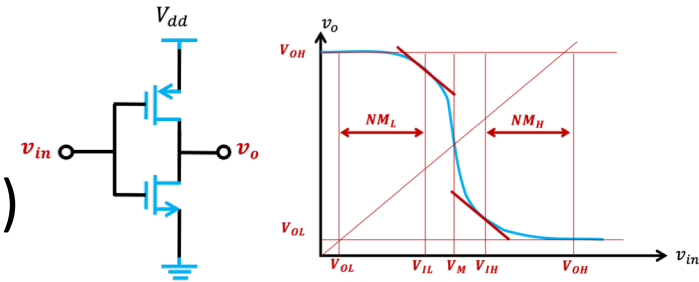


# Outline

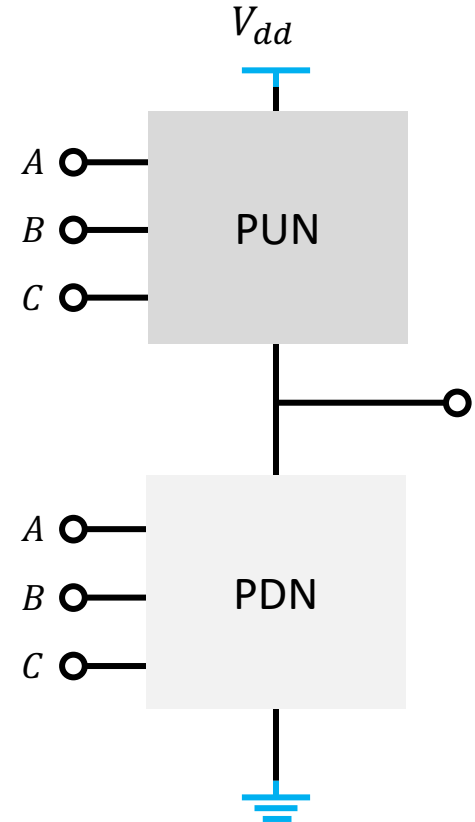
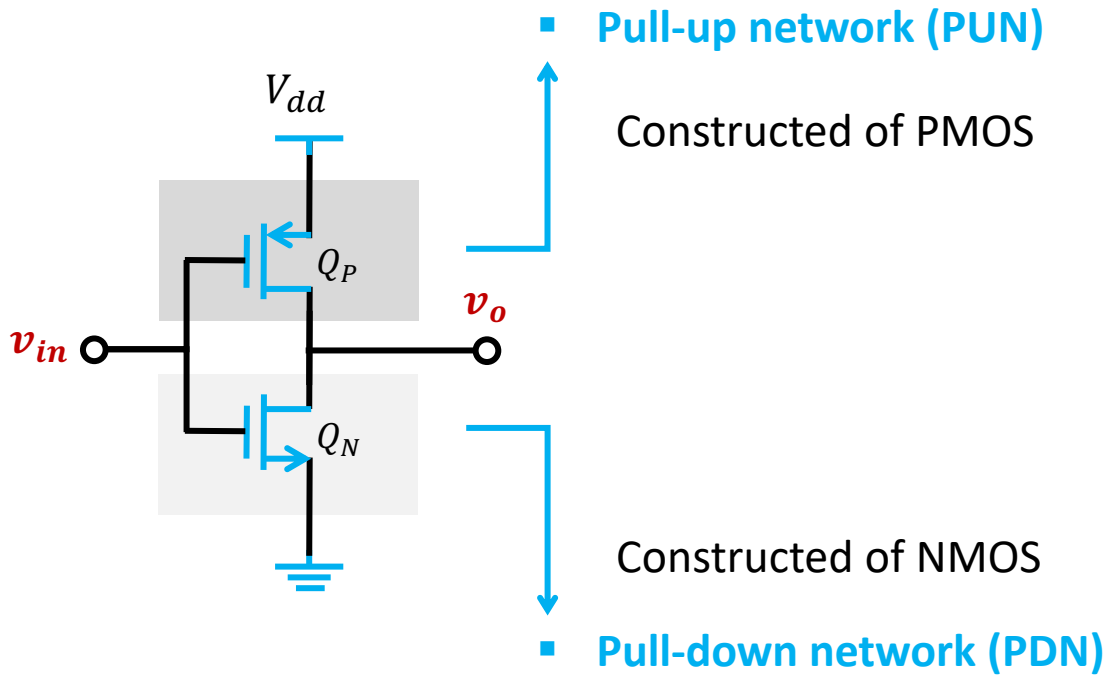
## ■ CMOS Inverters

- Voltage Transfer Characteristic (VTC)
- Noise margin
- Propagation delay
- Power consumption

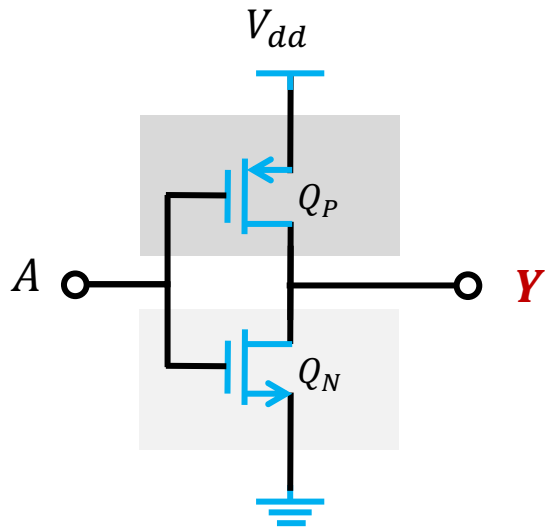
## ■ Logic-Gate Circuits



# CMOS Logic-Gate Circuits

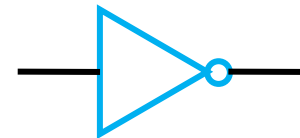


# An Example of CMOS NOT Logic



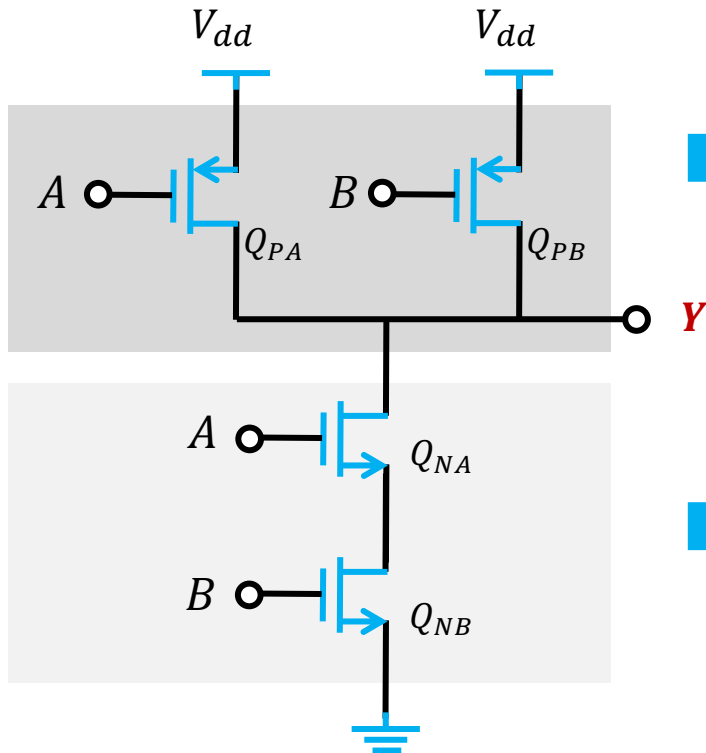
| $A$      | $Y$      |
|----------|----------|
| $V_{dd}$ | $GND$    |
| $GND$    | $V_{dd}$ |

$$Y = \bar{A}$$



# Example 1: NAND gate circuit

**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



- **Pull-up network (PUN)**

Constructed of all PMOS

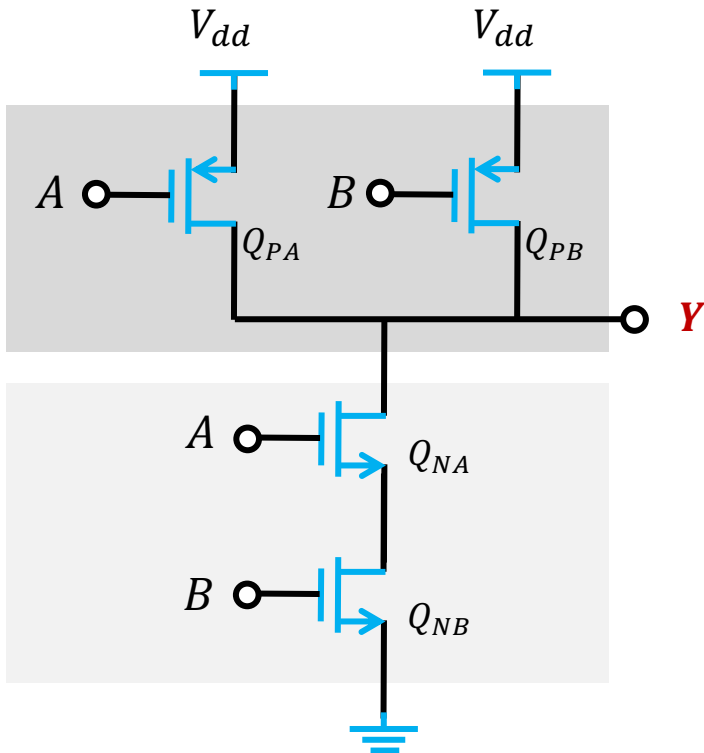


- **Pull-down network (PDN)**

Constructed of all NMOS

# Example 1: NAND gate circuit

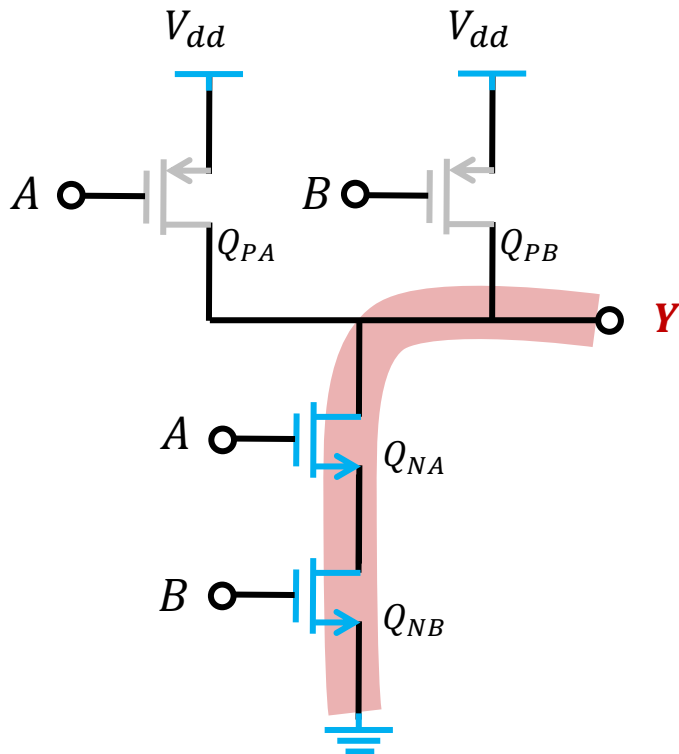
**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$ |
|----------|----------|-----|
| $V_{dd}$ | $V_{dd}$ |     |
| $V_{dd}$ | $GND$    |     |
| $GND$    | $V_{dd}$ |     |
| $GND$    | $GND$    |     |

# Example 1: NAND gate circuit

**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$

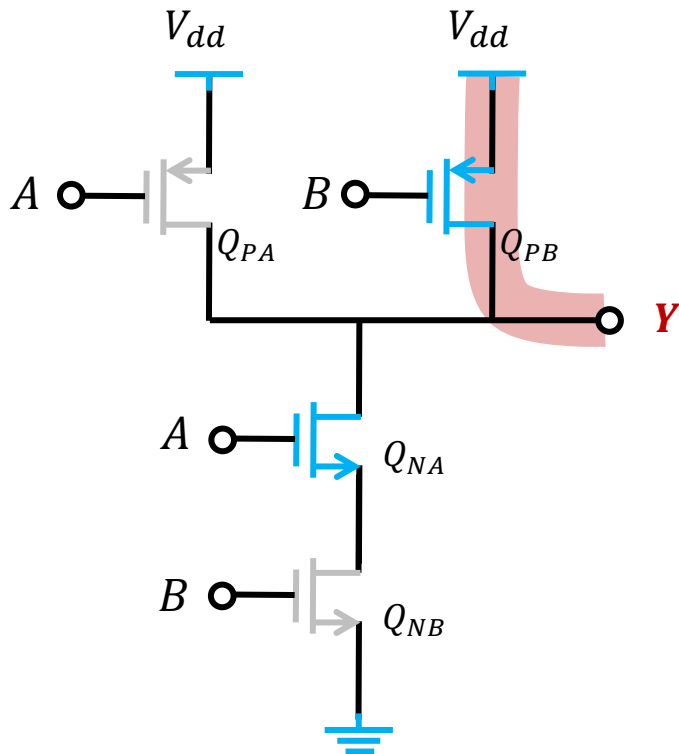


| $A$      | $B$      | $Y$   |
|----------|----------|-------|
| $V_{dd}$ | $V_{dd}$ | $GND$ |
| $V_{dd}$ | $GND$    |       |
| $GND$    | $V_{dd}$ |       |
| $GND$    | $GND$    |       |

- @  $A = V_{dd}, B = V_{dd}$   
 $Q_{PA}$  is off       $Q_{PB}$  is off  
 $Q_{NA}$  is on       $Q_{NB}$  is on

# Example 1: NAND gate circuit

**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$      |
|----------|----------|----------|
| $V_{dd}$ | $V_{dd}$ | $GND$    |
| $V_{dd}$ | $GND$    | $V_{dd}$ |
| $GND$    | $V_{dd}$ | $V_{dd}$ |
| $GND$    | $GND$    | $V_{dd}$ |

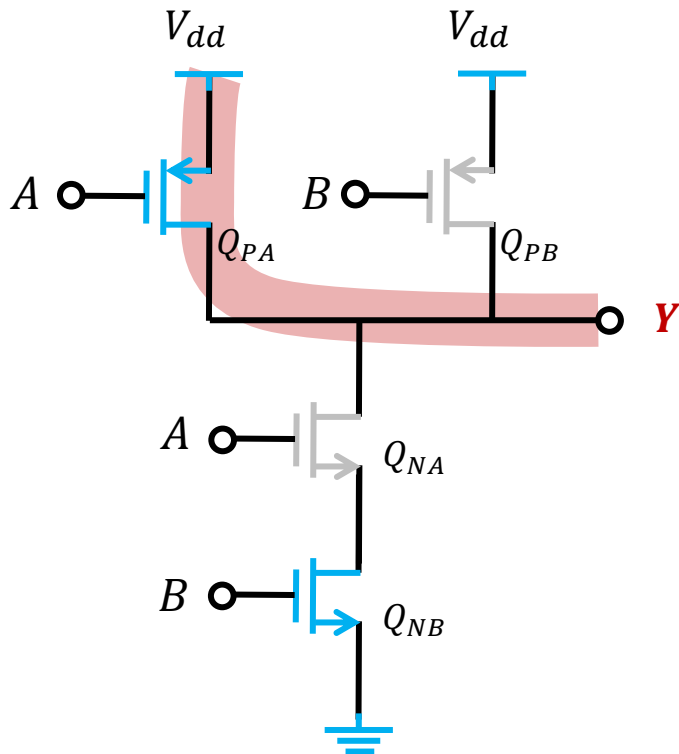
- @  $A = GND, B = V_{dd}$

$Q_{PA}$  is off       $Q_{PB}$  is on

$Q_{NA}$  is on       $Q_{NB}$  is off

# Example 1: NAND gate circuit

**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$      |
|----------|----------|----------|
| $V_{dd}$ | $V_{dd}$ | $GND$    |
| $V_{dd}$ | $GND$    | $V_{dd}$ |
| $GND$    | $V_{dd}$ | $V_{dd}$ |
| $GND$    | $GND$    |          |

- @  $A = V_{dd}, B = GND$

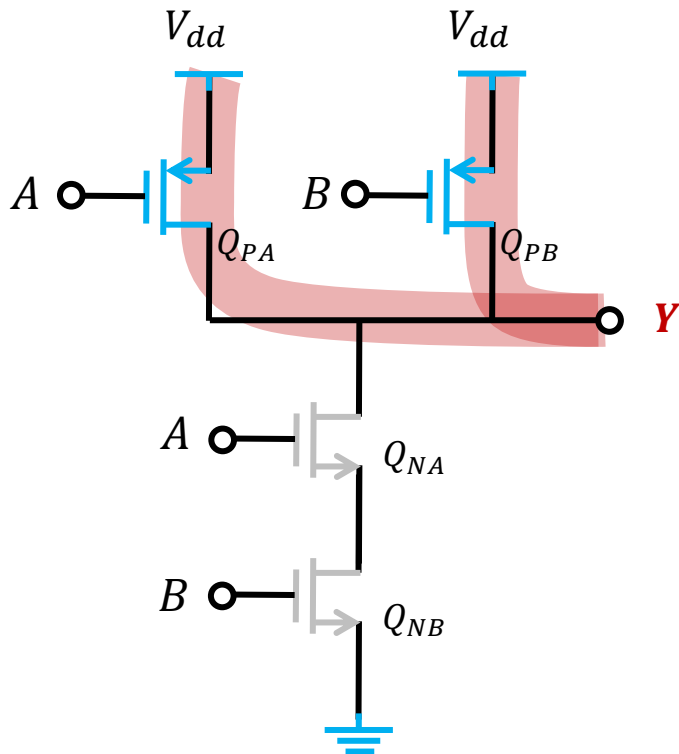
$Q_{PA}$  is on       $Q_{PB}$  is off

$Q_{NA}$  is off       $Q_{NB}$  is on



# Example 1: NAND gate circuit

**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$      |
|----------|----------|----------|
| $V_{dd}$ | $V_{dd}$ | $GND$    |
| $V_{dd}$ | $GND$    | $V_{dd}$ |
| $GND$    | $V_{dd}$ | $V_{dd}$ |
| $GND$    | $GND$    | $V_{dd}$ |

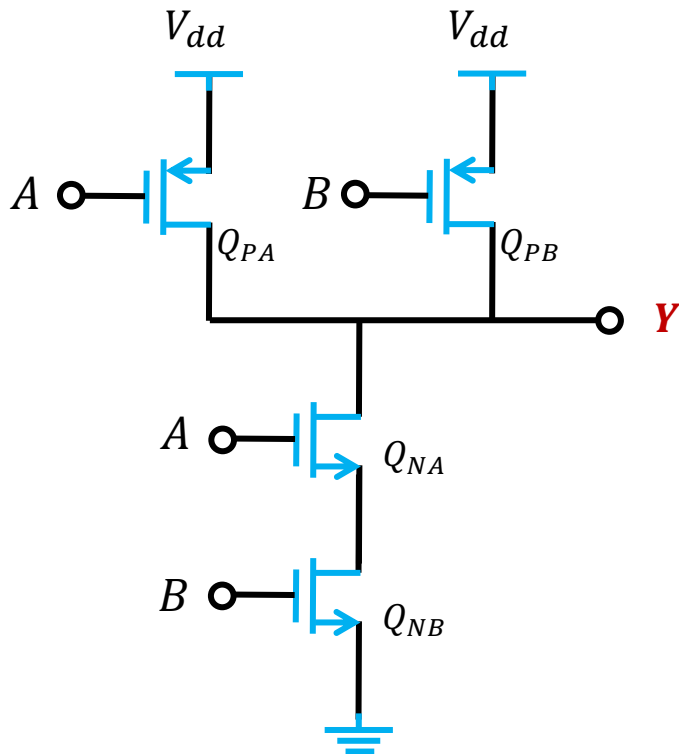
- @  $A = V_{dd}, B = V_{dd}$

$Q_{PA}$  is on       $Q_{PB}$  is off

$Q_{NA}$  is off       $Q_{NB}$  is on

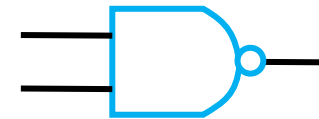
# Example 1: NAND gate circuit

**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$

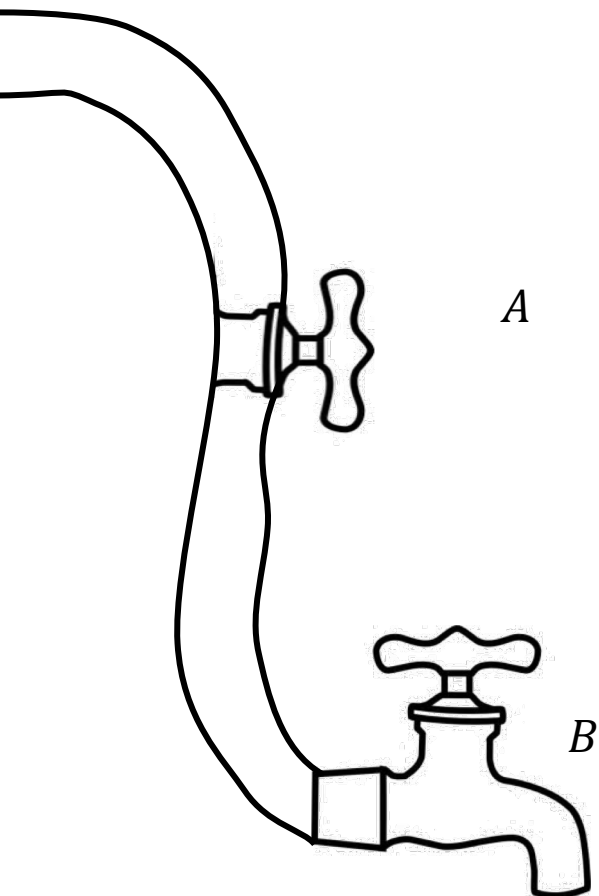


| $A$      | $B$      | $Y$      |
|----------|----------|----------|
| $V_{dd}$ | $V_{dd}$ | $GND$    |
| $V_{dd}$ | $GND$    | $V_{dd}$ |
| $GND$    | $V_{dd}$ | $V_{dd}$ |
| $GND$    | $GND$    | $V_{dd}$ |

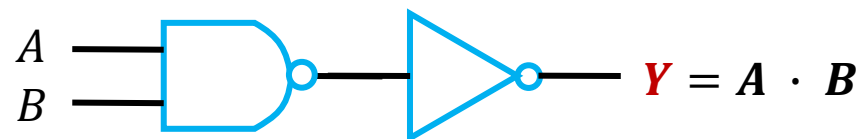
$$Y = \overline{A \cdot B}$$



# An Example of AND Logic

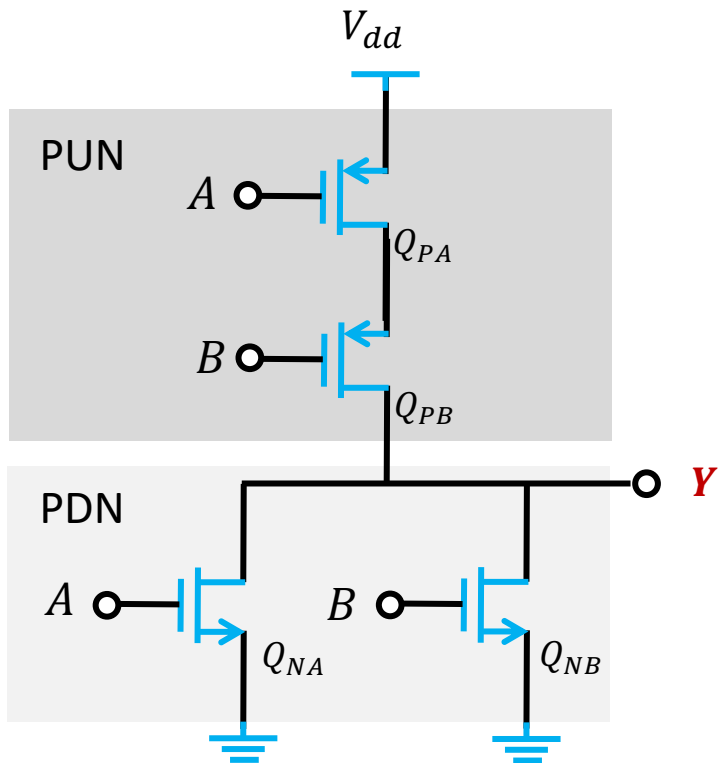


| <i>A</i> | <i>B</i> | <i>Y</i>         |
|----------|----------|------------------|
| On       | On       | <b>Water out</b> |
| On       | Off      | <b>No water</b>  |
| Off      | On       | <b>No water</b>  |
| Off      | Off      | <b>No water</b>  |



# Example 2: NOR gate circuit

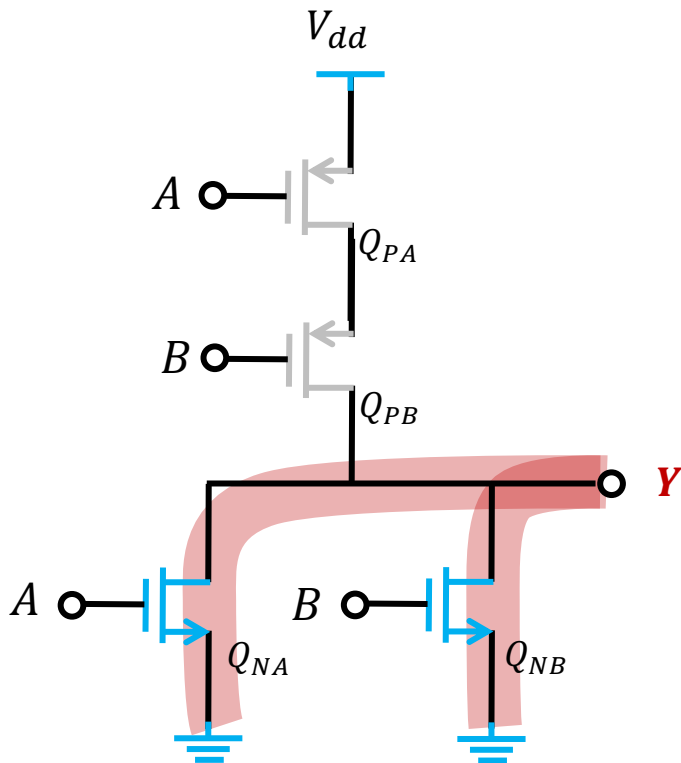
**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$ |
|----------|----------|-----|
| $V_{dd}$ | $V_{dd}$ |     |
| $V_{dd}$ | $GND$    |     |
| $GND$    | $V_{dd}$ |     |
| $GND$    | $GND$    |     |

# Example 2: NOR gate circuit

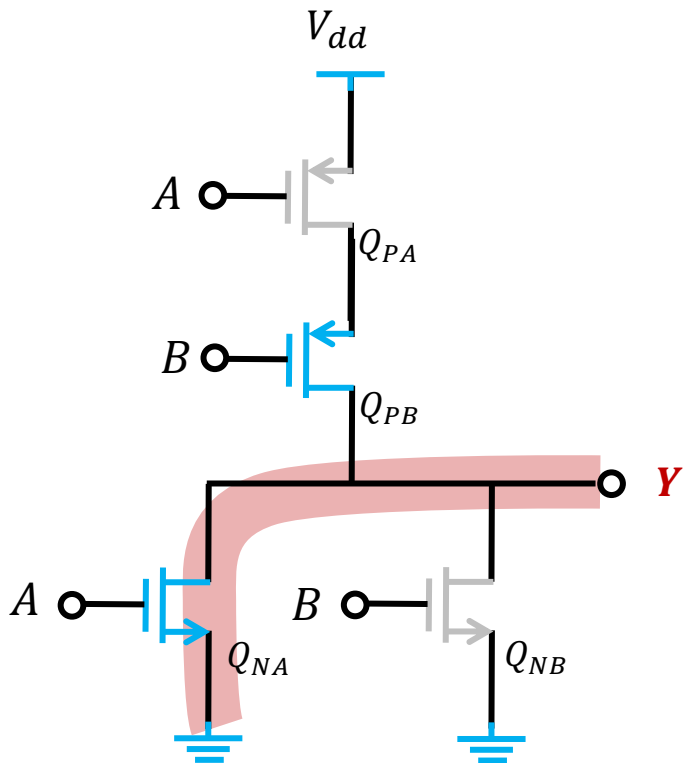
**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$   |
|----------|----------|-------|
| $V_{dd}$ | $V_{dd}$ | $GND$ |
| $V_{dd}$ | $GND$    |       |
| $GND$    | $V_{dd}$ |       |
| $GND$    | $GND$    |       |

# Example 2: NOR gate circuit

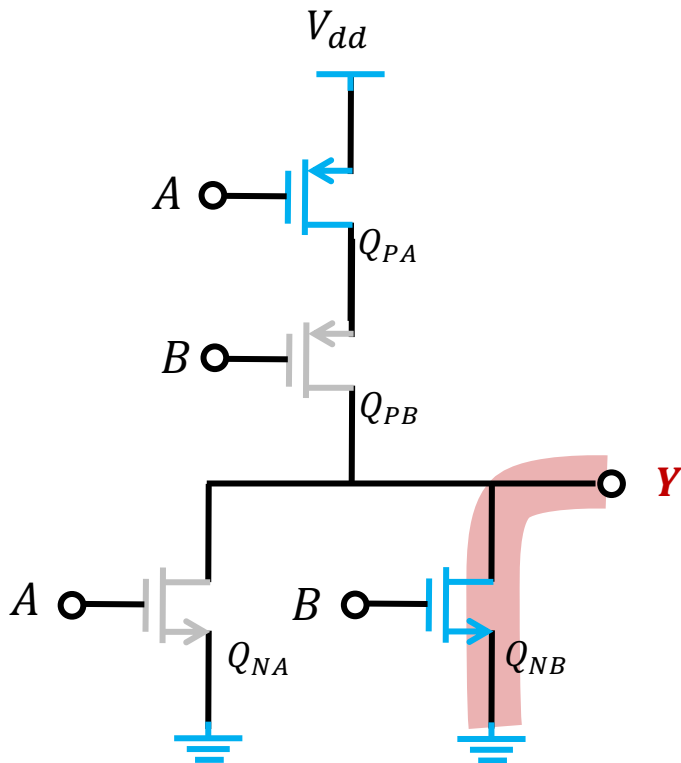
**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$      |
|----------|----------|----------|
| $V_{dd}$ | $V_{dd}$ | $GND$    |
| $V_{dd}$ | $GND$    | $GND$    |
| $GND$    | $V_{dd}$ | $GND$    |
| $GND$    | $GND$    | $V_{dd}$ |

# Example 2: NOR gate circuit

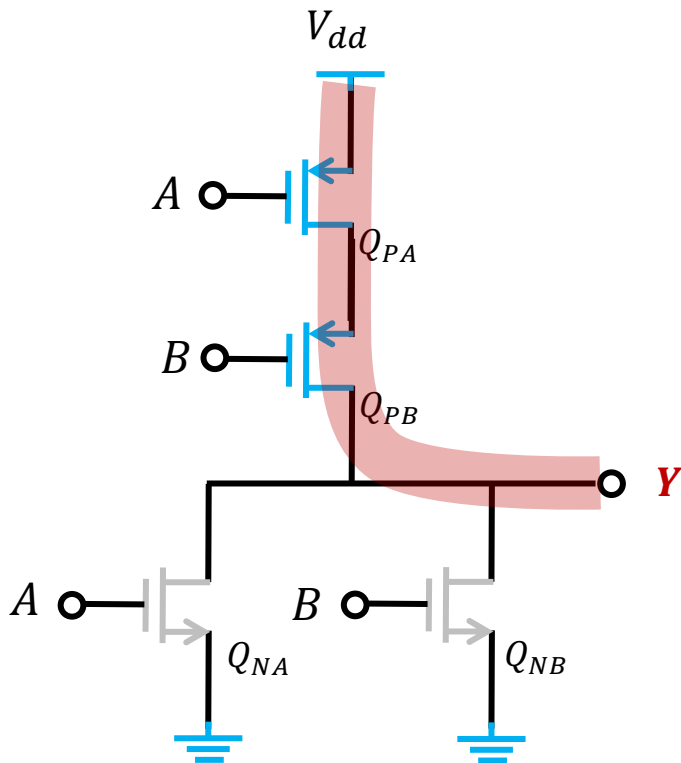
**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$   |
|----------|----------|-------|
| $V_{dd}$ | $V_{dd}$ | $GND$ |
| $V_{dd}$ | $GND$    | $GND$ |
| $GND$    | $V_{dd}$ | $GND$ |
| $GND$    | $GND$    |       |

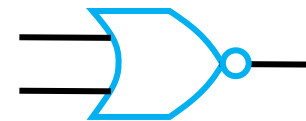
# Example 2: NOR gate circuit

**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



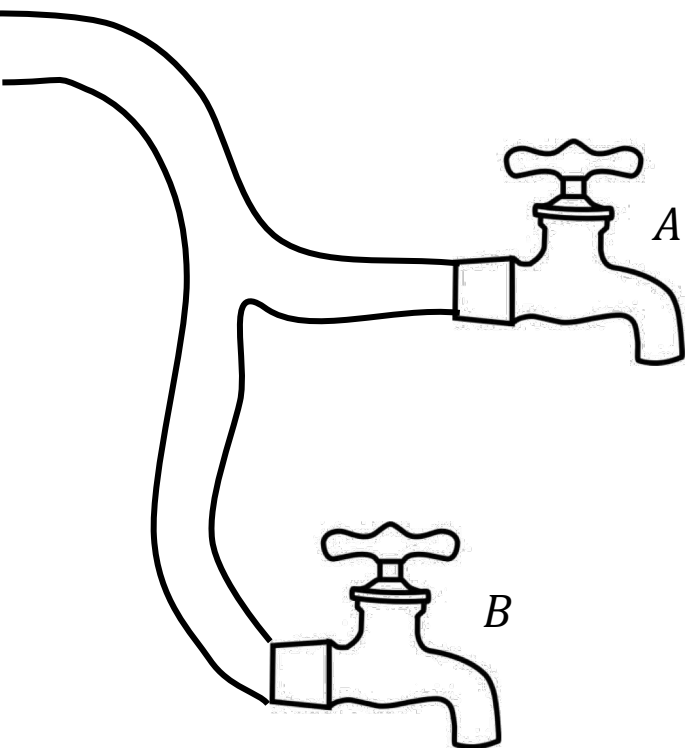
| $A$      | $B$      | $Y$      |
|----------|----------|----------|
| $V_{dd}$ | $V_{dd}$ | $GND$    |
| $V_{dd}$ | $GND$    | $GND$    |
| $GND$    | $V_{dd}$ | $GND$    |
| $GND$    | $GND$    | $V_{dd}$ |

$$Y = \overline{A + B}$$

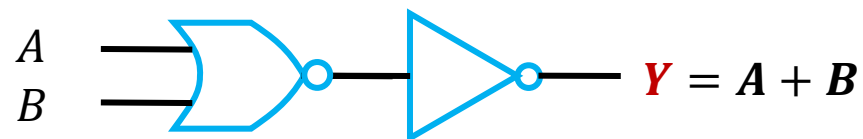




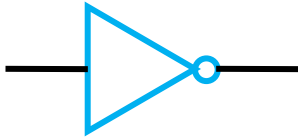
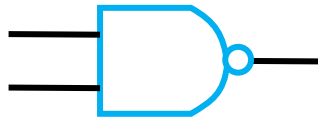
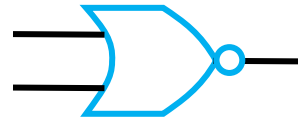
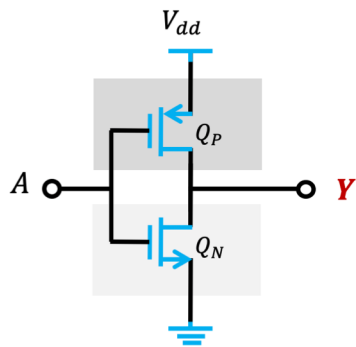
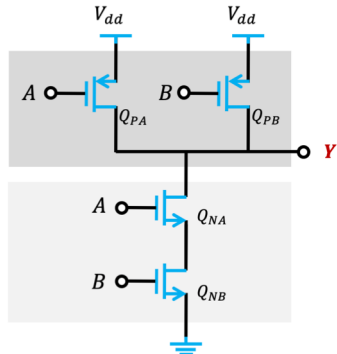
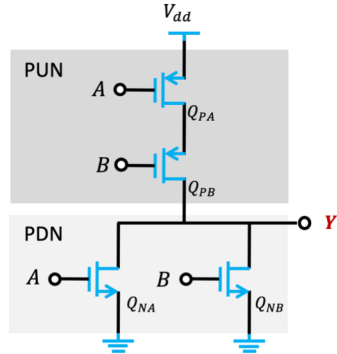
# An Example of OR Logic



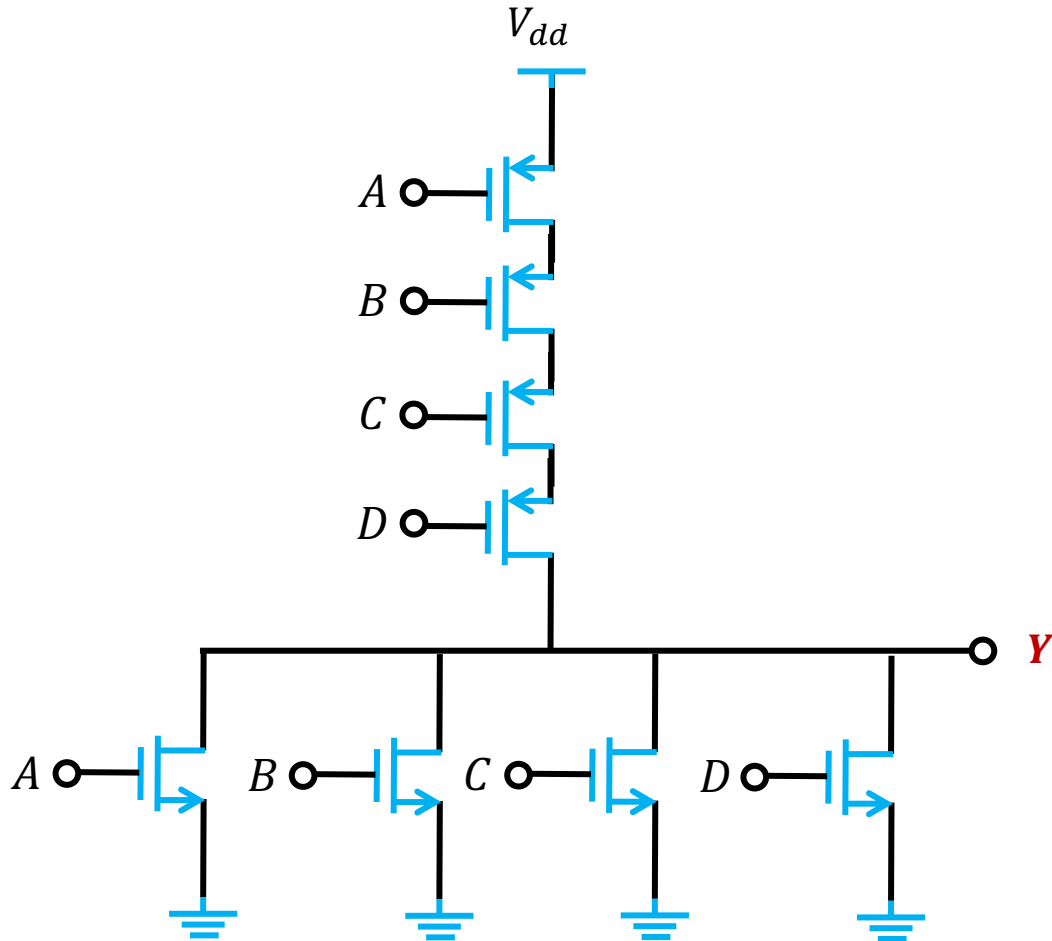
| <i>A</i> | <i>B</i> | <i>Y</i>         |
|----------|----------|------------------|
| On       | On       | <b>Water out</b> |
| On       | Off      | <b>Water out</b> |
| Off      | On       | <b>Water out</b> |
| Off      | Off      | <b>No water</b>  |



# Summary: CMOS Logic-Gate Circuits

|               | NOT Logic Gate   | NAND Logic Gate   | NOR Logic Gate   |
|---------------|--|---|--|
| Symbol        |   |   |   |
| Logic         | $Y = \bar{A}$  | $Y = \overline{A \cdot B}$  | $Y = \overline{A + B}$   |
| CMOS circuits |  |  |  |

# Fan-In & Fan-Out

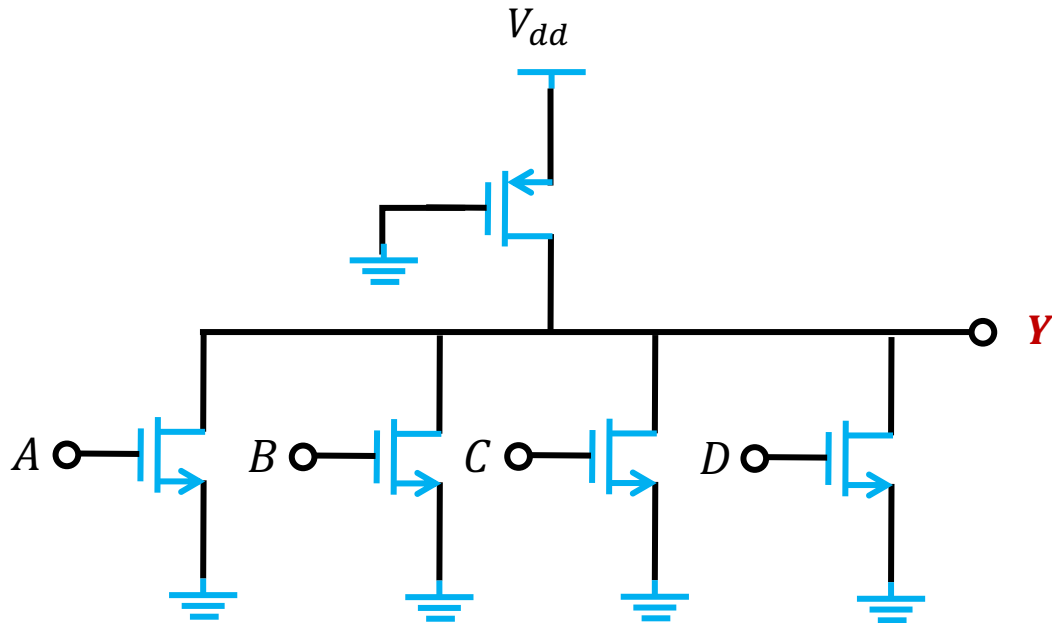


A 4-input NOR Gate

$$Y = \overline{A + B + C + D}$$

- **2** transistors required for **1** additional input
- An increasing of **silicon area**
- An increasing of the **capacitance**

# Pseudo-NMOS Circuits



A 4-input NOR Gate

$$Y = \overline{A + B + C + D}$$

## PROS

- 1 transistor for 1 additional input

## CONS

- Low logic swing
- Low noise margin
- High static power consumption

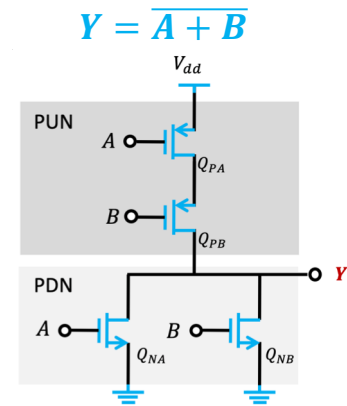
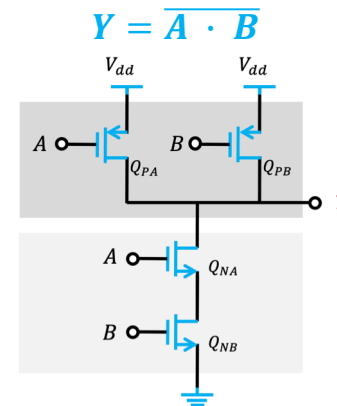
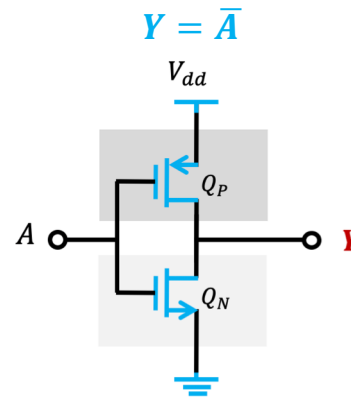
# Outline

## ■ CMOS Inverters

- Voltage Transfer Characteristic (VTC)
- Noise margin
- Propagation delay
- Power consumption

## ■ Logic-Gate Circuits

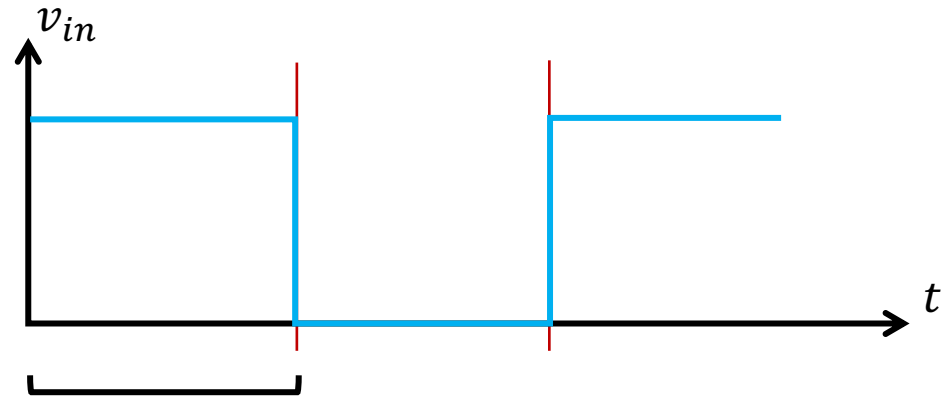
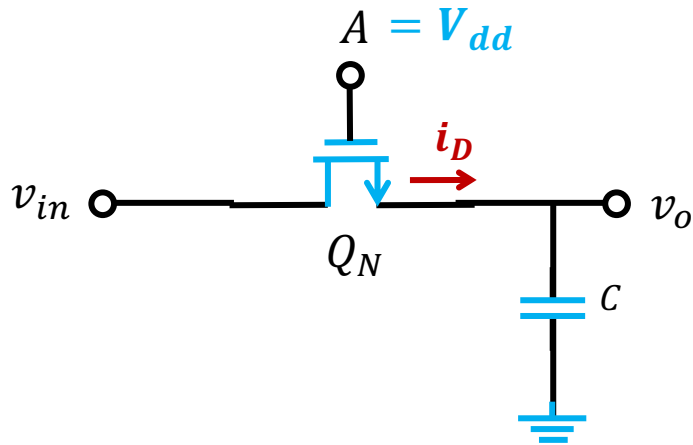
## ■ Digital Switches & Dynamic Logic Circuits



# Outline

- CMOS Inverters
- Logic-Gate Circuits
- Digital Switches & Dynamic Logic Circuits
  - **Single NMOS switch**

# Single NMOS Switch

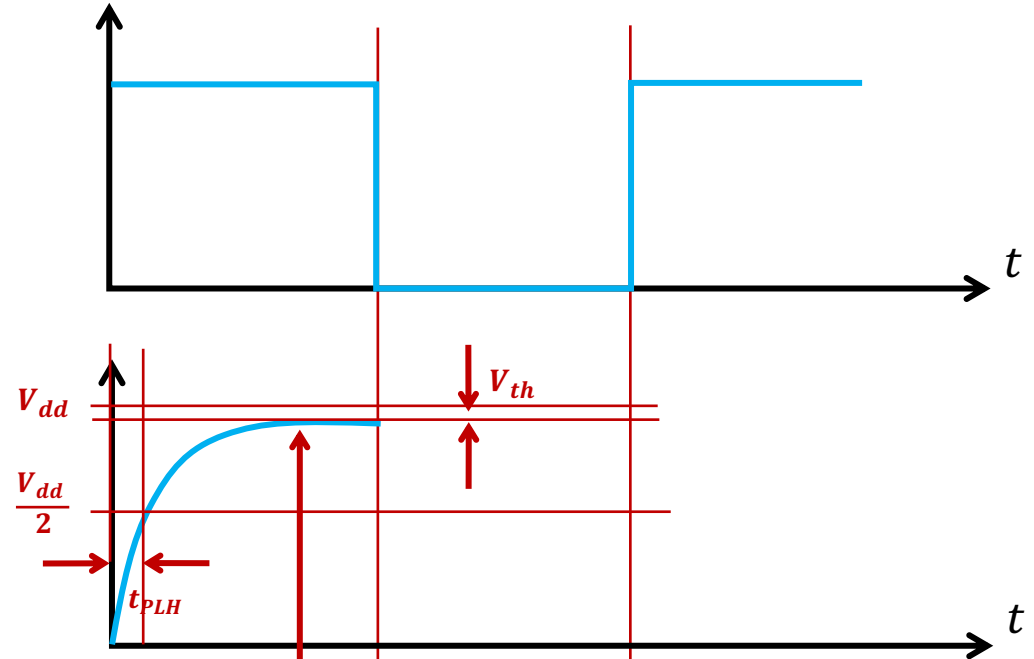
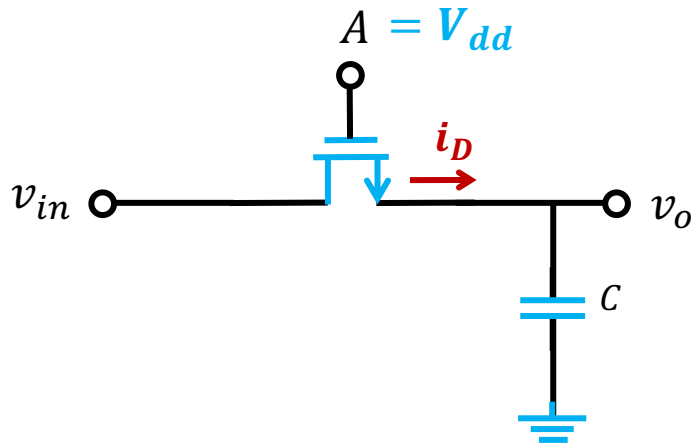


For  $Q_N$ ,  $v_{GS,N} - v_{DS,N} = 0 < V_{th,N}$

Assume  $v_{GS,N} > V_{th,N}$

$$i_{DN} = \frac{1}{2} k_n (V_{dd} - v_o - V_{th,N})^2$$

# Single NMOS Switch



For  $Q_N$ ,  $v_{GS,N} - v_{DS,N} = 0 < V_{th,N}$

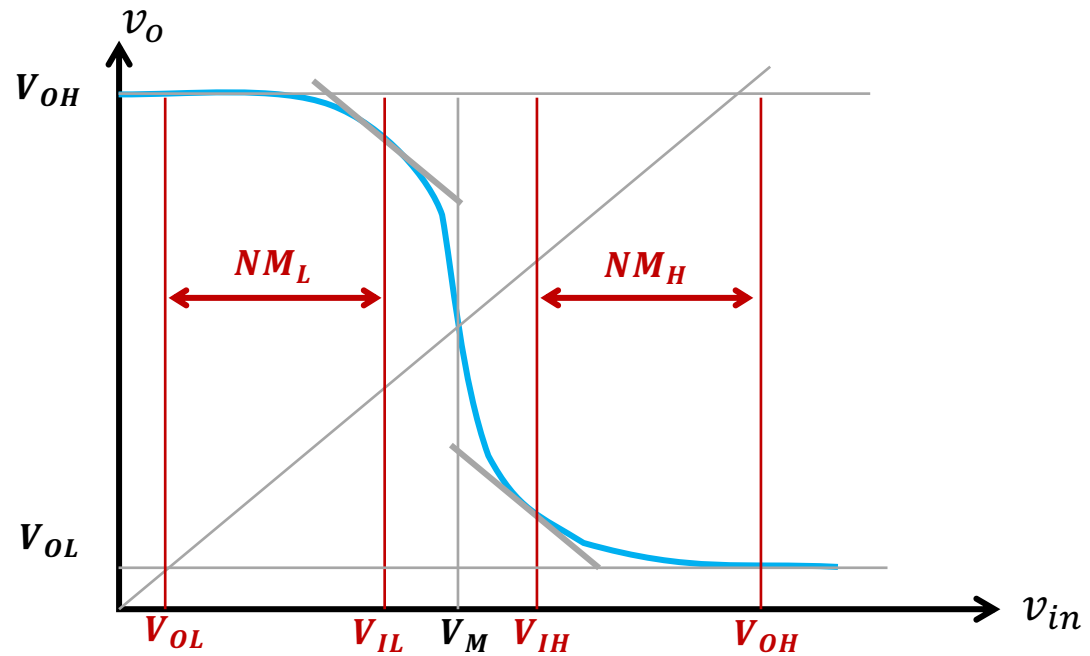
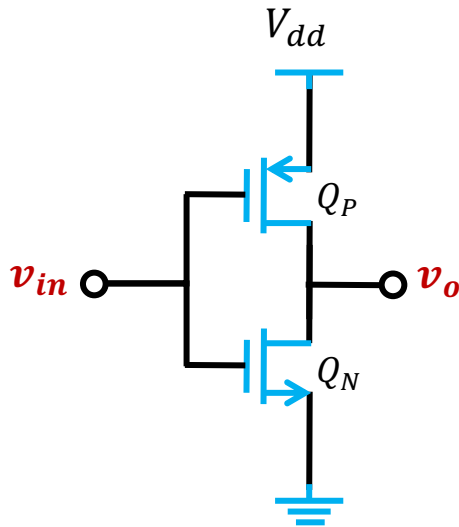
Assume  $v_{GS,N} > V_{th,N}$

$$i_{DN} = \frac{1}{2} k_n (V_{dd} - v_o - V_{th,N})^2$$

TRUE if  $v_o < V_{dd} - V_{th,N}$



# Recall: Noise Margin

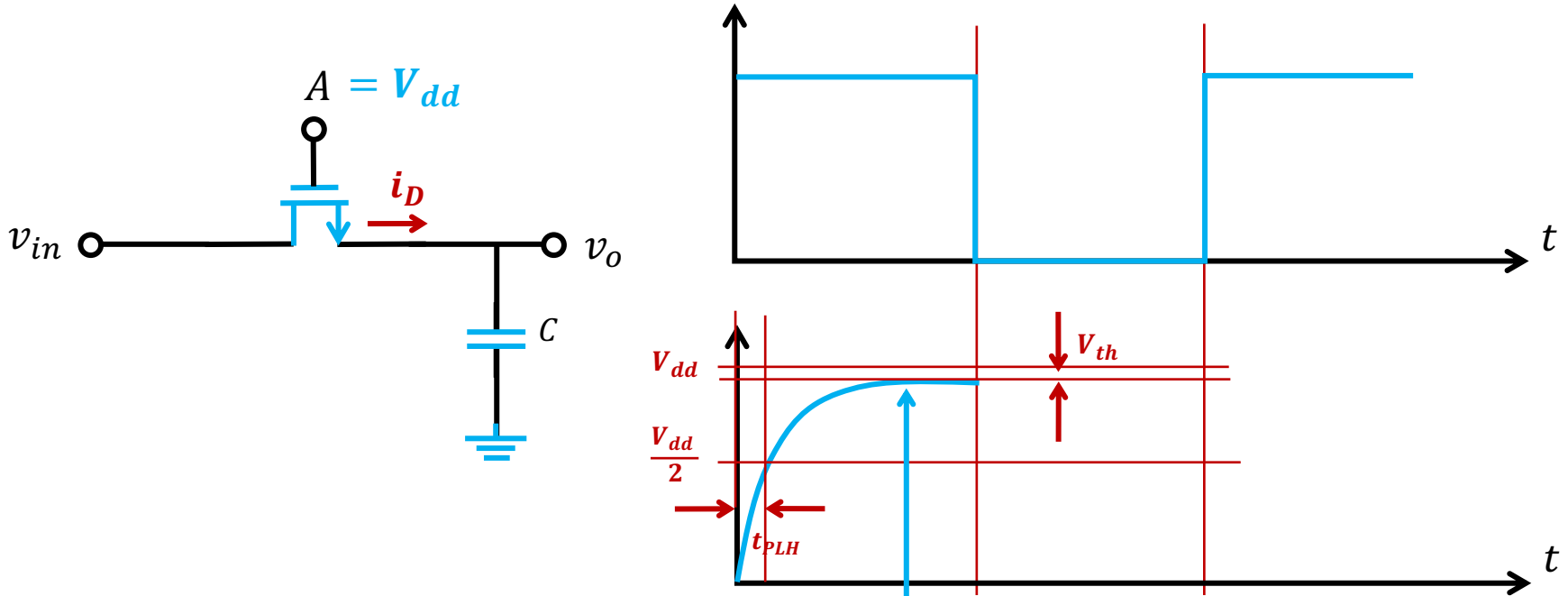


$$\begin{cases} V_{IH} = \frac{5V_{dd} - 2V_{th}}{8} \\ V_{IL} = \frac{3V_{dd} + 2V_{th}}{8} \end{cases}$$

$$NM_L = V_{IL} - \frac{V_{OL}}{0} = \frac{3V_{dd} + 2V_{th}}{8}$$

$$NM_H = \frac{V_{OH}}{V_{dd}} - V_{IH} = \frac{3V_{dd} + 2V_{th}}{8}$$

# Single NMOS Switch



For  $Q_N$ ,  $v_{GS,N} - v_{DS,N} = 0 < V_{th}$

Assume  $v_{GS,N} > V_{th}$

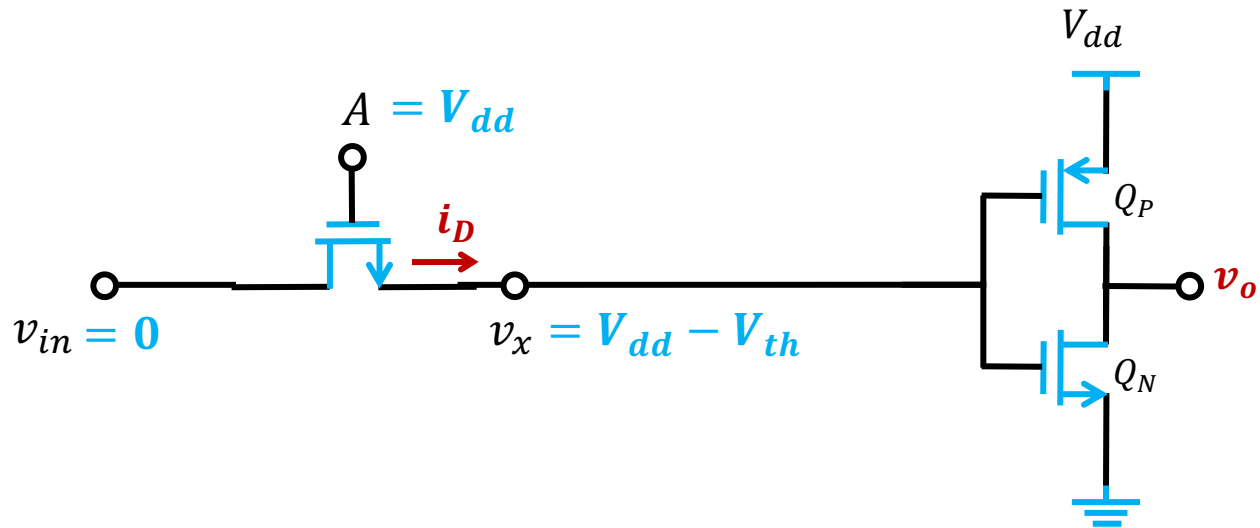
$$i_{DN} = \frac{1}{2} k_n (V_{dd} - v_o - V_{th})^2$$

TRUE if  $v_o < V_{dd} - V_{th}$

$V_{OH}$  is only  $V_{dd} - V_{th}$  instead of  $V_{dd}$

☹ Noise margin performance

# Single NMOS Switch

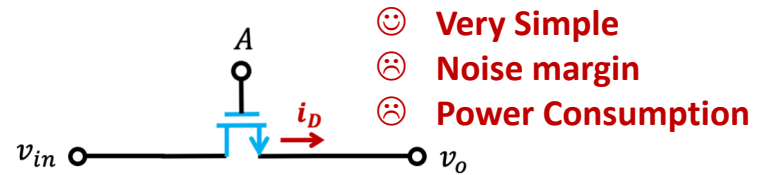


$Q_P$  is ON since  $|v_{GS,P}| = V_{th,P}$  ➡ Unexpected static power

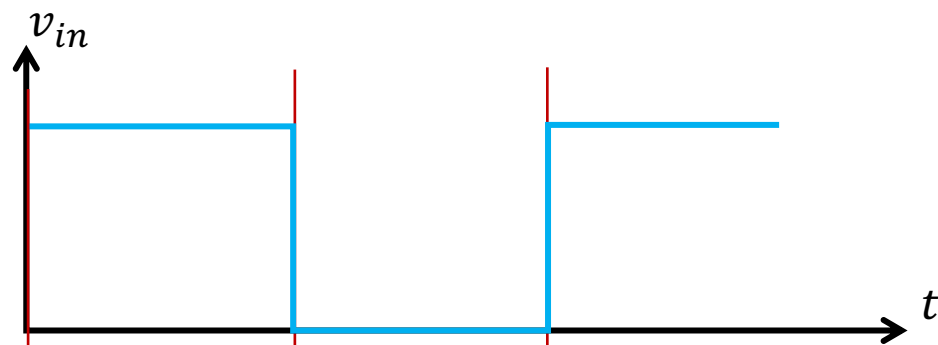
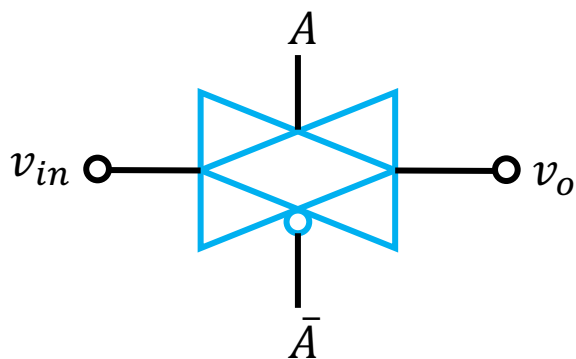
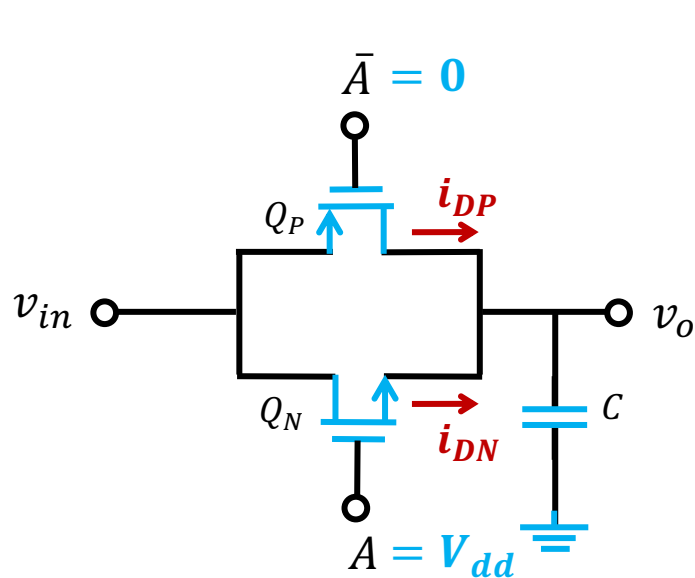
☹ **Static power consumption performance**

# Outline

- CMOS Inverters
- Logic-Gate Circuits
- Digital Switches & Dynamic Logic Circuits
  - Single NMOS switch
  - **Transmission Gate Switch**



# Transmission Gate Switch



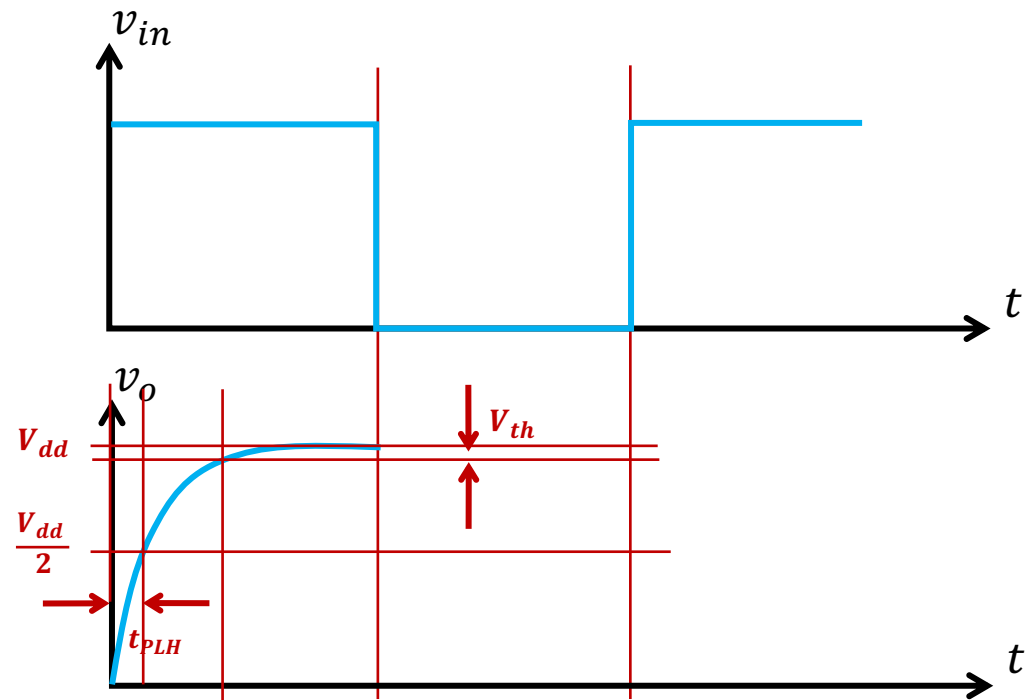
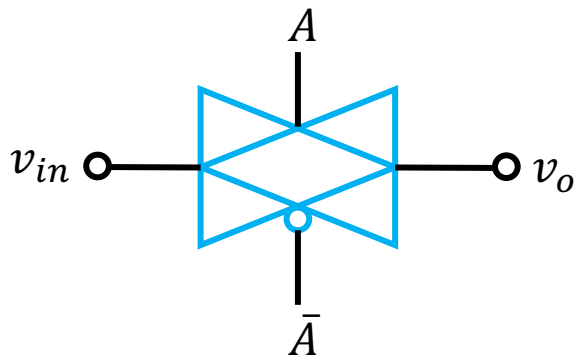
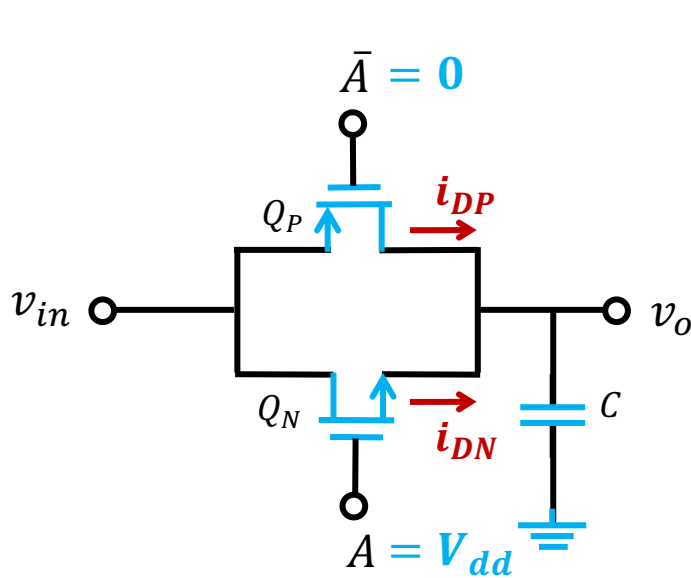
For  $Q_N$ ,  $v_{GS,N} - v_{DS,N} = 0 < V_{th,N}$

Assume  $v_{GS,N} > V_{th,N}$

$Q_N$  is biased in saturation region

$$i_{DN} = \frac{1}{2} k_n (V_{dd} - v_o - V_{th,N})^2$$

# Transmission Gate Switch



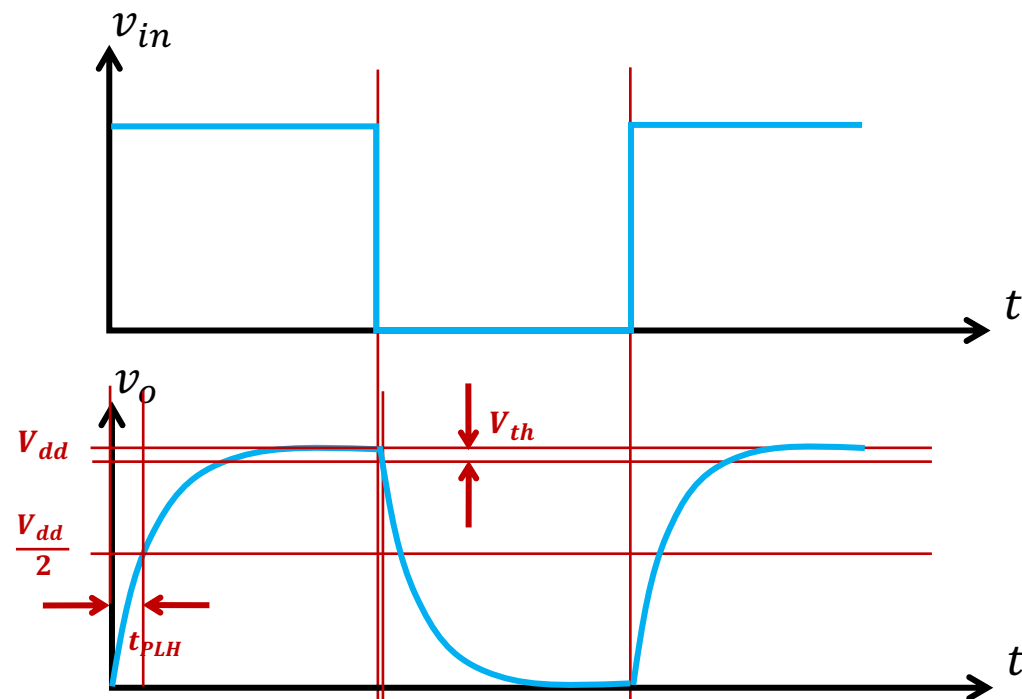
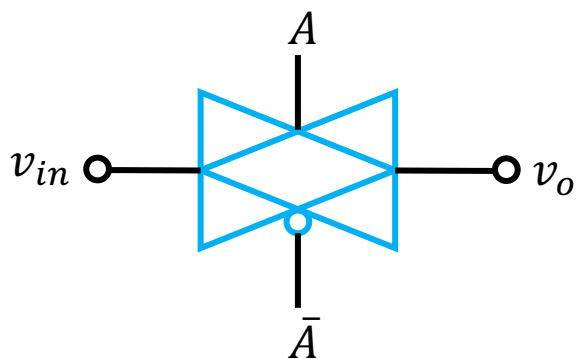
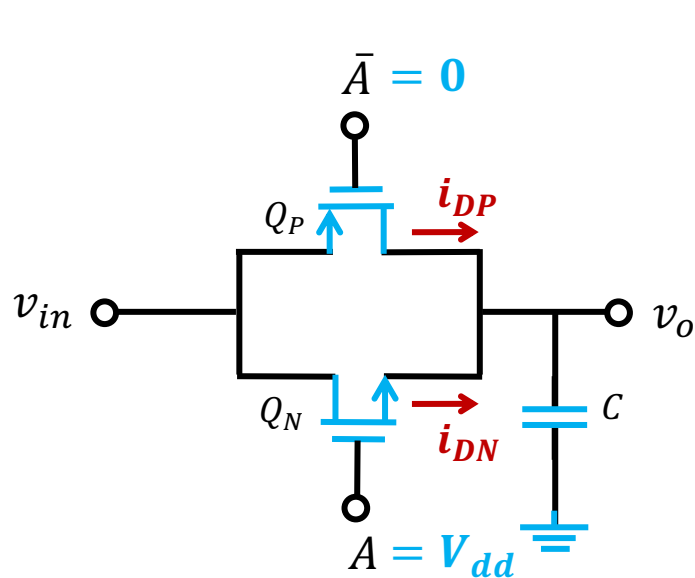
When  $v_o = V_{dd} - V_{th,N}$

$i_{DN} = 0$

$Q_P$  is ON

$i_{DP}$  charges  $C$  to  $V_{dd}$

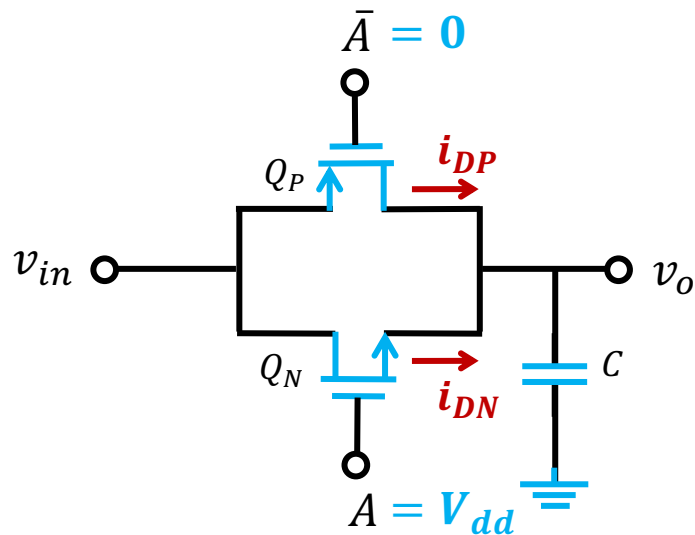
# Transmission Gate Switch



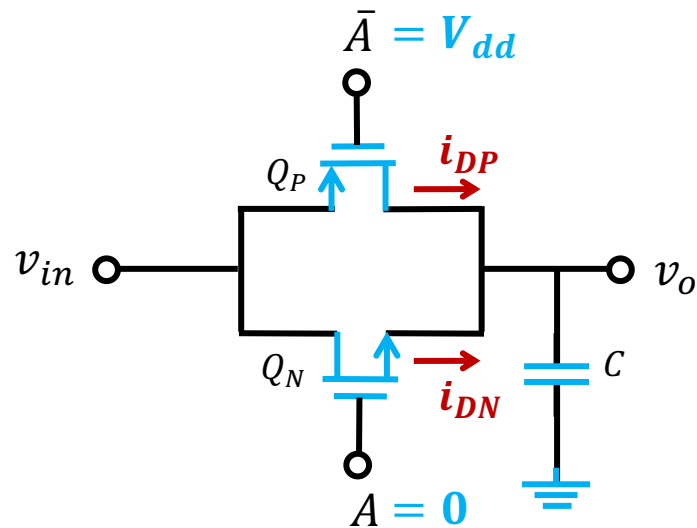
$Q_P$  is ON

$i_{DP}$  discharges  $C$  to 0

# Transmission Gate Switch



$$v_{out} = v_{in}$$

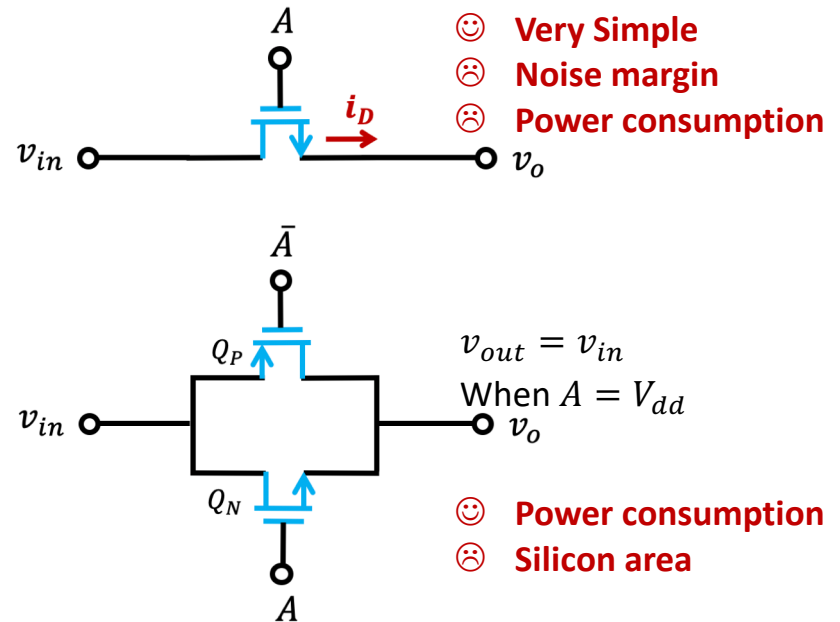


Both  $Q_N$  and  $Q_P$  are turned off



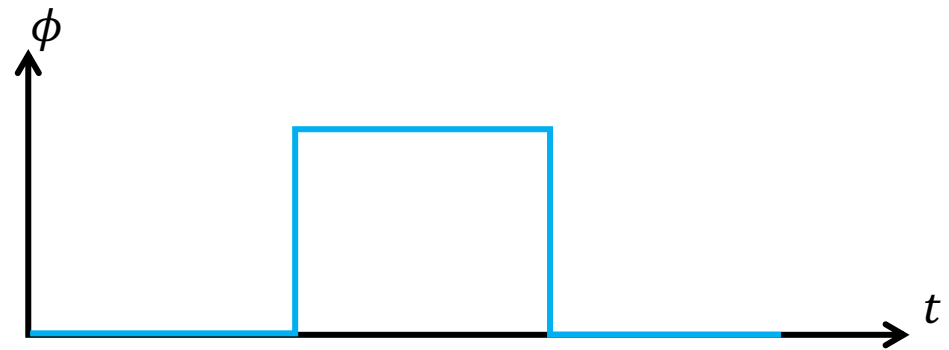
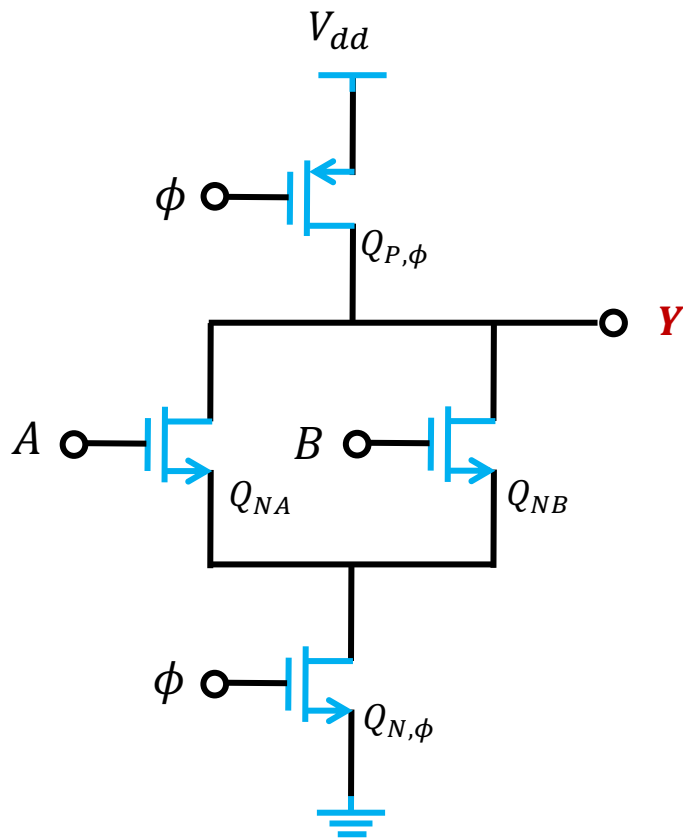
# Outline

- CMOS Inverters
- Logic-Gate Circuits
- Digital Switches & Dynamic Logic Circuits
  - Single NMOS switch
  - Transmission Gate Switch
  - **Dynamic logic circuits**



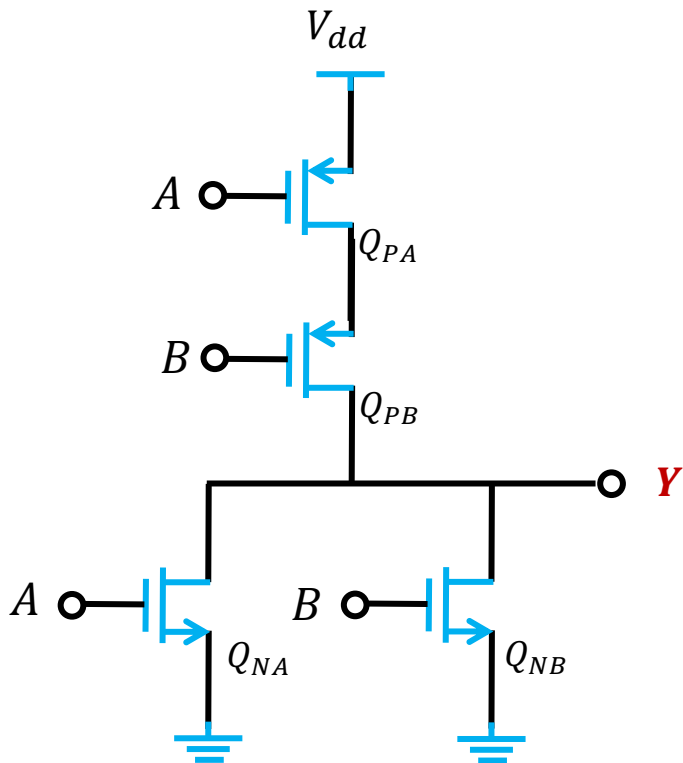
# Example 3: Dynamic MOS Logic

**QUESTION:** Find out the output  $Y$  with different combination of the inputs.  $\phi$  is a clock signal. The inputs switch between  $V_{dd}$  and  $GND$



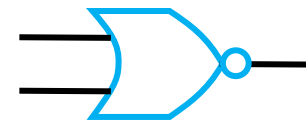
# Recall: NOR gate circuit

**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



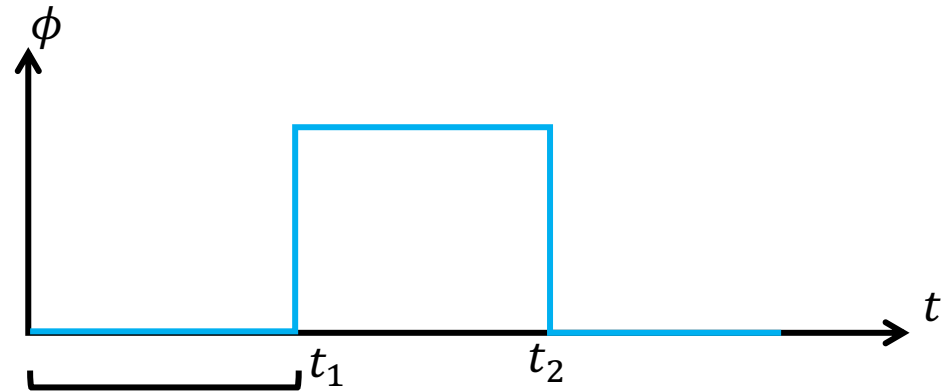
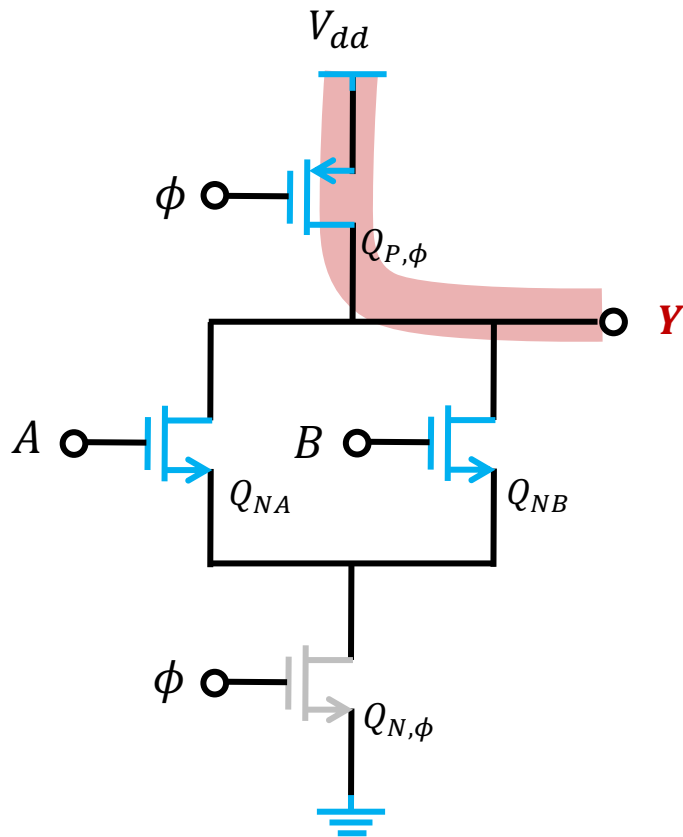
| $A$      | $B$      | $Y$      |
|----------|----------|----------|
| $V_{dd}$ | $V_{dd}$ | $GND$    |
| $V_{dd}$ | $GND$    | $GND$    |
| $GND$    | $V_{dd}$ | $GND$    |
| $GND$    | $GND$    | $V_{dd}$ |

$$Y = \overline{A + B}$$



# Example 3: Dynamic MOS Logic

**QUESTION:** Find out the output  $Y$  with different combination of the inputs.  $\phi$  is a clock signal. The inputs switch between  $V_{dd}$  and  $GND$



$Q_{P,\phi}$  is ON since  $|v_{GS,P}| = V_{dd} > V_{th,P}$

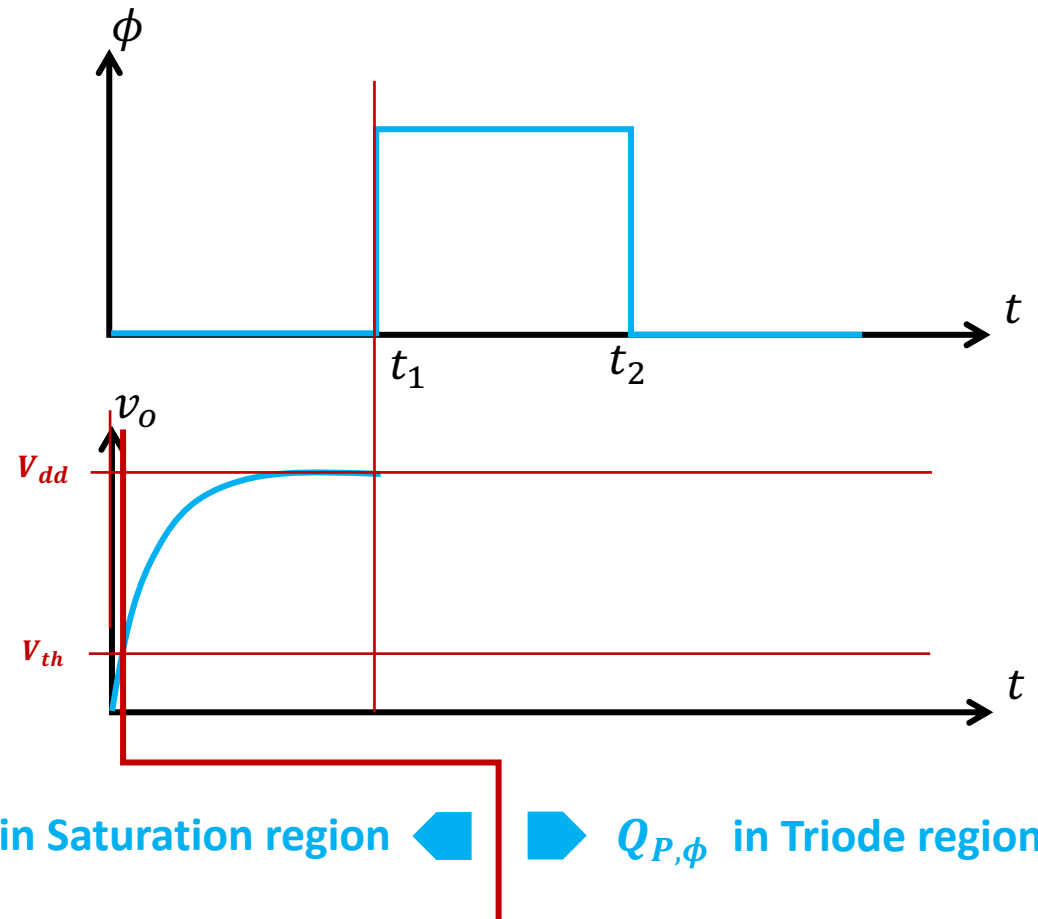
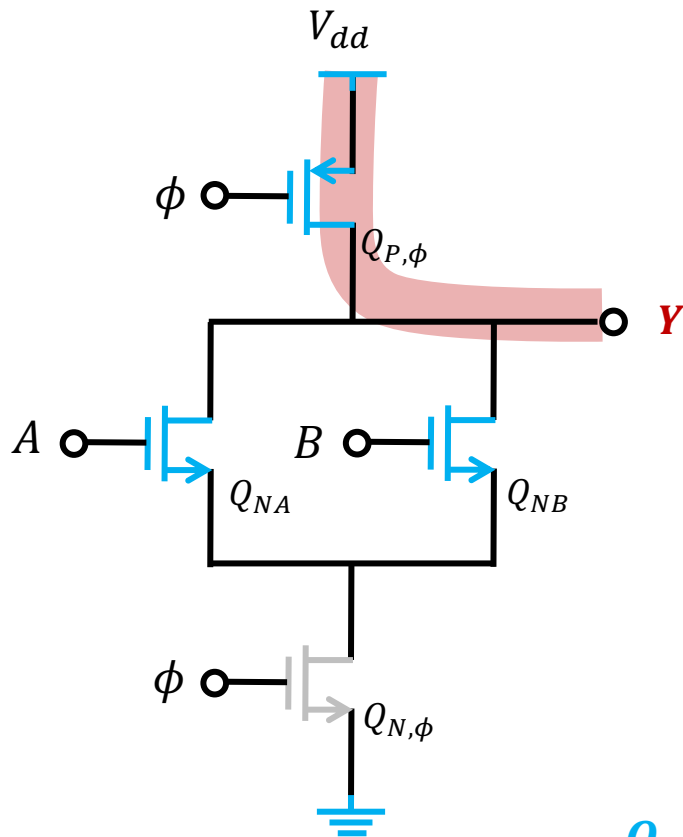
If  $Y = 0$  @  $t = 0$

$|v_{DS,P}| > |v_{GS,P}| - V_{th}$  ▶ Saturation

$$i_D = \frac{1}{2} k_p (|v_{GS,P}| - V_{th,P})^2$$

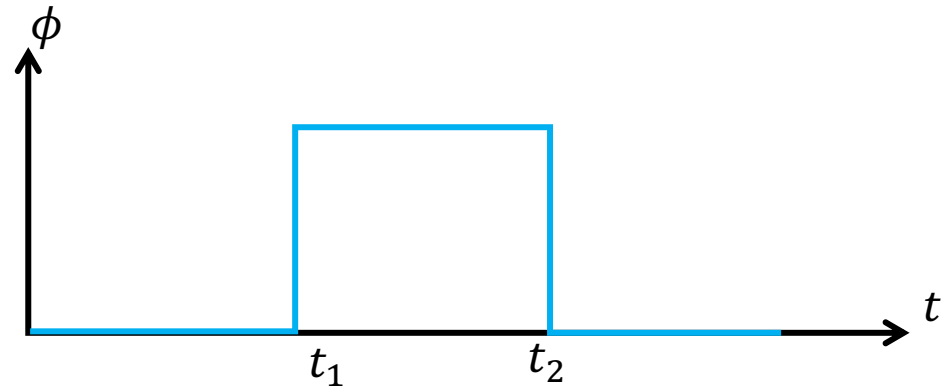
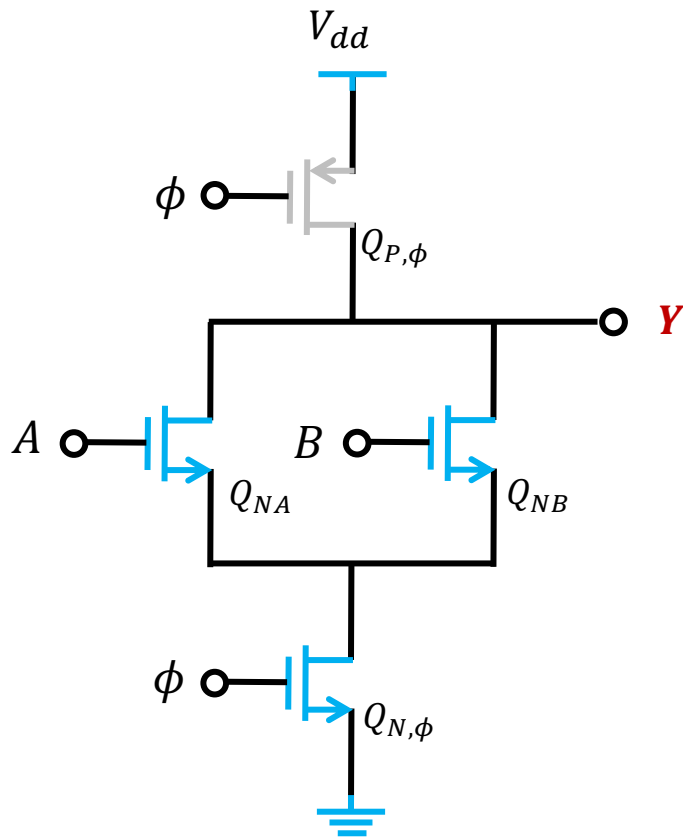
# Example 3: Dynamic MOS Logic

**QUESTION:** Find out the output  $Y$  with different combination of the inputs.  $\phi$  is a clock signal. The inputs switch between  $V_{dd}$  and  $GND$



# Example 3: Dynamic MOS Logic

**QUESTION:** Find out the output  $Y$  with different combination of the inputs.  $\phi$  is a clock signal. The inputs switch between  $V_{dd}$  and  $GND$



$$@ t = t_1^- \quad Y = V_{dd}$$

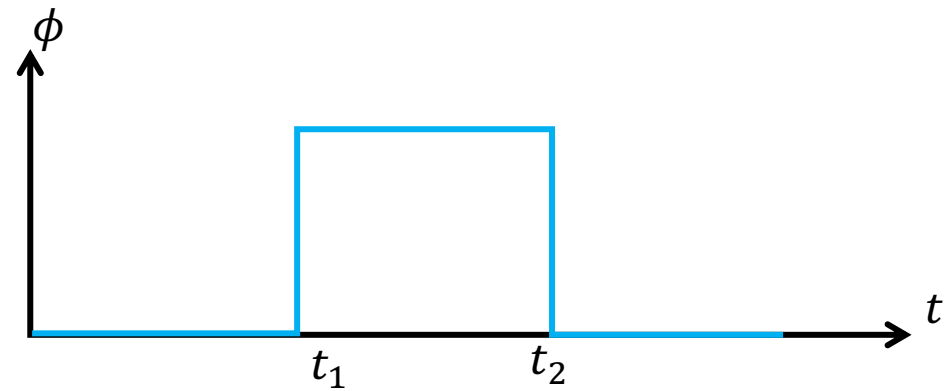
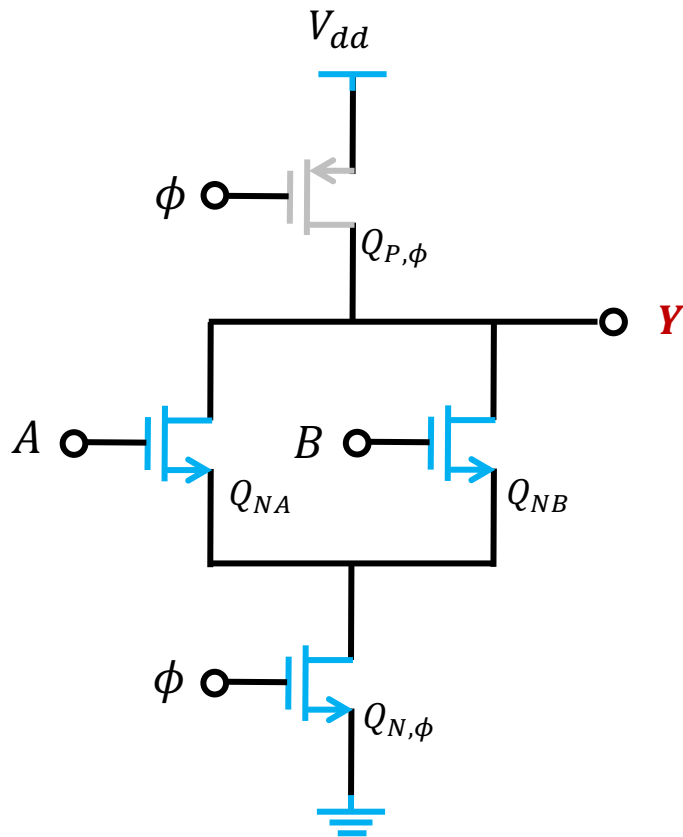
$$@ t = t_1^+ \quad Y = V_{dd}$$

$Q_{P,\phi}$  is OFF

$Q_{N,\phi}$  is ON

# Example 3: Dynamic MOS Logic

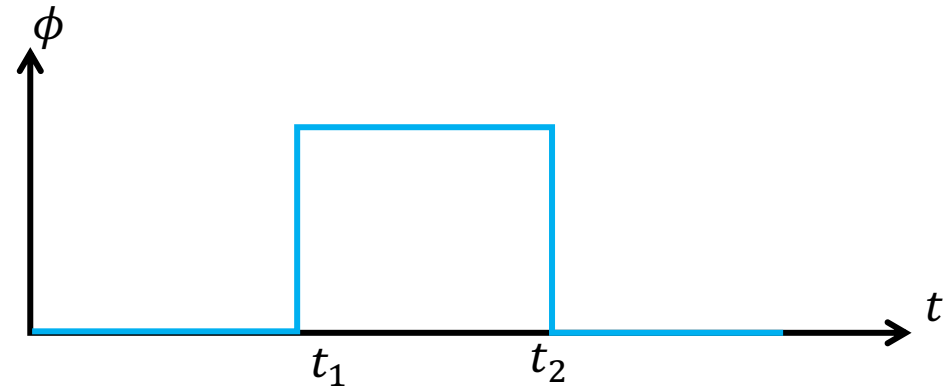
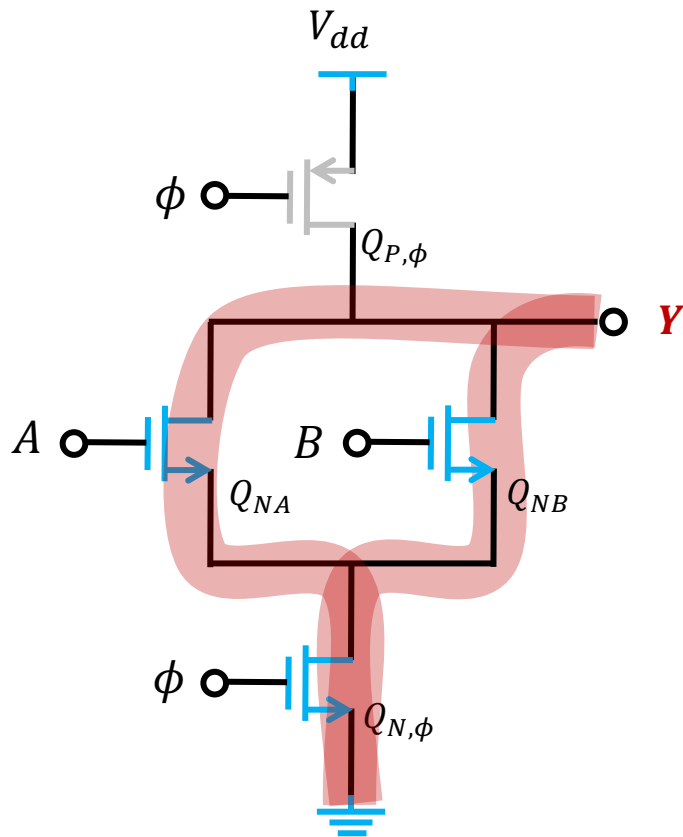
**QUESTION:** Find out the output  $Y$  with different combination of the inputs.  $\phi$  is a clock signal. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$ |
|----------|----------|-----|
| $V_{dd}$ | $V_{dd}$ |     |
| $V_{dd}$ | $GND$    |     |
| $GND$    | $V_{dd}$ |     |
| $GND$    | $GND$    |     |

# Example 3: Dynamic MOS Logic

**QUESTION:** Find out the output  $Y$  with different combination of the inputs.  $\phi$  is a clock signal. The inputs switch between  $V_{dd}$  and  $GND$

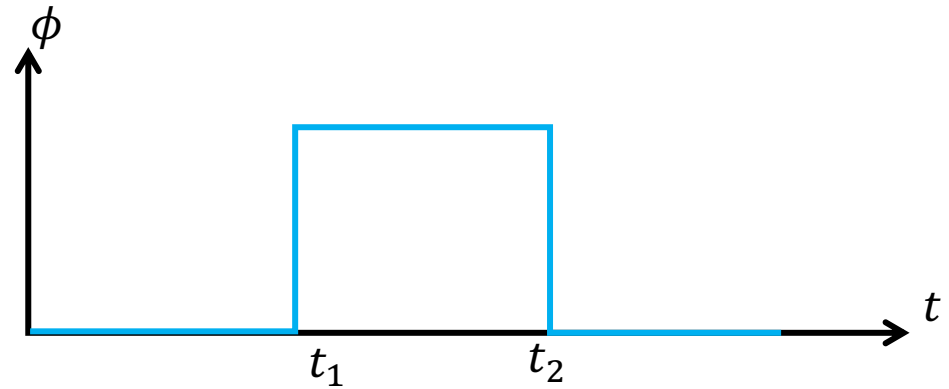
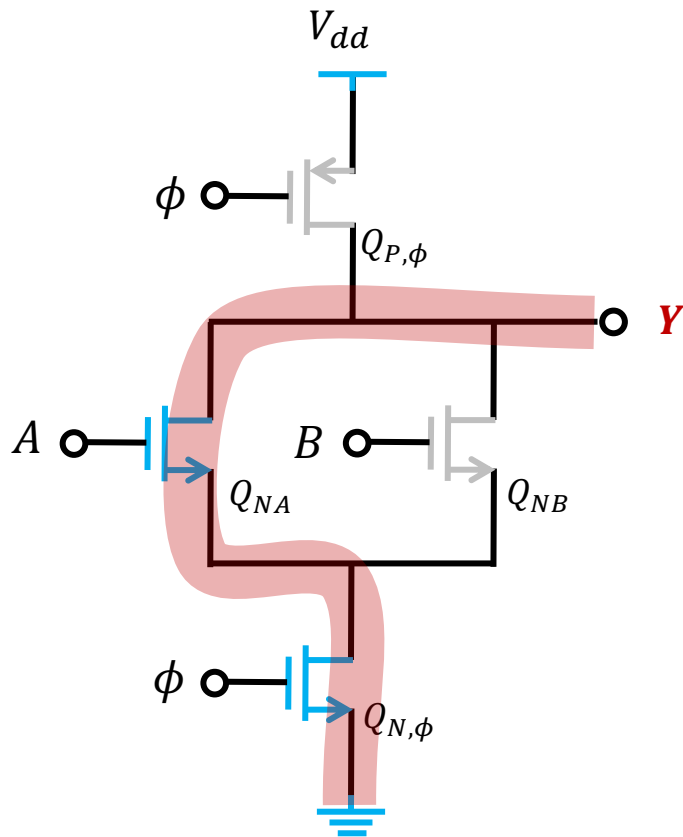


| $A$      | $B$      | $Y$   |
|----------|----------|-------|
| $V_{dd}$ | $V_{dd}$ | $GND$ |
| $V_{dd}$ | $GND$    |       |
| $GND$    | $V_{dd}$ |       |
| $GND$    | $GND$    |       |



# Example 3: Dynamic MOS Logic

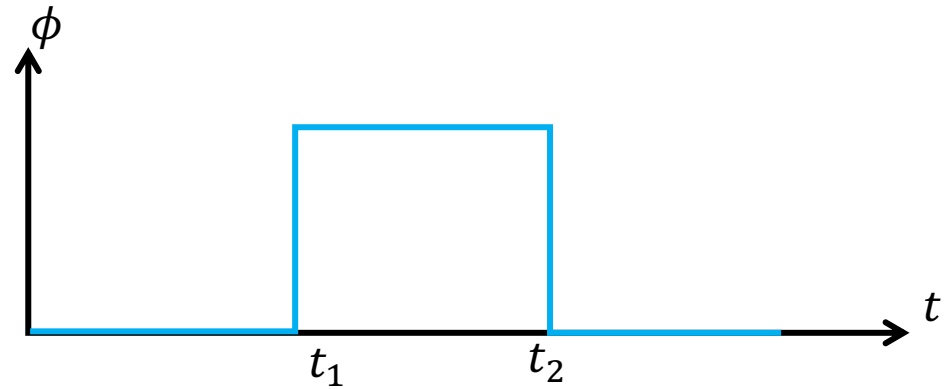
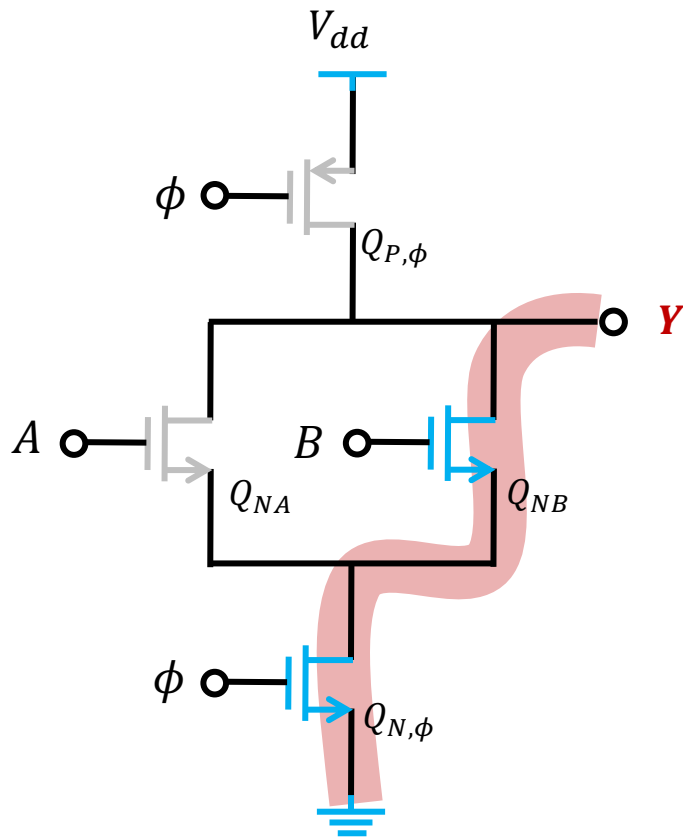
**QUESTION:** Find out the output  $Y$  with different combination of the inputs.  $\phi$  is a clock signal. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$   |
|----------|----------|-------|
| $V_{dd}$ | $V_{dd}$ | $GND$ |
| $V_{dd}$ | $GND$    | $GND$ |
| $GND$    | $V_{dd}$ |       |
| $GND$    | $GND$    |       |

# Example 3: Dynamic MOS Logic

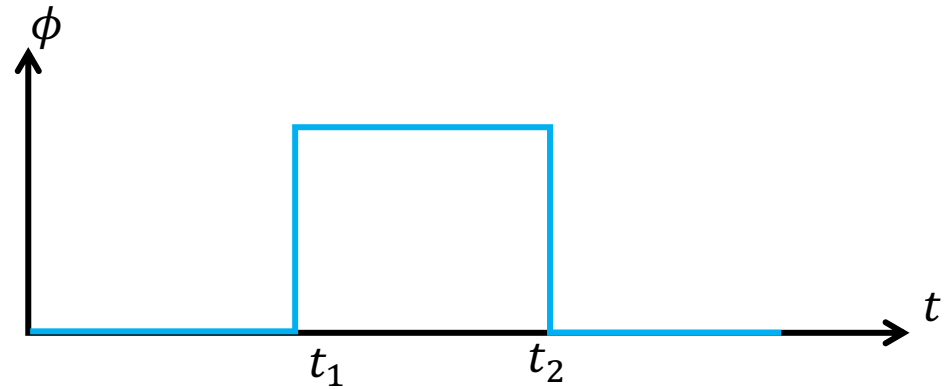
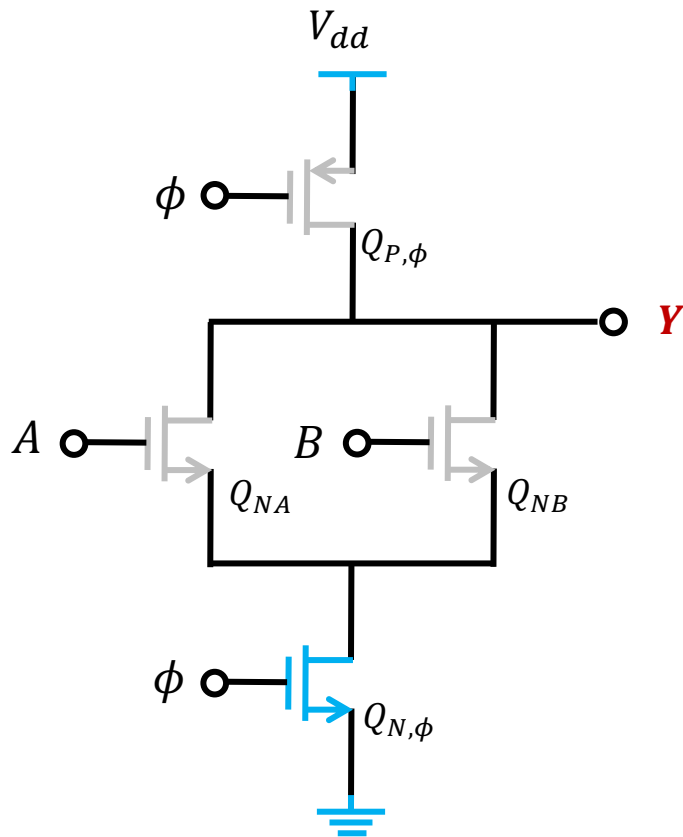
**QUESTION:** Find out the output  $Y$  with different combination of the inputs.  $\phi$  is a clock signal. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$   |
|----------|----------|-------|
| $V_{dd}$ | $V_{dd}$ | $GND$ |
| $V_{dd}$ | $GND$    | $GND$ |
| $GND$    | $V_{dd}$ | $GND$ |
| $GND$    | $GND$    |       |

# Example 3: Dynamic MOS Logic

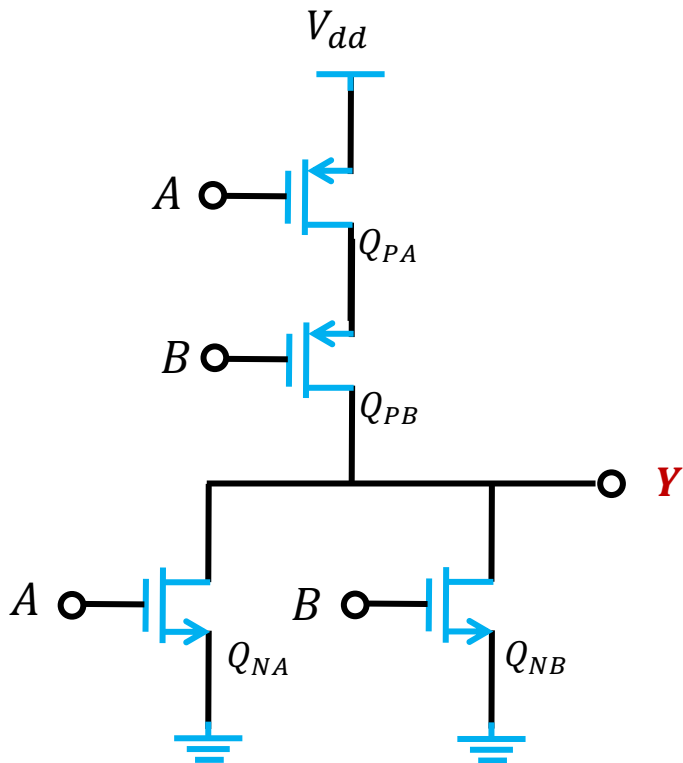
**QUESTION:** Find out the output  $Y$  with different combination of the inputs.  $\phi$  is a clock signal. The inputs switch between  $V_{dd}$  and  $GND$



| $A$      | $B$      | $Y$                        |
|----------|----------|----------------------------|
| $V_{dd}$ | $V_{dd}$ | <b><math>GND</math></b>    |
| $V_{dd}$ | $GND$    | <b><math>GND</math></b>    |
| $GND$    | $V_{dd}$ | <b><math>GND</math></b>    |
| $GND$    | $GND$    | <b><math>V_{dd}</math></b> |

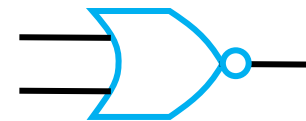
# Recall: NOR gate circuit

**QUESTION:** Find out the output  $Y$  with different combination of the inputs. The inputs switch between  $V_{dd}$  and  $GND$



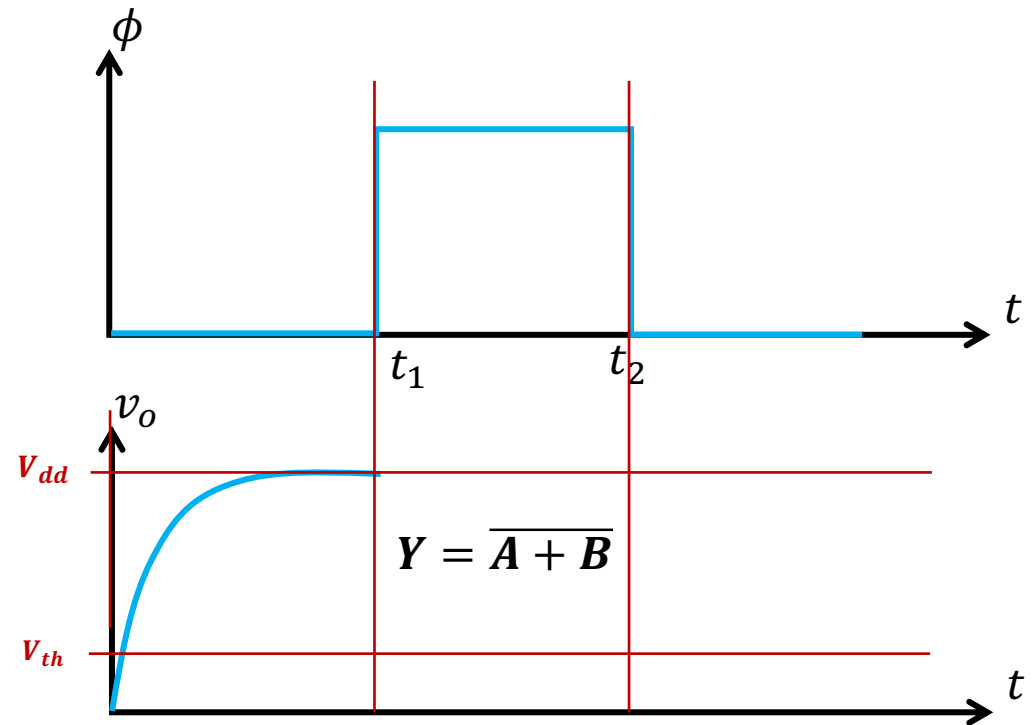
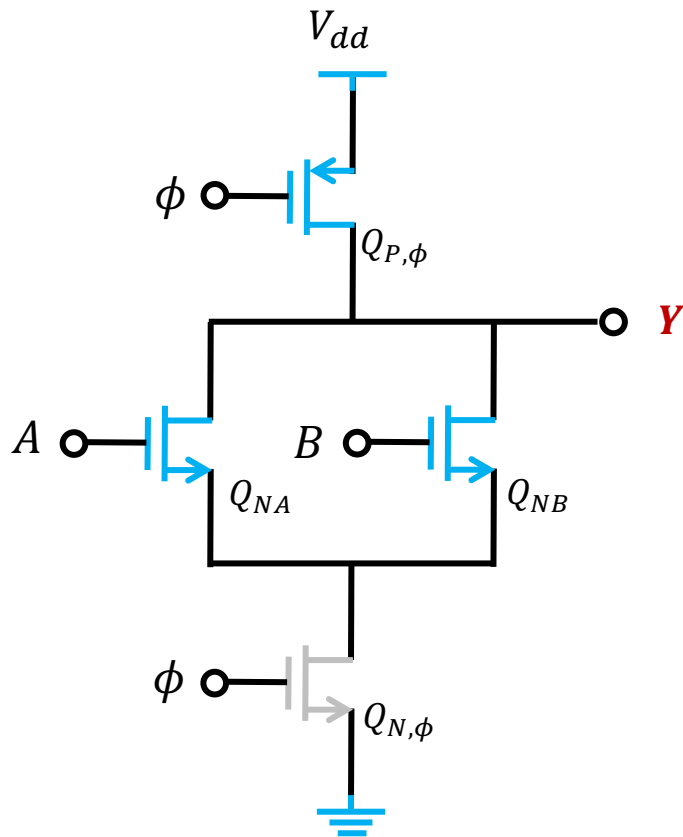
| $A$      | $B$      | $Y$      |
|----------|----------|----------|
| $V_{dd}$ | $V_{dd}$ | $GND$    |
| $V_{dd}$ | $GND$    | $GND$    |
| $GND$    | $V_{dd}$ | $GND$    |
| $GND$    | $GND$    | $V_{dd}$ |

$$Y = \overline{A + B}$$



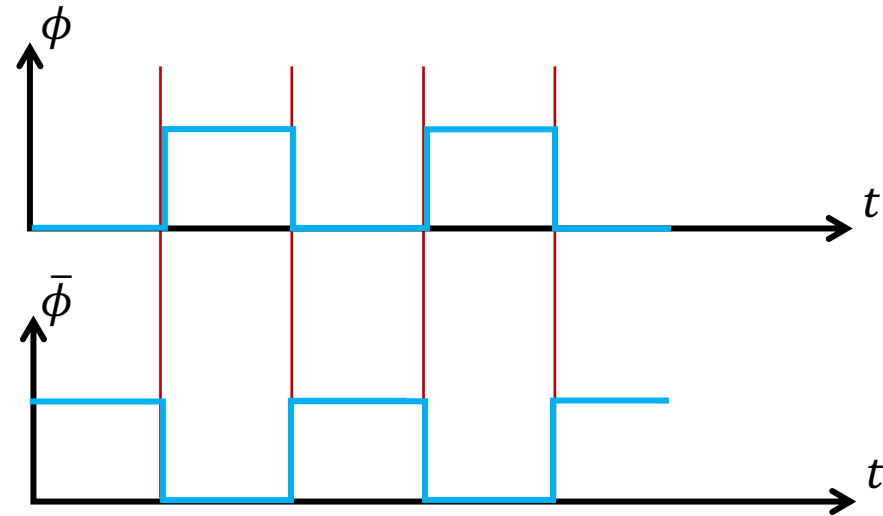
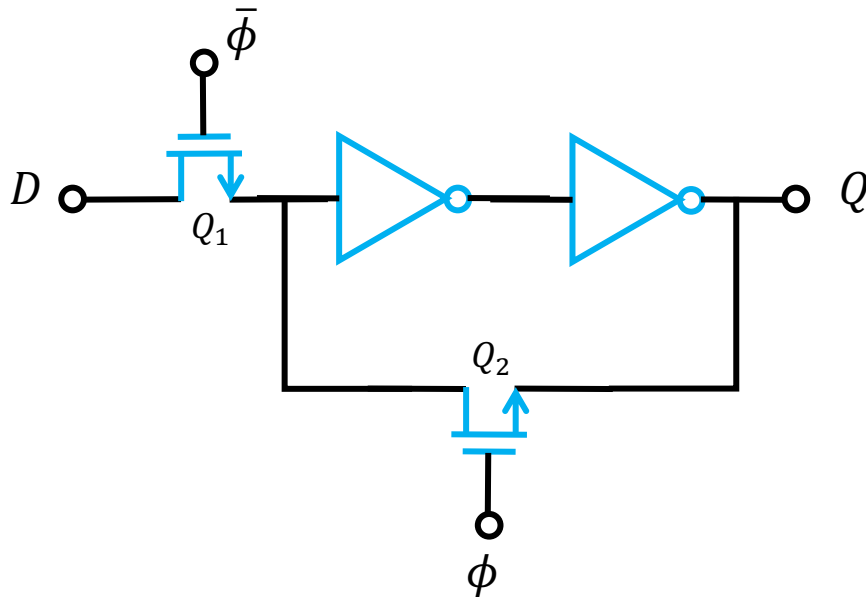
# Example 3: Dynamic MOS Logic

**QUESTION:** Find out the output  $Y$  with different combination of the inputs.  $\phi$  is a clock signal. The inputs switch between  $V_{dd}$  and  $GND$



# Example 4

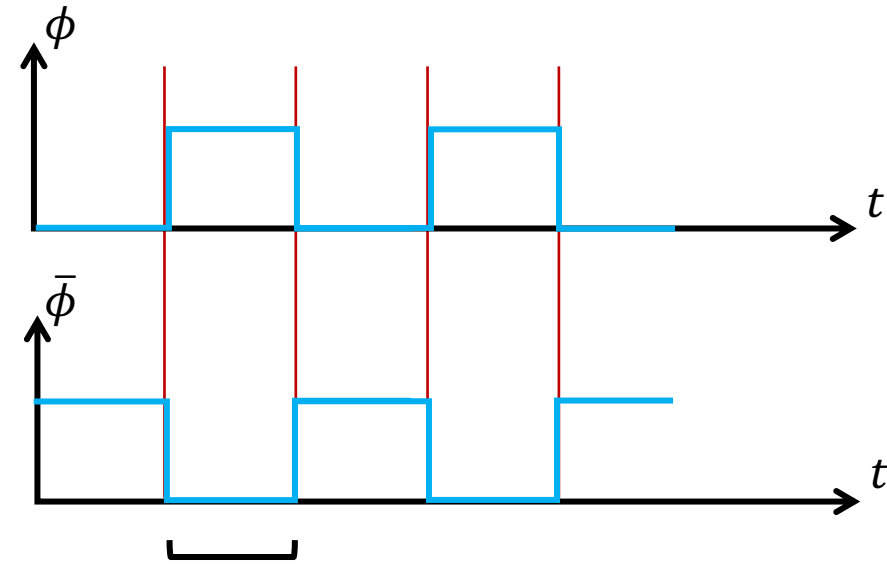
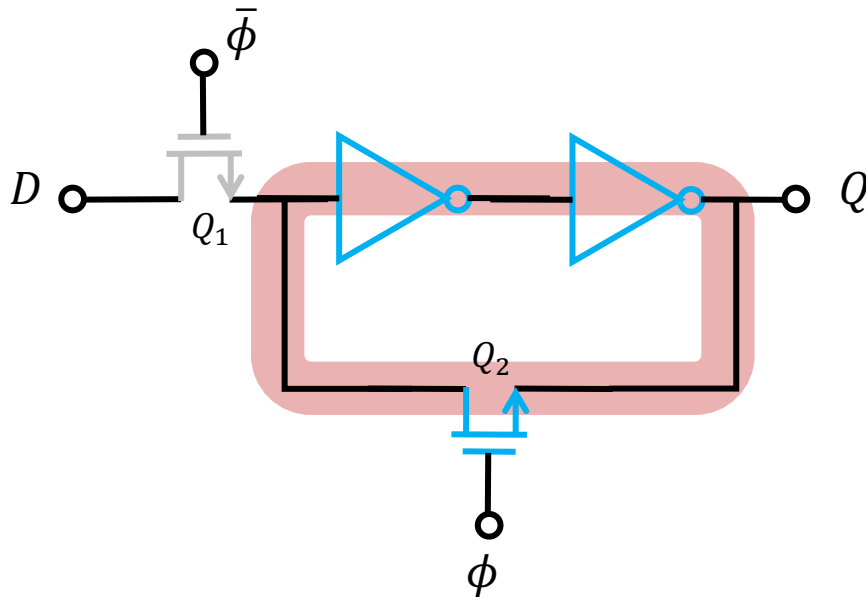
**QUESTION:** Find out the output  $Q$  with different input  $D$ .  $\phi$  is a clock signal. The input switches between  $V_{dd}$  and  $GND$





# Example 4

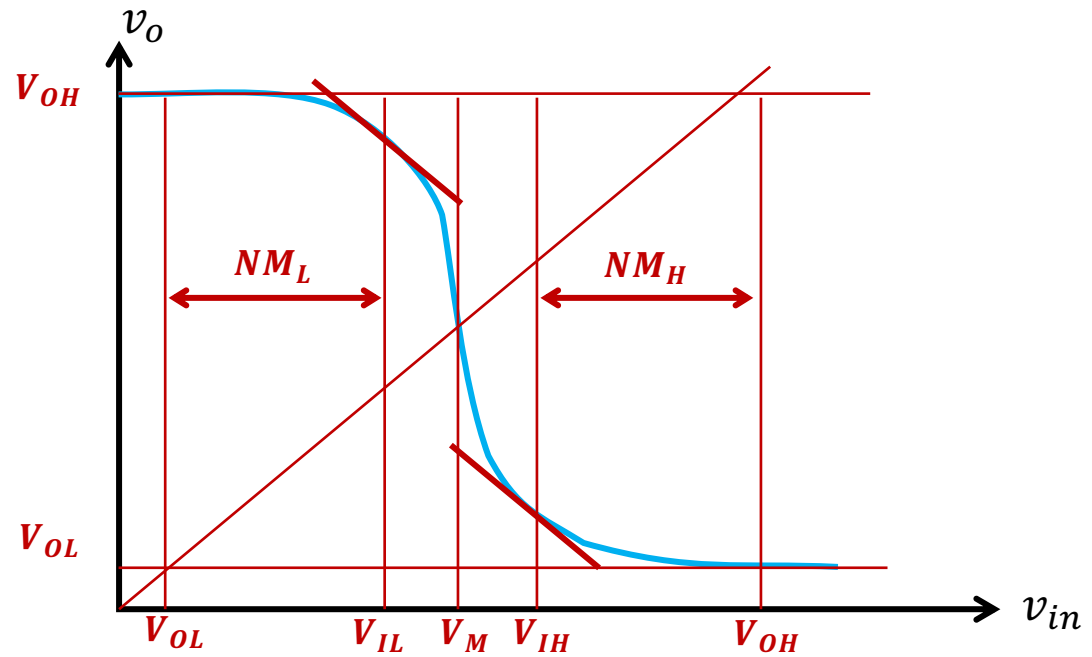
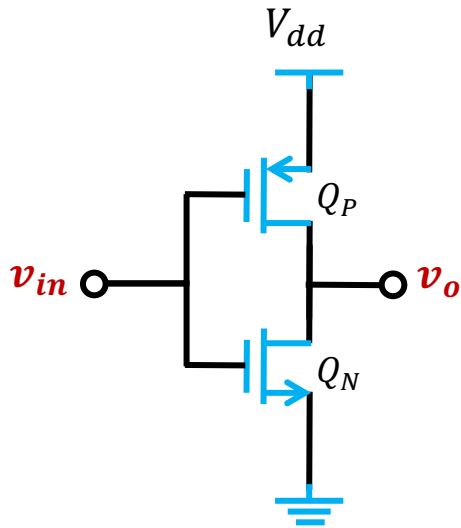
**QUESTION:** Find out the output  $Q$  with different input  $D$ .  $\phi$  is a clock signal. The input switches between  $V_{dd}$  and  $GND$



$Q_1$  is OFF  
 $Q_2$  is ON

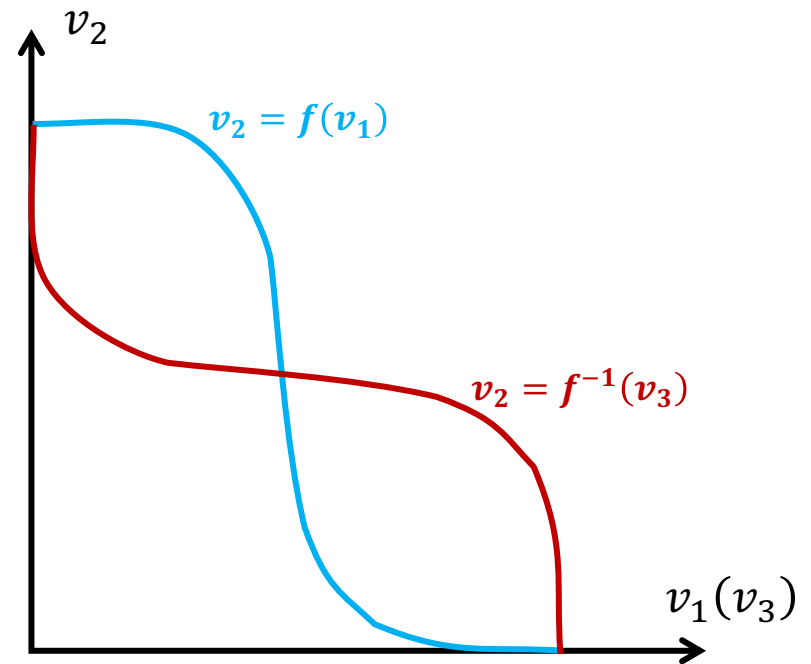
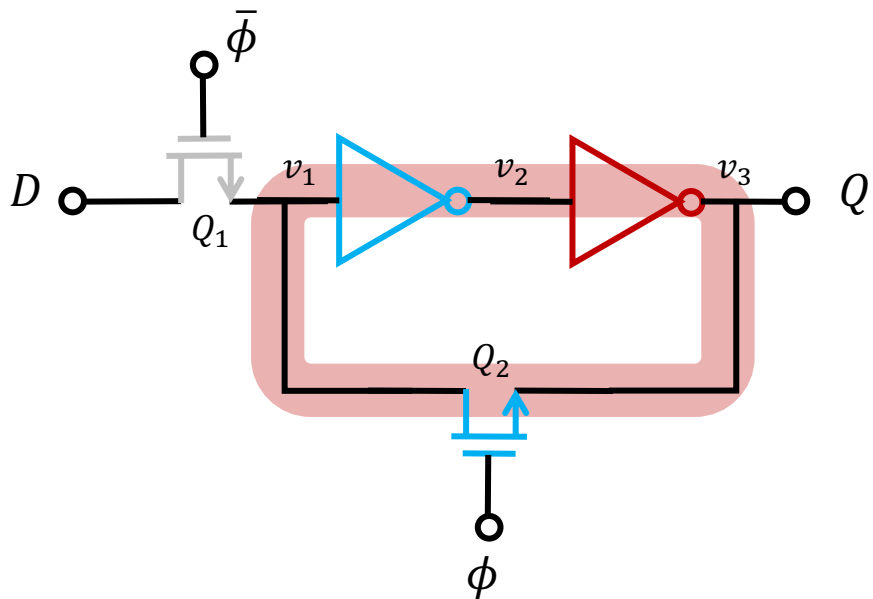


# Recall: VTC of an Inverter



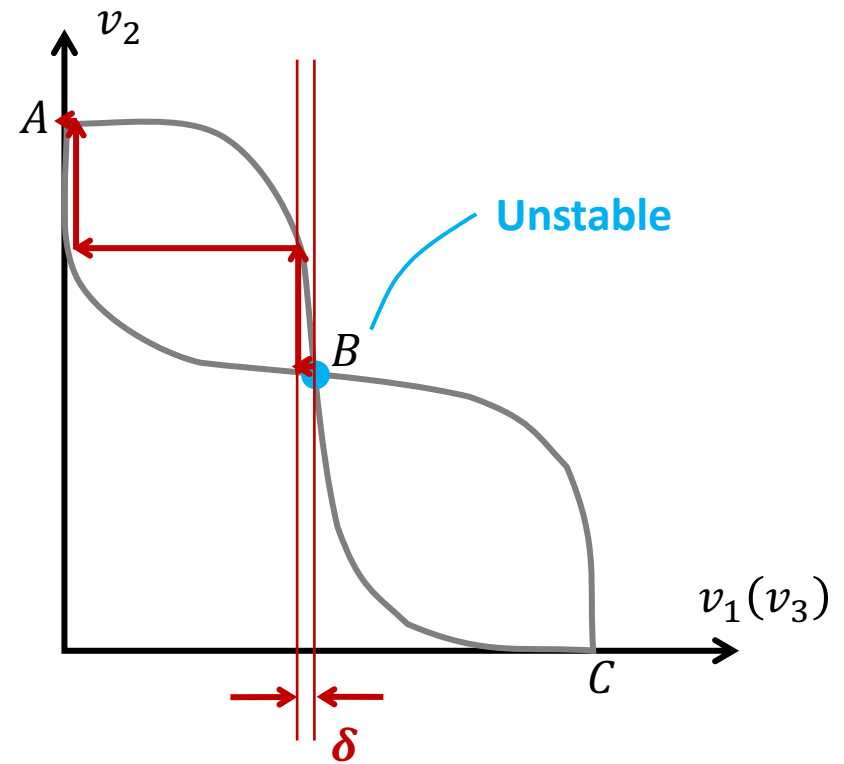
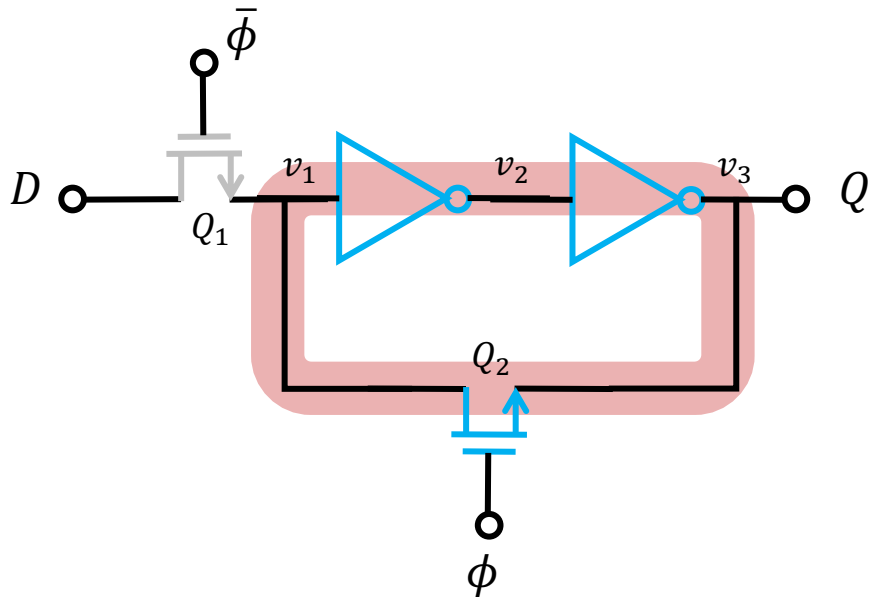
# Example 4

**QUESTION:** Find out the output  $Q$  with different input  $D$ .  $\phi$  is a clock signal. The input switches between  $V_{dd}$  and  $GND$



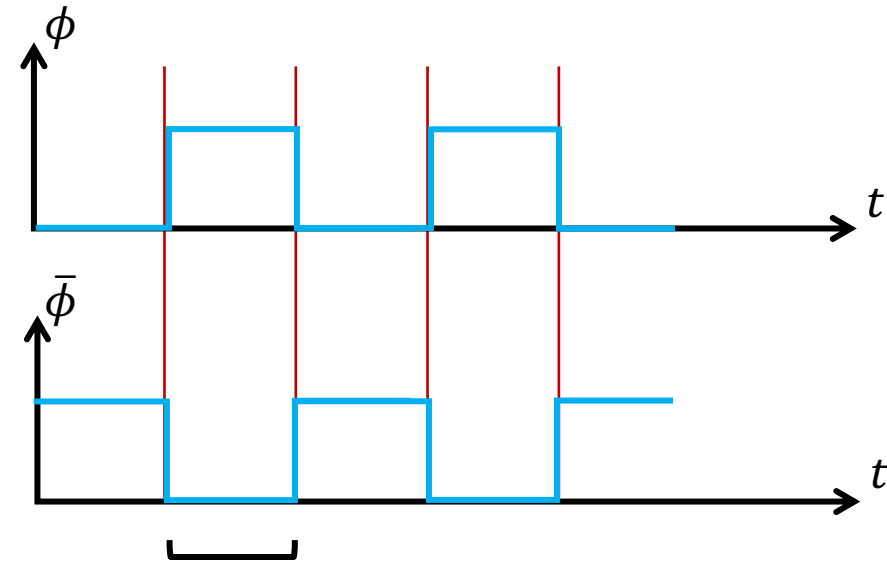
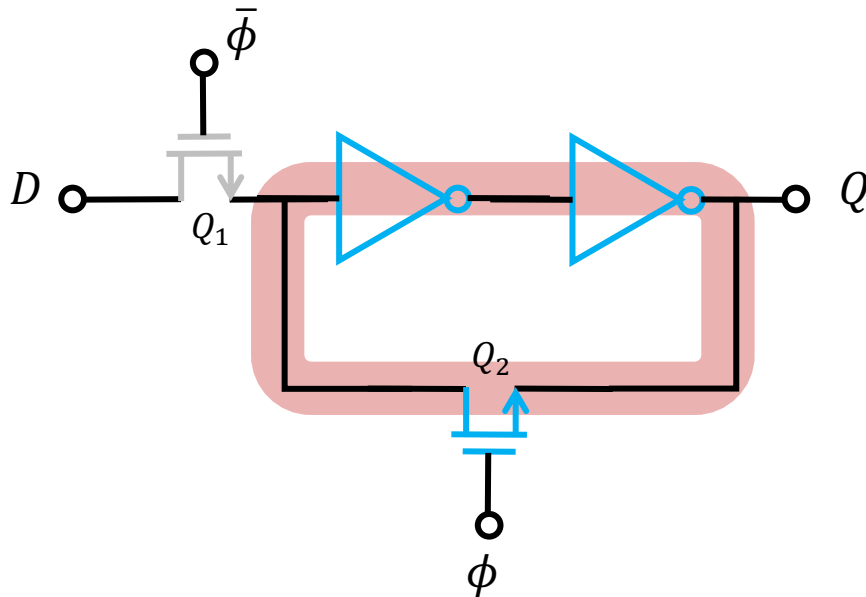
# Example 4

**QUESTION:** Find out the output  $Q$  with different input  $D$ .  $\phi$  is a clock signal. The input switches between  $V_{dd}$  and  $GND$



# Example 4

**QUESTION:** Find out the output  $Q$  with different input  $D$ .  $\phi$  is a clock signal. The input switches between  $V_{dd}$  and  $GND$

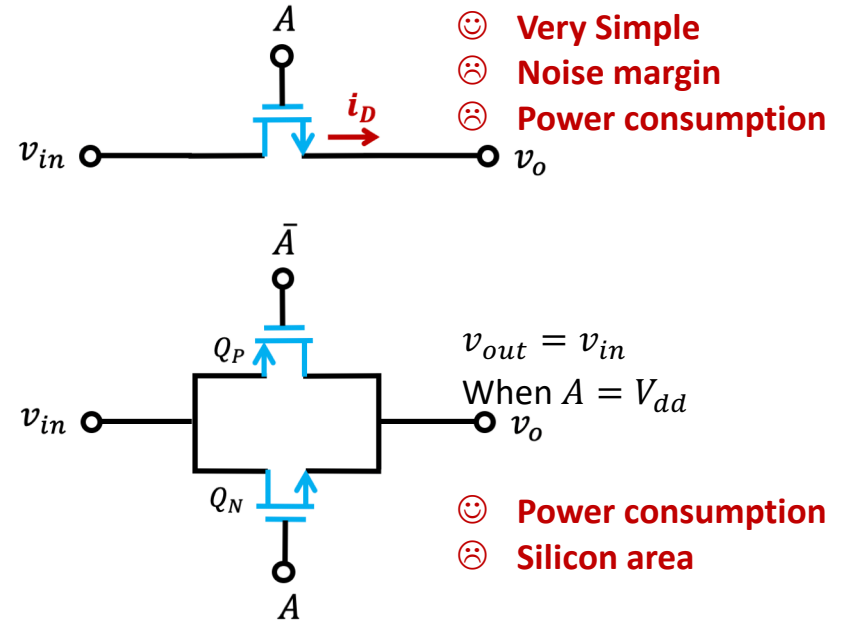


$Q_1$  is OFF  
 $Q_2$  is ON  
 $Q$  does not change

This is a simplest D Flip-Flop  
Learn more in 30230793

# Outline

- CMOS Inverters
- Logic-Gate Circuits
- Digital Switches & Dynamic Logic Circuits
  - Single NMOS switch
  - Transmission Gate Switch
  - Dynamic logic circuits
- Memory Circuits



# 2 Types of Computer Memory



## Main memory

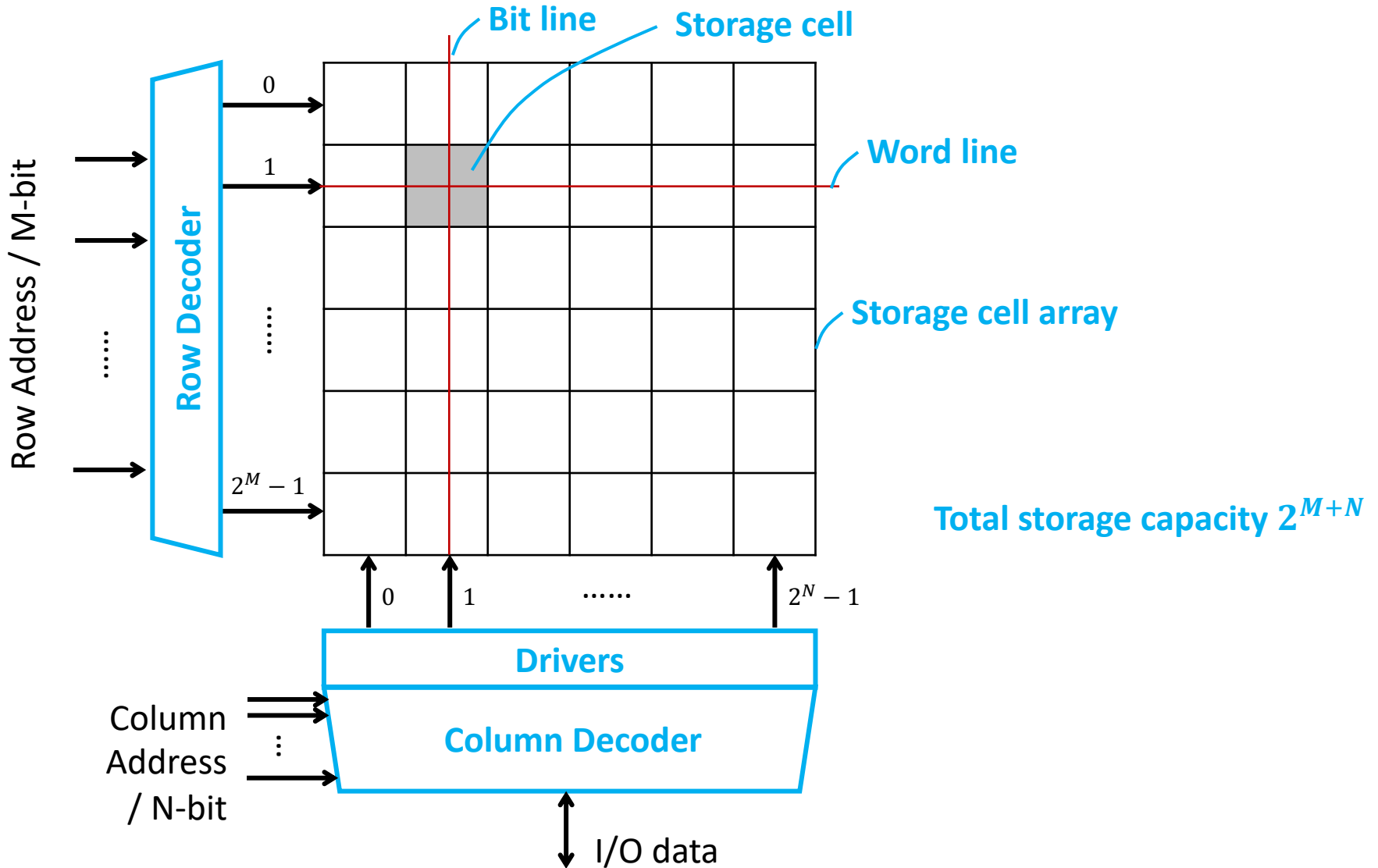
- Usually most rapidly accessible
- Usually **random-access**
- Execute most/all instructions



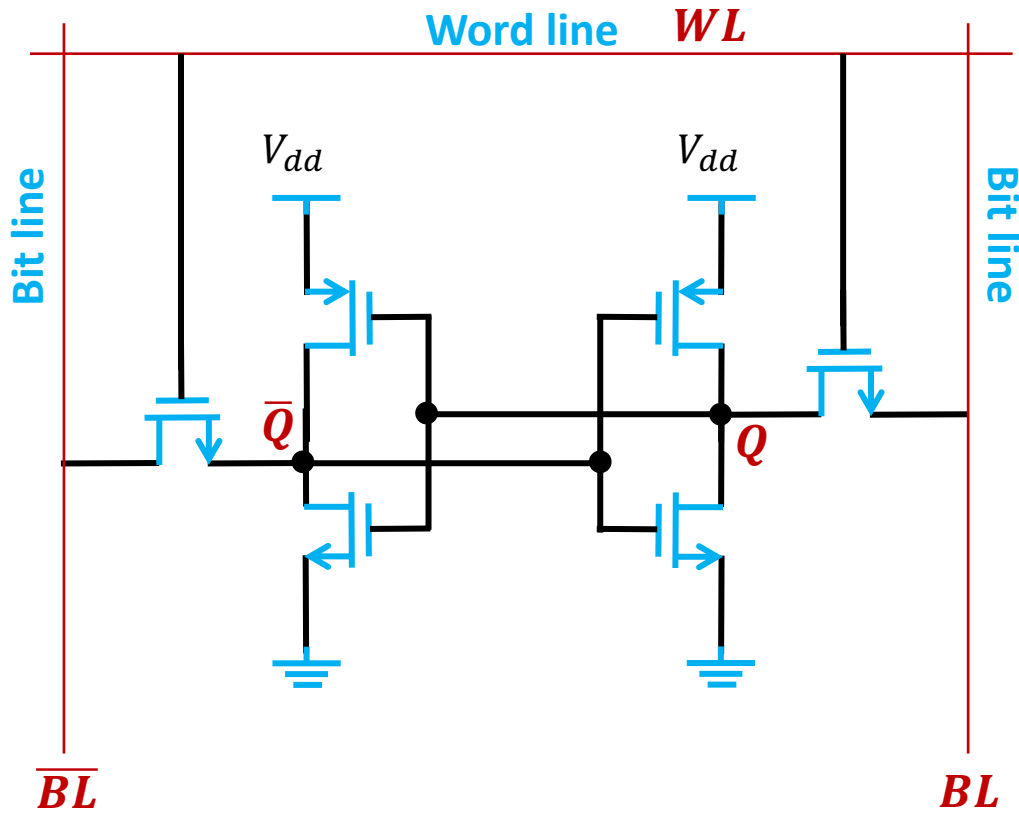
## Mass-storage memory

- High storage capability

# Random-Access Memory Chip



# Random-Access Memory Cell



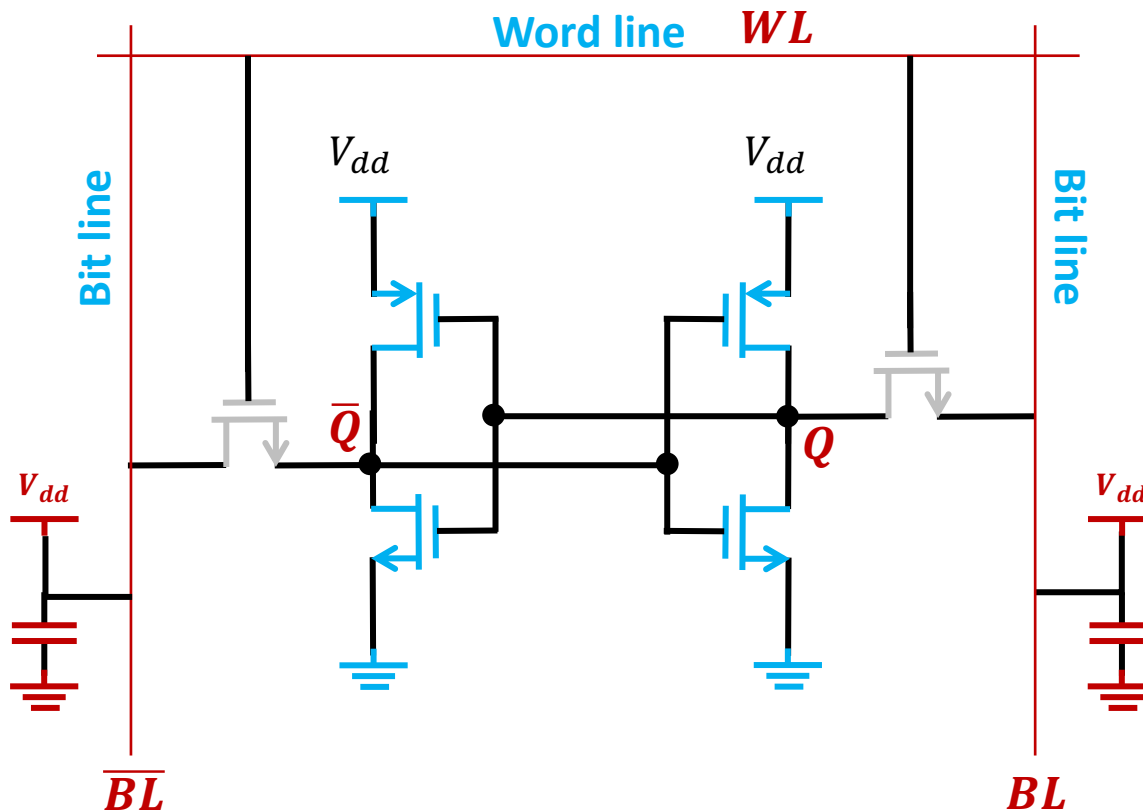
## READ OPERATION

- $WL$  is pulled down

## Static Random-Access Memory (SRAM) Cell



# Random-Access Memory Cell

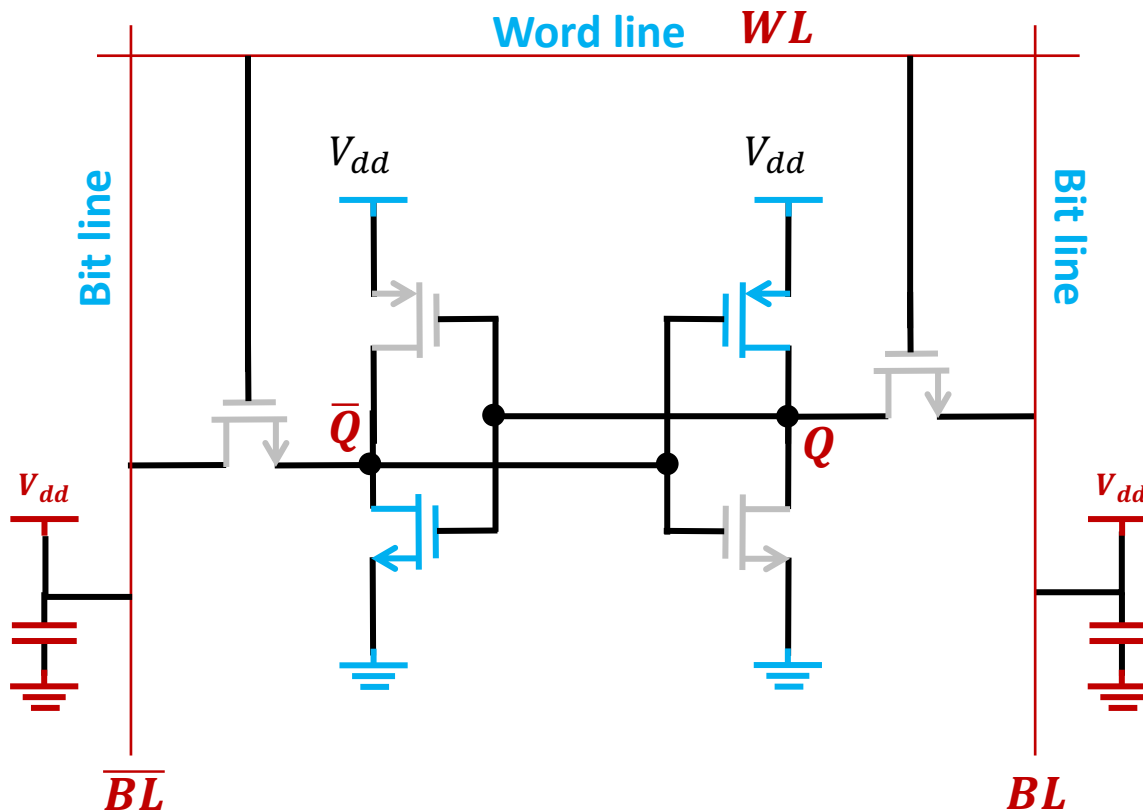


## READ OPERATION

- Word line is pulled down
- Bit lines are recharged to  $V_{dd}$

Static Random-Access Memory (SRAM) Cell

# Random-Access Memory Cell

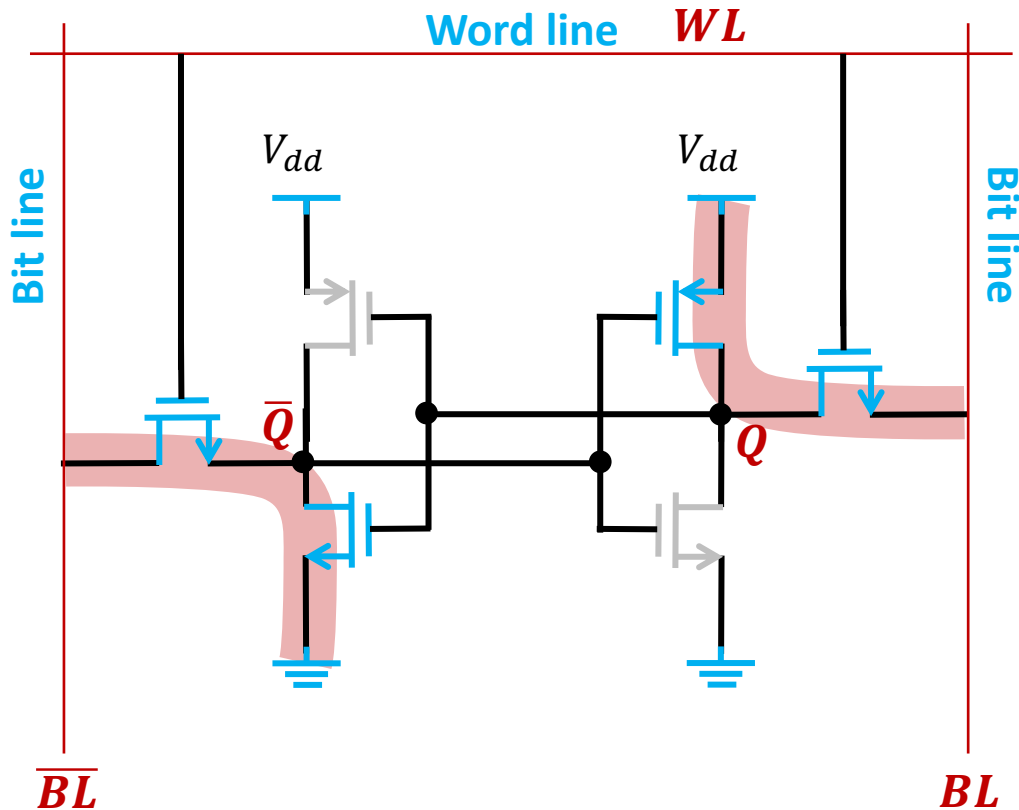


## READ OPERATION

- Word line is pulled down
- Bit lines are recharged to  $V_{dd}$
- Assume the stored  $Q = V_{dd}$

Static Random-Access Memory (SRAM) Cell

# Random-Access Memory Cell

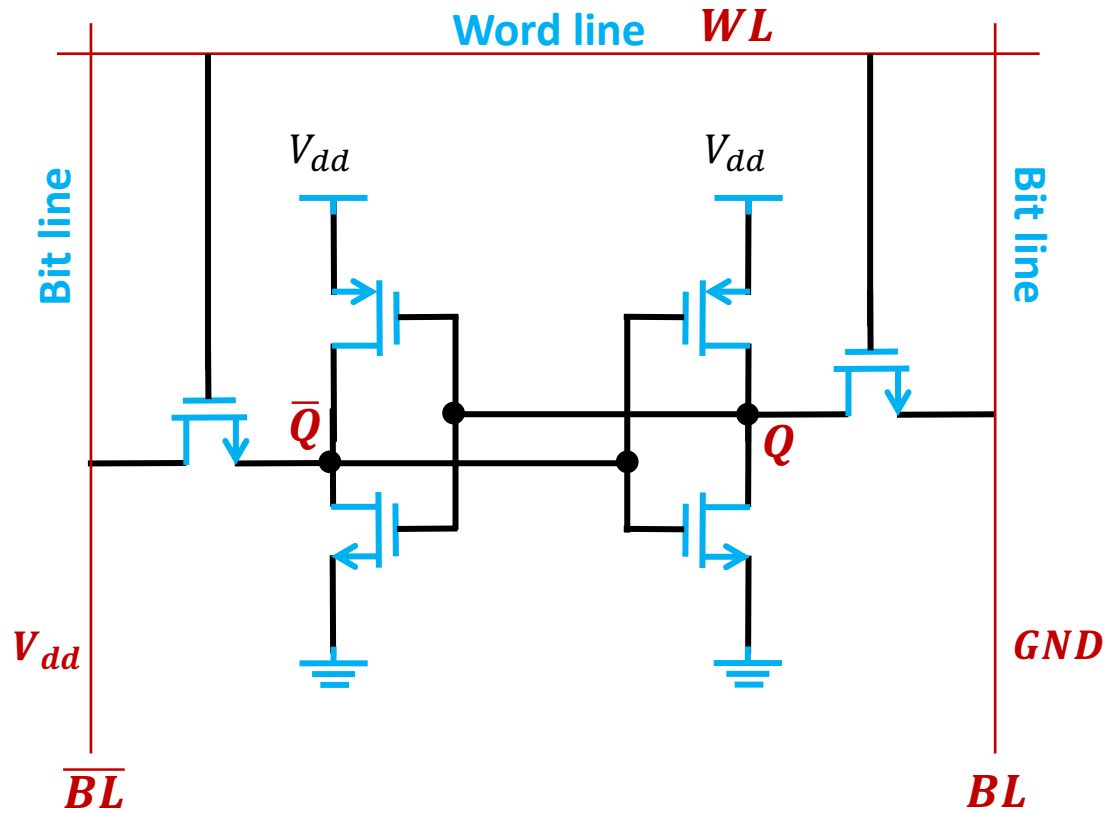


## READ OPERATION

- Word line is pulled down
- Bit lines are recharged to  $V_{dd}$
- Assume the stored  $Q = V_{dd}$
- Pull up the word line
- $BL$  keeps  $V_{dd}$ .
- $\overline{BL}$  is pulled down to  $\overline{Q}$ .

## Static Random-Access Memory (SRAM) Cell

# Random-Access Memory Cell

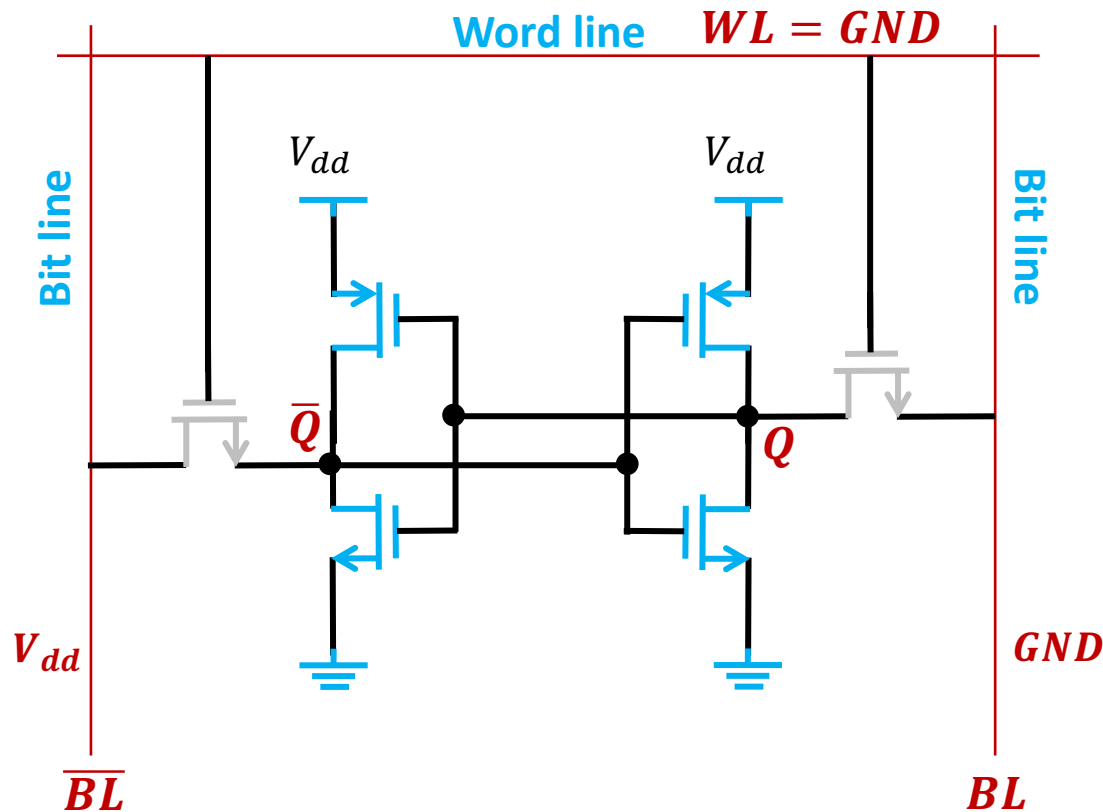


## WRITE OPERATION

- Assume the stored  $Q = V_{dd}$
- Pull down the word line

Static Random-Access Memory (SRAM) Cell

# Random-Access Memory Cell

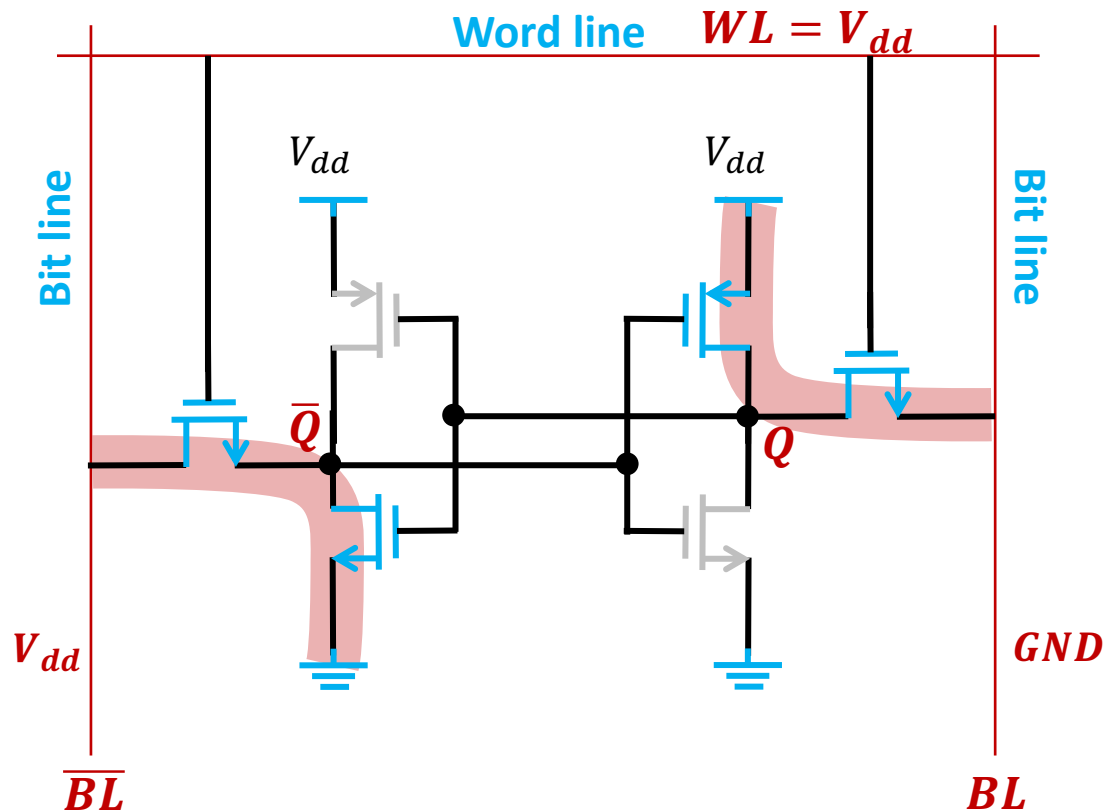


## WRITE OPERATION

- Assume the stored  $Q = V_{dd}$
- Pull down the word line
- Assume  $GND$  is to be written
- Pull down  $BL$  to  $GND$
- Pull up  $\overline{BL}$  to  $V_{dd}$

Static Random-Access Memory (SRAM) Cell

# Random-Access Memory Cell

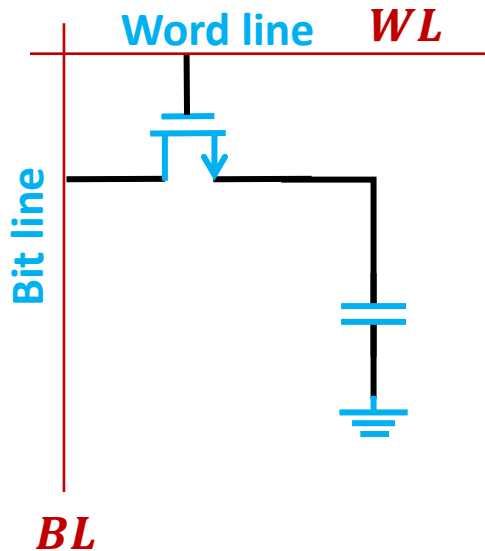


## WRITE OPERATION

- Assume the stored  $Q = V_{dd}$
- Pull down the word line
- Assume  $GND$  is to be written
- Pull down  $BL$  to  $GND$
- Pull up  $\overline{BL}$  to  $V_{dd}$
- The word line is pull up
- $\overline{Q}$  is pull up to  $V_{dd}$
- $Q$  is discharged to  $GND$

## Static Random-Access Memory (SRAM) Cell

# Random-Access Memory Cell



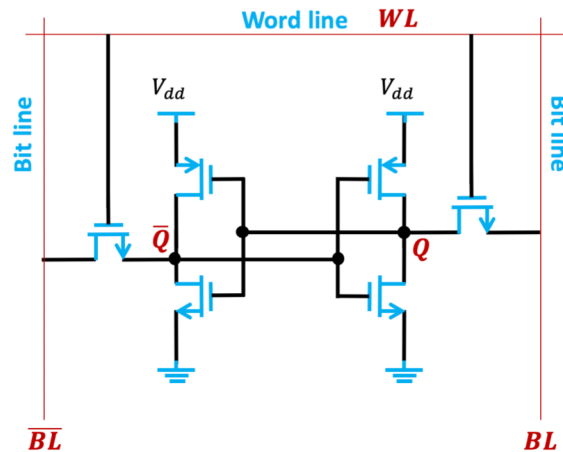
## Dynamic Random-Access Memory (DRAM) Cell

### WRITE OPERATION

- Assume the stored  $Q = GND$
- Pull down the word line
- Assume  $V_{dd}$  is to be written
- Pull up  $BL$  to  $V_{dd}$
- The word line is pull up
- $Q$  is charged to  $V_{dd} - V_{th}$

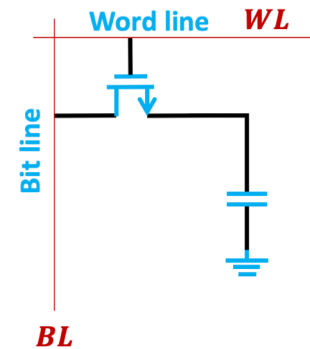
# Summary: Random-Access Memory

## Static RAM (SRAM) Cell



- Data stored in **latches**
- Simple **read/write operation**
- Relative large **area**

## Dynamic RAM (DRAM) Cell

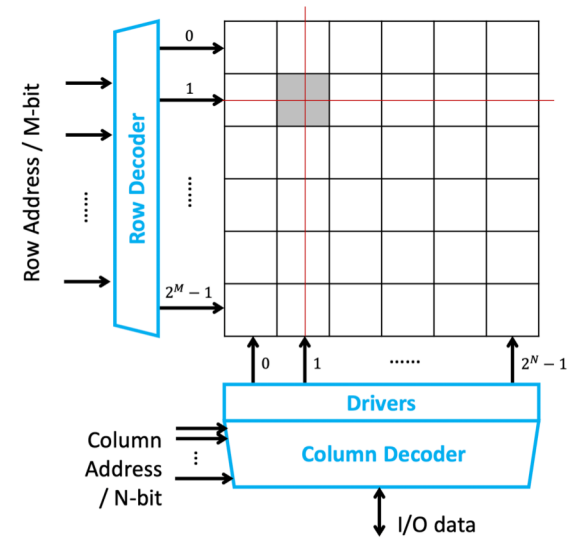


- Data stored in **capacitors**
- Complex **read/write operation**
- Low silicon **area** consumption

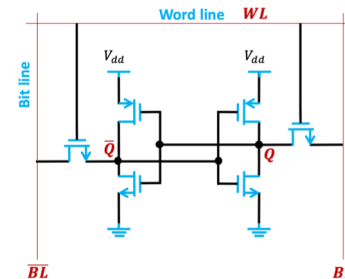


# Outline

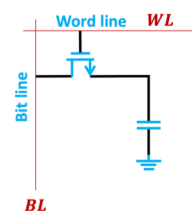
- CMOS Inverters
- Logic-Gate Circuits
- Digital Switches & Dynamic Logic Circuits
- Memory Circuits
  - Overview
  - Memory cell
  - **Address decoder**



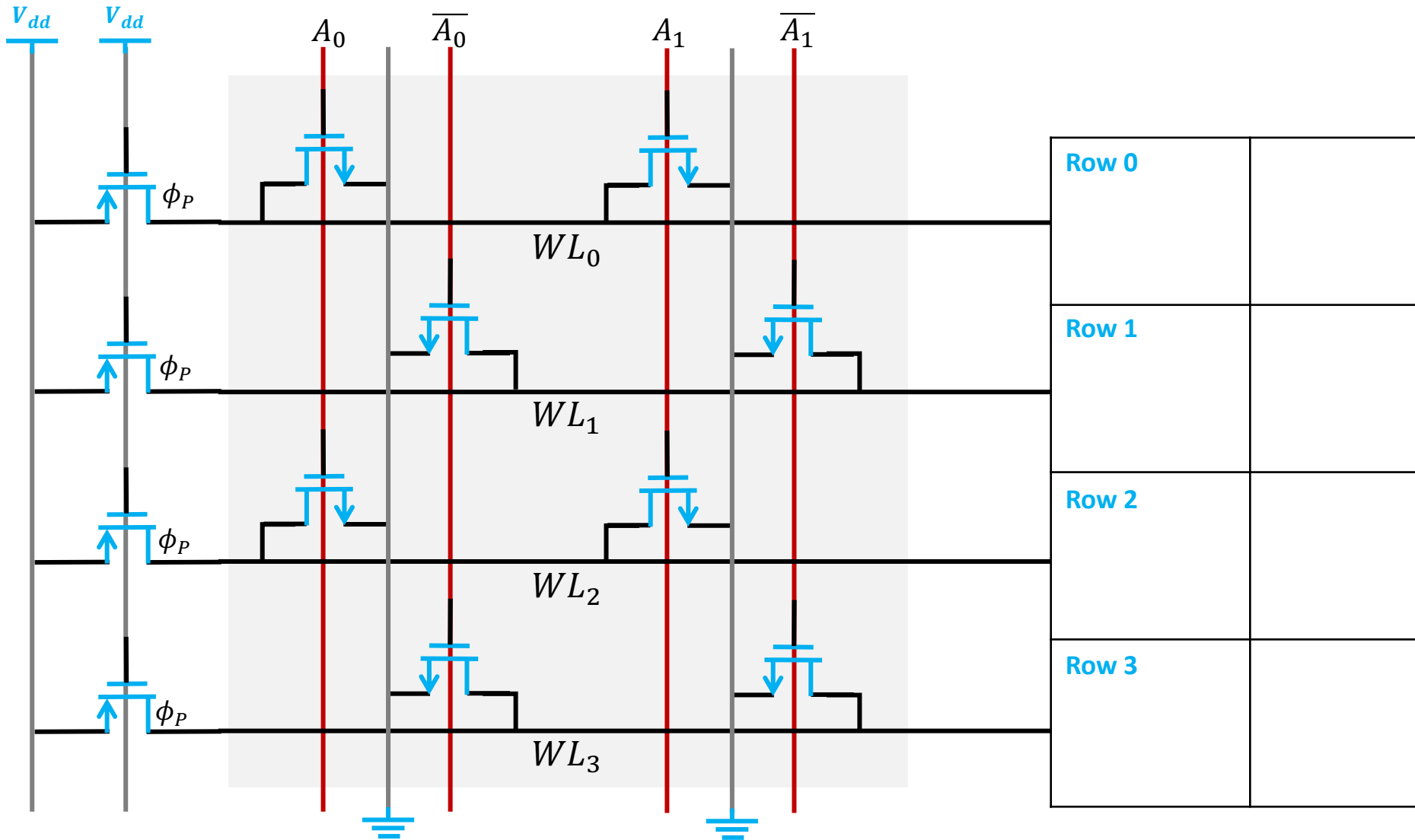
SRAM



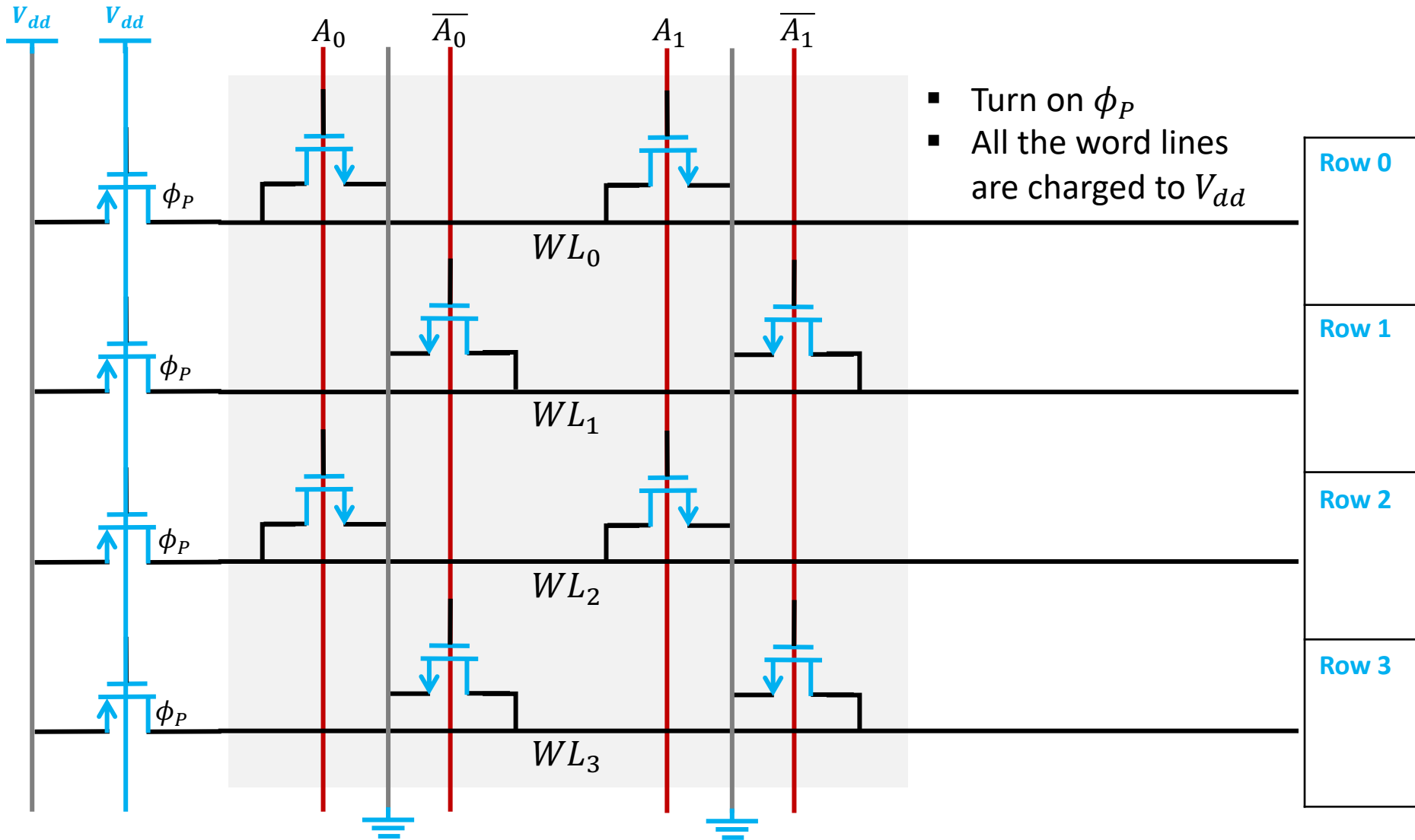
DRAM



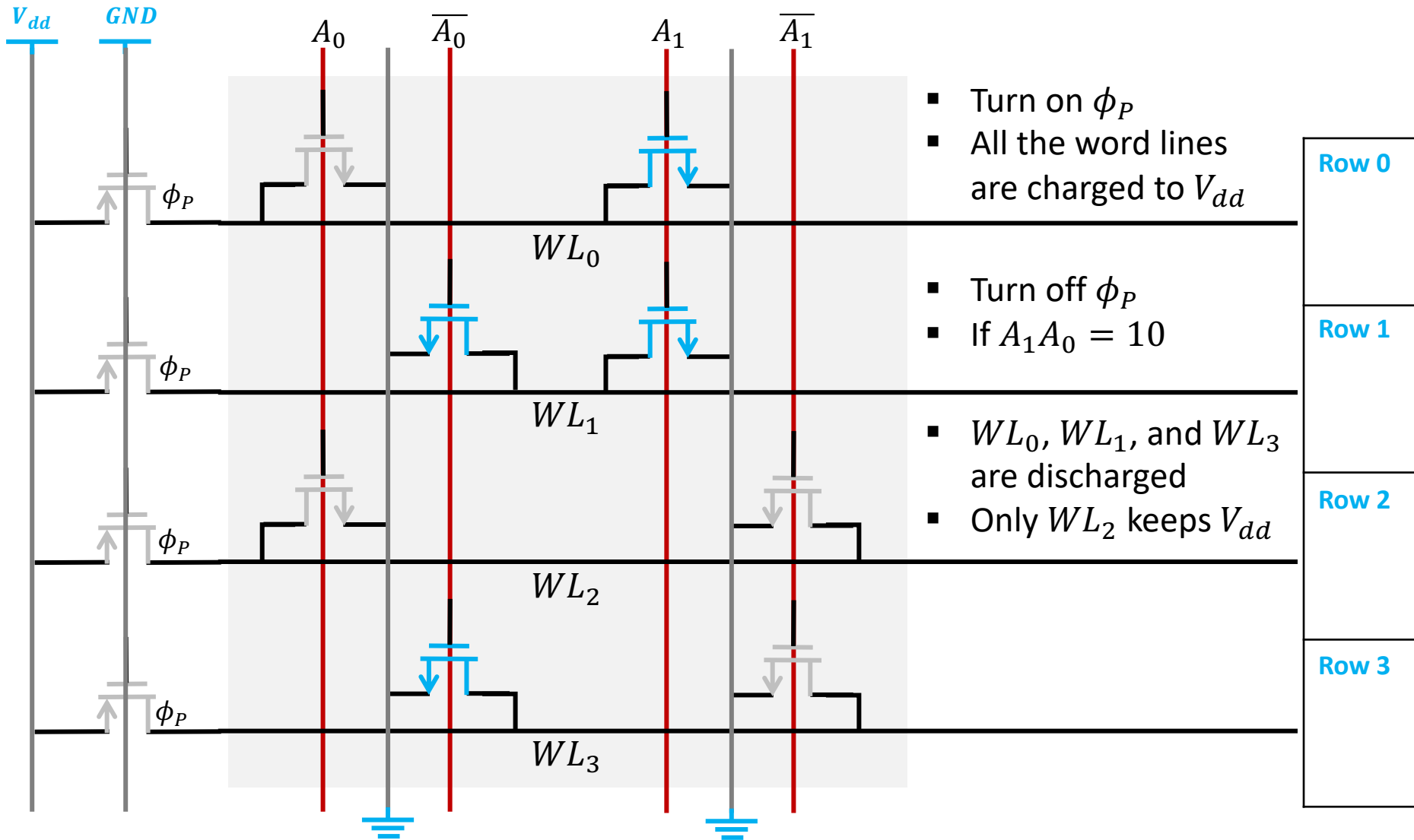
# Row-Address Decoder



# Row-Address Decoder



# Row-Address Decoder

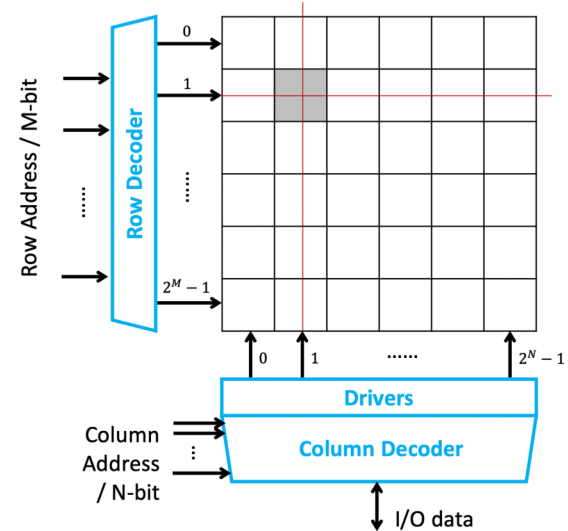


# Outline

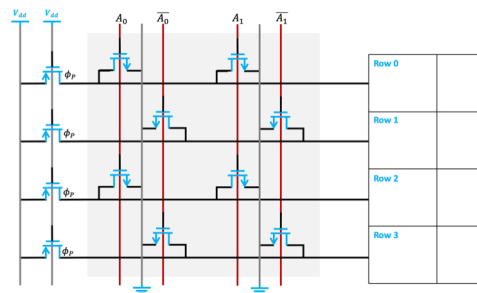
- CMOS Inverters
- Logic-Gate Circuits
- Digital Switches & Dynamic Logic Circuits

- Memory Circuits

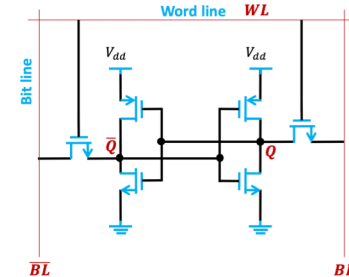
- Overview
- Memory cell
- Address decoder



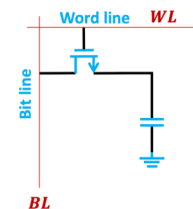
Address decoder



SRAM



DRAM



# Reading tasks & learning goals

- Reading tasks
  - Microelectronic Circuits, 6<sup>th</sup> edition
    - Chapter 13 – 14.3.1, 15.2 – 15.3, 15.4.2
- Learning goals
  - Well understand how to analyze the **power consumption**, **propagation delay** and **noise margins** of a CMOS logic gate
  - Well understand how to analyze the **logic-gate circuits**
  - Well understand how to analyze the **CMOS switch circuit**
  - Know the different types of **memory** circuits